12500 TI Blvd
Dallas, Texas 75243
www.ti.com

Total Ionizing Dose (TID)

TPS7H1101A-RHA
(5962R1320202VXC)

1.5-V to 7-V Input, 3-A, Radiation-Hardened LDO Regulator

Date: 3/21/2017
Approved by: Brent Rhoton
12500 TI Blvd
Dallas , TX 75243
Phone: 214-479-5373
Email: brentr@ti.com

1.0 Summary

Texas Instruments (TI) plans to release a radiation hardness assurance (RHA) version of the TPS7H1101A-SP, 1.5-V to 7-V Input, 3-A, Radiation-Hardened LDO Regulator. The TPS7H1101A-SP passes 100 Krad (Si) total ionizing dose (TID) radiations per MIL-STD-883J, Test Method 1019.9 and Condition A. The test results showed that the part remained functional after irradiation of 100 Krad (Si).

2.0 Radiation Source

Total Ionizing Dose High Dose Rate (TID LDR) radiation testing was performed at the SVA in its Santa Clara, CA facility using Co-60 gamma ray source with dose rate maintained at 63.58 rad(Si)/sec and accuracy of +/-10%.

Radiation Summary report contains the detailed TID testing information for lot traceability and radiation details

3.0 Results

The parametric data for the TPS7H1101A-SP passes up to 100 Krad (Si) High Dose Rate TID to cover the Group E needed for this lot. Refer to data and plots in the HDR Report bookmark.

TPS7H1101A-RHA Radiation Summary Report

Device Information: TPS7H1101A-RHA (5962R1320202VXC)
Wafer lot number: 1651039DL2
Wafer number: 3

Manufacturer: Texas Instruments, Inc

Controlling Specification: 5962R1320202VXC

Package Type: 16-pin Ceramic CFP Package

Samples were exposed biased for HDR.

High Dose Rate Radiation Source: SVA
Santa Clara, CA facility using Co-60 gamma ray source

High Dose Rate: 63.58 rad(Si)/sec

Disposition: Passes Group E 100KRAD High Dose Rate

Summary:
Passes Room Temp @:

- HDR (63.58 rad/sec) biased: Post 100 Krad(Si).

Prepared By: Ram Gooty Date: 03/21/2017
Approved By QA: Brent Rhoton Date: 03/21/2017

Device:	TPS7H1101A-RHA (5962R1320202VXC)
Technology:	LBC7X
Wafer FAB:	Freising (FR-BIP-1)

TPS7H1101A-RHA Radiation Test Plan:

The test plan details the characterization plan for completing Group E RLAT for production material 5962R1320202VXC for TPS7H1101A-RHA release at 100 Krad(Si) (level R).

Table I. RLAT Test Sampling Plan (Group E coverage)

	Test Condition	Total Die Tested
RLAT (Group E)	Test at RHA level: 100 Krad(Si), Dose rate: 65.58 mrad(Si)/s.	22 die to complete testing at 100 Krad(Si) to meet wafer lot sample size requirement per MIL-PRF-38535, TABLE B-I. Group E (RHA) TCI, Class V, Subgroup 2. Wafer lot will be qualified as RHA.

TID High Dose Rate Report: 100krad(Si) RLAT

TI Part Number	TPS7H1101A-RHA
Device Function	1.5-V to 7-V, ULTRA LOW DROPOUT REGULATOR
Package	16 HKR
Technology	LBC7x
Die Lot Number	1651039DL2
A/T Lot Number / Date Code	7001112MMT (LTC: 1703A)
Quantity Tested	23 devices including 1 control device. 22 devices irradiatiated biased at 100Krad(Si)
Lot Accept/Reject	Devices passed 100krad(Si) RLAT
Radiation Facility	Texas Instruments SVA Group, Santa Clara, CA
HDR Dose	100krad(Si)
HDR Dose Rate	63.58 rad/sec
Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
Irradiation Temperature	Ambient, room

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TPS7H1101A-RHA

RLAT 100Krad (Si) HDR RLAT Report

All units passed SMD specification limits up to 100Krad HDR RLAT.

TEXAS INSTRUMENTS

Total Dose Radiation Test
Test Flow For Gamma Cell 220 Excel

Hi-Rel Operations

NSPN: TPS7H1101 RLAT

Test Date: 3/20/2017

IPI:

A. SAMPLE LIST

Serial Numbers Start	 End	Qty.	LTC	Lot #	Date Code	BS #	Die Rev.
		9	100k biased				
		9	100k biased				
		4	100k biased				

Correlation unit serial number: ______ control units
79, 80 SPARES

B. DOSE RATE

Test Date: 3/20/2017

Enclosure Type: 2

Enclosures:
1 - No Enclosure
2 - Field Flattener w/Al Liner
3 - Field Flattener w/JLS 25% Attenuator & Liner
4 - 53% Attenuator
5 - 66% Attenuator
6 - 90% Attenuator

Calculations (based upon last dosimetery data):
26-Aug-05

Days since last dosimetery: 4224

Reference decay: 0.06276 min/kRad(Si)

Reference dose rate: 265.54 Rads(Si)/sec

Decay: 0.28837 min/kRad(Si)

Dose Rate: (Expected) 57.80 Rads(Si)/sec

(Range) 52.02 to 63.58 Rads(Si)/sec

C. EXPOSURE TIMES

Supply Current Starting	Separated Total-Dose kRads(Si)[1]	Total Dose kRads(Si)	Time mins	Time Seconds	Exposure Time (HHMM) Start	Exposure Time (HHMM) Stop	Serial Number	ATE Time (HHMM) Stop	Supply Current Ending
mA							See page 3		mA
142	100	100	28.85	1731	10:13	10:42	Biased		143
	10						9		
142	100	100	28.85	1731	10:48	11:17	Biased		144
	50						9		
632	100	100	28.85	1731	11:25	11:54	Biased		64
	100						4		
	100								
	100								
	100								

[1] Minumum dose is 450 Rads(Si) per cycle.

* See attached list

Bias Circuit: Dallas TPS7H1101 biased

Start Voltage: 5V

End Voltage: 5V

D. ELECTRICAL TESTS

Tester Type:

Station No: 1

Location: Dallas

Harness No:

Socket No.:

Test Box No:

Program Name:

Lot Names:

1-
2-
3-
4-
5-
6-
7-
8-

Test conducted by: Thang

Meter: Fluke 79, Cal # 07695500	8/23/2017
Agilent E3631A #0764388	1/11/2018
Fluke 8050 #076695052	11/01/17

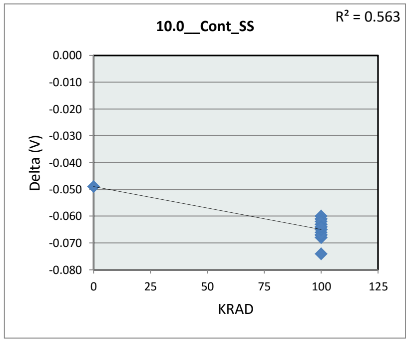
Delta Threshold 10.00%

TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

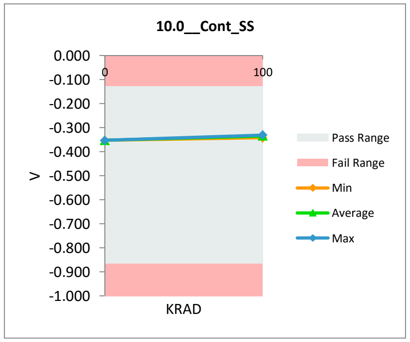
TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

	10.0__Cont_SS		
Test Site	CLAB	CLAB	
Tester	EAG03	EAG03	
Test Number	EF506901	EF506901	
Unit	V	V	
Max Limit	-0.127	-0.127	
Min Limit	-0.864	-0.864	

KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	-0.402	-0.353	-0.049
100	294	-0.401	-0.334	-0.067
100	296	-0.399	-0.336	-0.063
100	298	-0.405	-0.331	-0.074
100	299	-0.401	-0.336	-0.065
100	300	-0.402	-0.334	-0.068
100	301	-0.405	-0.340	-0.065
100	302	-0.400	-0.333	-0.067
100	303	-0.398	-0.333	-0.065
100	305	-0.398	-0.337	-0.061
100	307	-0.399	-0.333	-0.066
100	308	-0.403	-0.335	-0.068
100	309	-0.395	-0.335	-0.060
100	310	-0.400	-0.335	-0.065
100	312	-0.398	-0.331	-0.067
100	313	-0.398	-0.333	-0.065
100	314	-0.397	-0.332	-0.065
100	316	-0.400	-0.337	-0.063
100	317	-0.403	-0.342	-0.061
100	318	-0.397	-0.335	-0.062
100	320	-0.398	-0.334	-0.064
100	321	-0.401	-0.337	-0.064
100	322	-0.397	-0.333	-0.064
	Max	-0.395	-0.331	-0.049
	Average	-0.400	-0.336	-0.064
	Min	-0.405	-0.353	-0.074
	Std Dev	0.003	0.005	0.004

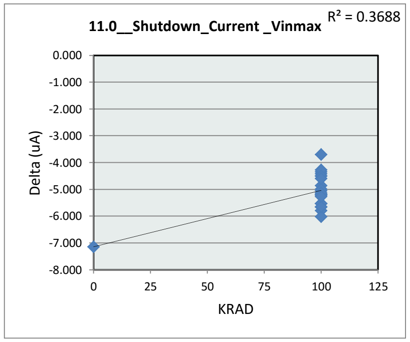


	10.0__Cont_SS	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	-0.127	V
Min Limit	-0.864	V
KRAD	0	100
LL	-0.864	-0.864
Min	-0.353	-0.342
Average	-0.353	-0.335
Max	-0.353	-0.331
UL	-0.127	-0.127

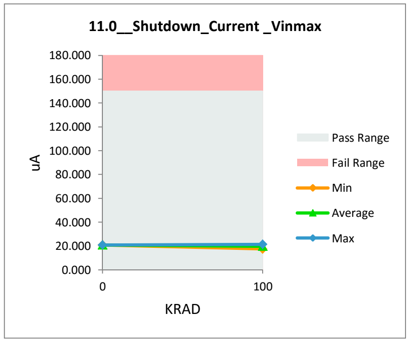


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		11.0__Shutdown_Current _Vinm		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	0.1	0.1	
KRAD	Serial #	PreRLAT_3-3-17.tx	101A-RLAT-POST_	Delta
0	C1	13.665	20.808	-7.143
100	294	14.639	18.988	-4.349
100	296	15.742	21.405	-5.663
100	298	14.822	18.523	-3.701
100	299	14.784	19.197	-4.413
100	300	14.240	18.746	-4.506
100	301	14.123	18.395	-4.272
100	302	15.007	20.058	-5.051
100	303	15.526	21.058	-5.532
100	305	15.040	19.902	-4.862
100	307	15.984	21.200	-5.216
100	308	14.272	19.265	-4.993
100	309	13.682	19.473	-5.791
100	310	15.012	20.192	-5.180
100	312	13.693	19.716	-6.023
100	313	14.454	19.984	-5.530
100	314	15.541	21.075	-5.534
100	316	14.887	20.539	-5.652
100	317	13.013	17.513	-4.500
100	318	13.425	18.025	-4.600
100	320	14.535	19.730	-5.195
100	321	15.482	20.620	-5.138
100	322	15.536	20.805	-5.269
	Max	15.984	21.405	-3.701
	Average	14.657	19.792	-5.135
	Min	13.013	17.513	-7.143
	Std Dev	0.802	1.082	0.721

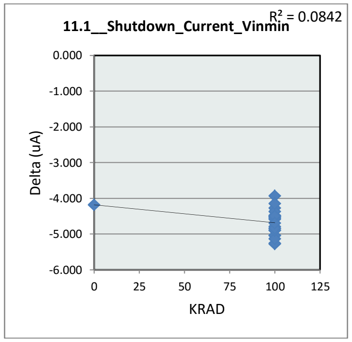


	11.0__Shutdown_Current _Vir	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	150	uA
Min Limit	0.1	uA
KRAD	0	100
LL	0.100	0.100
Min	20.808	17.513
Average	20.808	19.746
Max	20.808	21.405
UL	150.000	150.000

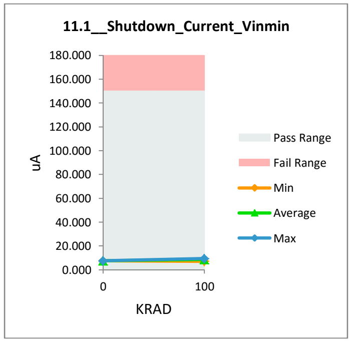


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		11.1__Shutdown_Current_Vinm		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	0.1	0.1	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	3.388	7.573	-4.185
100	294	3.674	8.178	-4.504
100	296	4.398	9.431	-5.033
100	298	3.341	7.927	-4.586
100	299	3.857	8.335	-4.478
100	300	3.434	7.936	-4.502
100	301	3.343	7.611	-4.268
100	302	4.023	8.865	-4.842
100	303	4.204	9.481	-5.277
100	305	4.180	8.552	-4.372
100	307	4.397	9.439	-5.042
100	308	3.605	8.397	-4.792
100	309	3.402	8.660	-5.258
100	310	4.183	8.719	-4.536
100	312	3.655	8.788	-5.133
100	313	3.901	8.795	-4.894
100	314	4.467	9.368	-4.901
100	316	4.182	9.018	-4.836
100	317	3.146	7.079	-3.933
100	318	3.417	7.560	-4.143
100	320	4.088	8.645	-4.557
100	321	4.500	8.995	-4.495
100	322	4.538	9.232	-4.694
	Max	4.538	9.481	-3.933
	Average	3.884	8.547	-4.664
	Min	3.146	7.079	-5.277
	Std Dev	0.443	0.681	0.359

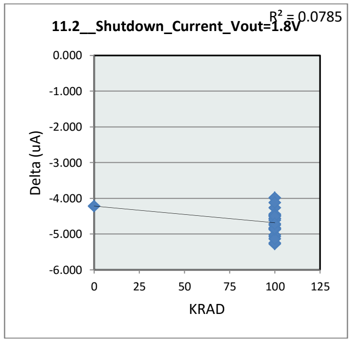


	11.1__Shutdown_Current_Vin	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	150	uA
Min Limit	0.1	uA
KRAD	0	100
LL	0.100	0.100
Min	7.573	7.079
Average	7.573	8.591
Max	7.573	9.481
UL	150.000	150.000

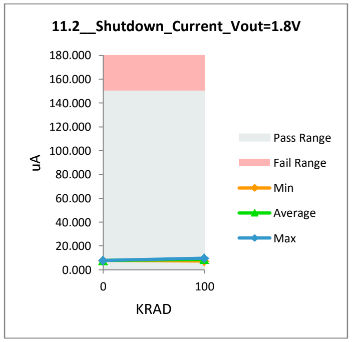


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		11.2__Shutdown_Current_Vout:		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	0.1	0.1	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	3.556	7.773	-4.217
100	294	3.897	8.367	-4.470
100	296	4.538	9.612	-5.074
100	298	3.556	8.126	-4.570
100	299	4.007	8.507	-4.500
100	300	3.645	8.126	-4.481
100	301	3.563	7.822	-4.259
100	302	4.246	9.078	-4.832
100	303	4.391	9.663	-5.272
100	305	4.310	8.748	-4.438
100	307	4.611	9.634	-5.023
100	308	3.826	8.576	-4.750
100	309	3.591	8.843	-5.252
100	310	4.337	8.907	-4.570
100	312	3.820	8.954	-5.134
100	313	4.115	8.969	-4.854
100	314	4.673	9.541	-4.868
100	316	4.352	9.200	-4.848
100	317	3.258	7.245	-3.987
100	318	3.592	7.710	-4.118
100	320	4.247	8.855	-4.608
100	321	4.684	9.189	-4.505
100	322	4.712	9.422	-4.710
	Max	4.712	9.663	-3.987
	Average	4.066	8.733	-4.667
	Min	3.258	7.245	-5.272
	Std Dev	0.441	0.682	0.350

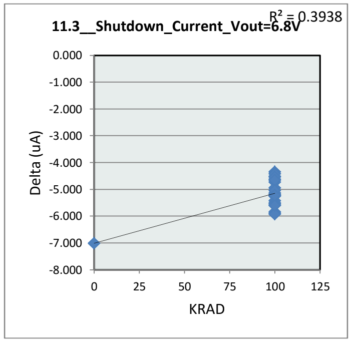


	11.2__Shutdown_Current_Vou	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	150	uA
Min Limit	0.1	uA
KRAD	0	100
LL	0.100	0.100
Min	7.773	7.245
Average	7.773	8.777
Max	7.773	9.663
UL	150.000	150.000

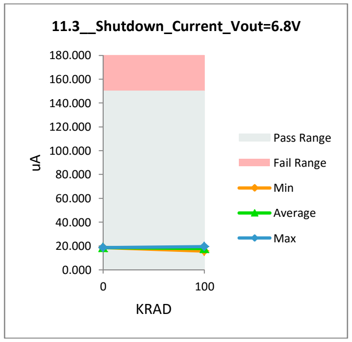


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		11.3__Shutdown_Current_Vout=		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	uA	uA	
	Max Limit	150	150	
	Min Limit	0.1	0.1	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	11.675	18.684	-7.009
100	294	12.682	17.197	-4.515
100	296	13.851	19.443	-5.592
100	298	12.354	16.702	-4.348
100	299	12.771	17.391	-4.620
100	300	12.076	16.802	-4.726
100	301	12.090	16.504	-4.414
100	302	13.049	18.298	-5.249
100	303	13.548	19.393	-5.845
100	305	13.116	18.063	-4.947
100	307	13.995	19.421	-5.426
100	308	12.169	17.394	-5.225
100	309	11.760	17.650	-5.890
100	310	13.209	18.345	-5.136
100	312	11.923	17.847	-5.924
100	313	12.675	18.185	-5.510
100	314	13.715	19.252	-5.537
100	316	13.095	18.696	-5.601
100	317	11.212	15.744	-4.532
100	318	11.568	16.226	-4.658
100	320	12.801	17.982	-5.181
100	321	13.725	18.765	-5.040
100	322	13.740	18.957	-5.217
	Max	13.995	19.443	-4.348
	Average	12.730	17.954	-5.224
	Min	11.212	15.744	-7.009
	Std Dev	0.820	1.074	0.620

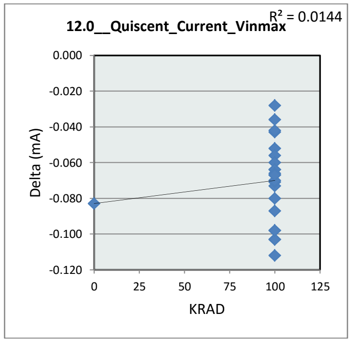


	11.3__Shutdown_Current_Vou	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	150	uA
Min Limit	0.1	uA
KRAD	0	100
LL	0.100	0.100
Min	18.684	15.744
Average	18.684	17.921
Max	18.684	19.443
UL	150.000	150.000

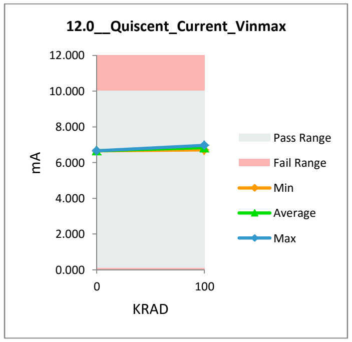


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		12.0__Quiscent_Current_Vinmax		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mA	mA	
	Max Limit	10	10	
	Min Limit	0.1	0.1	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.576	6.659	-0.083
100	294	6.816	6.868	-0.052
100	296	6.781	6.893	-0.112
100	298	6.604	6.702	-0.098
100	299	6.752	6.839	-0.087
100	300	6.695	6.768	-0.073
100	301	6.891	6.934	-0.043
100	302	6.723	6.826	-0.103
100	303	6.731	6.802	-0.071
100	305	6.732	6.788	-0.056
100	307	6.721	6.791	-0.070
100	308	6.704	6.784	-0.080
100	309	6.675	6.739	-0.064
100	310	6.902	6.962	-0.060
100	312	6.711	6.814	-0.103
100	313	6.841	6.905	-0.064
100	314	6.749	6.816	-0.067
100	316	6.880	6.946	-0.066
100	317	6.877	6.905	-0.028
100	318	6.604	6.702	-0.098
100	320	6.759	6.826	-0.067
100	321	6.871	6.913	-0.042
100	322	6.807	6.843	-0.036
	Max	6.902	6.962	-0.028
	Average	6.757	6.827	-0.071
	Min	6.576	6.659	-0.112
	Std Dev	0.094	0.081	0.023

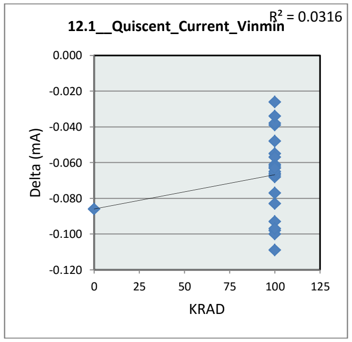


	12.0__Quiscent_Current_Vinm	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	10	mA
Min Limit	0.1	mA
KRAD	0	100
LL	0.100	0.100
Min	6.659	6.702
Average	6.659	6.835
Max	6.659	6.962
UL	10.000	10.000

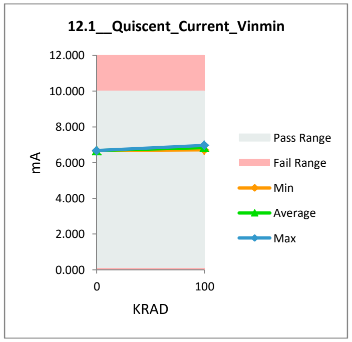


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		12.1__Quiscent_Current_Vinmin		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		mA	mA	
Max Limit		10	10	
Min Limit		0.1	0.1	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.589	6.675	-0.086
100	294	6.827	6.875	-0.048
100	296	6.789	6.898	-0.109
100	298	6.616	6.709	-0.093
100	299	6.765	6.848	-0.083
100	300	6.708	6.776	-0.068
100	301	6.895	6.934	-0.039
100	302	6.734	6.832	-0.098
100	303	6.743	6.809	-0.066
100	305	6.744	6.799	-0.055
100	307	6.733	6.800	-0.067
100	308	6.715	6.792	-0.077
100	309	6.685	6.746	-0.061
100	310	6.910	6.967	-0.057
100	312	6.721	6.821	-0.100
100	313	6.846	6.909	-0.063
100	314	6.762	6.824	-0.062
100	316	6.888	6.953	-0.065
100	317	6.879	6.905	-0.026
100	318	6.615	6.712	-0.097
100	320	6.769	6.832	-0.063
100	321	6.879	6.917	-0.038
100	322	6.815	6.849	-0.034
	Max	6.910	6.967	-0.026
	Average	6.766	6.834	-0.068
	Min	6.589	6.675	-0.109
	Std Dev	0.092	0.079	0.023

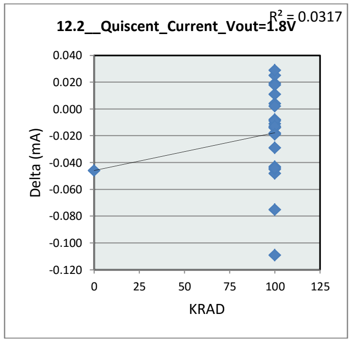


	12.1__Quiscent_Current_Vinm	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	10	mA
Min Limit	0.1	mA
KRAD	0	100
LL	0.100	0.100
Min	6.675	6.709
Average	6.675	6.841
Max	6.675	6.967
UL	10.000	10.000

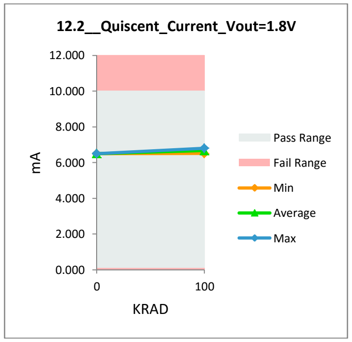


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		12.2__Quiscent_Current_Vout=		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mA	mA	
	Max Limit	10	10	
	Min Limit	0.1	0.1	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.457	6.503	-0.046
100	294	6.714	6.695	0.019
100	296	6.680	6.728	-0.048
100	298	6.483	6.512	-0.029
100	299	6.647	6.722	-0.075
100	300	6.584	6.693	-0.109
100	301	6.794	6.769	0.025
100	302	6.609	6.652	-0.043
100	303	6.620	6.628	-0.008
100	305	6.608	6.604	0.004
100	307	6.596	6.607	-0.011
100	308	6.583	6.597	-0.014
100	309	6.568	6.566	0.002
100	310	6.790	6.808	-0.018
100	312	6.595	6.640	-0.045
100	313	6.723	6.737	-0.014
100	314	6.632	6.641	-0.009
100	316	6.769	6.782	-0.013
100	317	6.771	6.742	0.029
100	318	6.478	6.522	-0.044
100	320	6.640	6.659	-0.019
100	321	6.754	6.743	0.011
100	322	6.689	6.671	0.018
	Max	6.794	6.808	0.029
	Average	6.643	6.662	-0.019
	Min	6.457	6.503	-0.109
	Std Dev	0.098	0.087	0.033

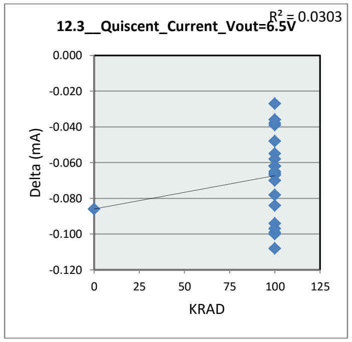


	12.2__Quiscent_Current_Vout	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	10	mA
Min Limit	0.1	mA
KRAD	0	100
LL	0.100	0.100
Min	6.503	6.512
Average	6.503	6.669
Max	6.503	6.808
UL	10.000	10.000

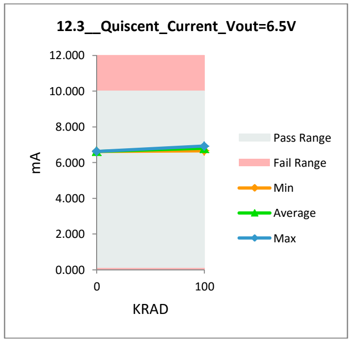


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		12.3__Quiscent_Current_Vout=		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mA	mA	
	Max Limit	10	10	
	Min Limit	0.1	0.1	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.544	6.630	-0.086
100	294	6.782	6.830	-0.048
100	296	6.744	6.852	-0.108
100	298	6.569	6.663	-0.094
100	299	6.719	6.803	-0.084
100	300	6.661	6.731	-0.070
100	301	6.849	6.888	-0.039
100	302	6.688	6.787	-0.099
100	303	6.697	6.763	-0.066
100	305	6.699	6.754	-0.055
100	307	6.688	6.755	-0.067
100	308	6.669	6.747	-0.078
100	309	6.639	6.701	-0.062
100	310	6.864	6.922	-0.058
100	312	6.674	6.774	-0.100
100	313	6.801	6.863	-0.062
100	314	6.717	6.779	-0.062
100	316	6.842	6.908	-0.066
100	317	6.833	6.860	-0.027
100	318	6.569	6.666	-0.097
100	320	6.723	6.788	-0.065
100	321	6.834	6.872	-0.038
100	322	6.769	6.805	-0.036
	Max	6.864	6.922	-0.027
	Average	6.721	6.789	-0.068
	Min	6.544	6.630	-0.108
	Std Dev	0.092	0.079	0.022

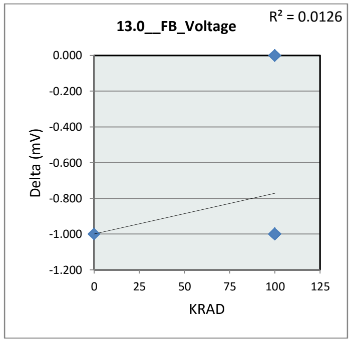


	12.3__Quiscent_Current_Vout	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	10	mA
Min Limit	0.1	mA
KRAD	0	100
LL	0.100	0.100
Min	6.630	6.663
Average	6.630	6.796
Max	6.630	6.922
UL	10.000	10.000

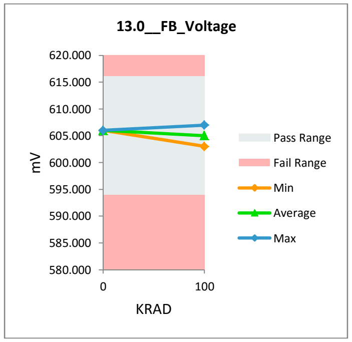


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.0__FB_Voltage		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	605.000	606.000	-1.000
100	294	604.000	605.000	-1.000
100	296	604.000	605.000	-1.000
100	298	604.000	605.000	-1.000
100	299	603.000	604.000	-1.000
100	300	603.000	603.000	0.000
100	301	606.000	606.000	0.000
100	302	605.000	605.000	0.000
100	303	606.000	607.000	-1.000
100	305	603.000	604.000	-1.000
100	307	604.000	605.000	-1.000
100	308	604.000	605.000	-1.000
100	309	606.000	606.000	0.000
100	310	605.000	606.000	-1.000
100	312	604.000	605.000	-1.000
100	313	604.000	605.000	-1.000
100	314	604.000	605.000	-1.000
100	316	606.000	607.000	-1.000
100	317	604.000	604.000	0.000
100	318	603.000	604.000	-1.000
100	320	604.000	605.000	-1.000
100	321	603.000	604.000	-1.000
100	322	604.000	605.000	-1.000
	Max	606.000	607.000	0.000
	Average	604.261	605.043	-0.783
	Min	603.000	603.000	-1.000
	Std Dev	1.010	0.976	0.422

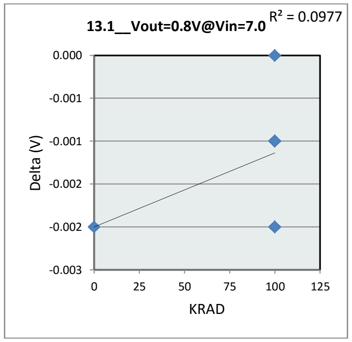


	13.0__FB_Voltage	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.000	603.000
Average	606.000	605.000
Max	606.000	607.000
UL	616.000	616.000

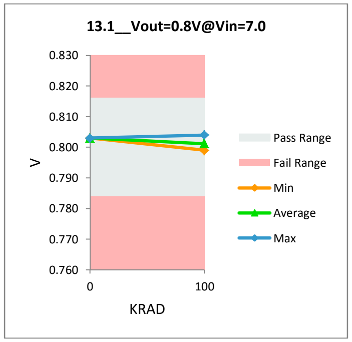


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.1__Vout=0.8V@Vin=7.0		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.801	0.803	-0.002
100	294	0.800	0.801	-0.001
100	296	0.800	0.801	-0.001
100	298	0.800	0.801	-0.001
100	299	0.798	0.800	-0.002
100	300	0.799	0.799	0.000
100	301	0.802	0.803	-0.001
100	302	0.800	0.802	-0.002
100	303	0.802	0.803	-0.001
100	305	0.798	0.799	-0.001
100	307	0.800	0.801	-0.001
100	308	0.800	0.802	-0.002
100	309	0.802	0.803	-0.001
100	310	0.801	0.802	-0.001
100	312	0.800	0.801	-0.001
100	313	0.800	0.801	-0.001
100	314	0.800	0.801	-0.001
100	316	0.802	0.804	-0.002
100	317	0.800	0.800	0.000
100	318	0.799	0.800	-0.001
100	320	0.800	0.801	-0.001
100	321	0.799	0.800	-0.001
100	322	0.799	0.801	-0.002
	Max	0.802	0.804	0.000
	Average	0.800	0.801	-0.001
	Min	0.798	0.799	-0.002
	Std Dev	0.001	0.001	0.001

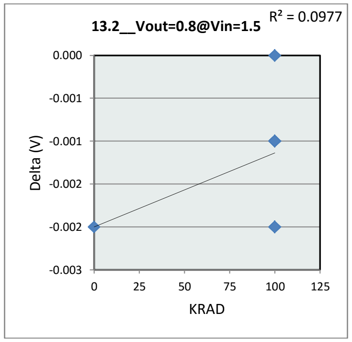


	13.1__Vout=0.8V@Vin=7.0	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.816	V
Min Limit	0.784	V
KRAD	0	100
LL	0.784	0.784
Min	0.803	0.799
Average	0.803	0.801
Max	0.803	0.804
UL	0.816	0.816

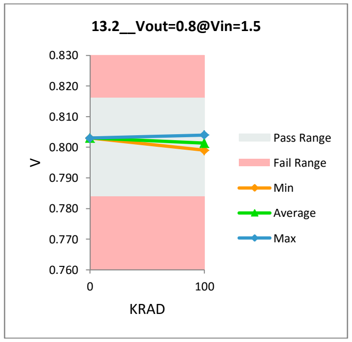


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.2__Vout=0.8@Vin=1.5		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.801	0.803	-0.002
100	294	0.800	0.801	-0.001
100	296	0.800	0.801	-0.001
100	298	0.800	0.801	-0.001
100	299	0.798	0.800	-0.002
100	300	0.799	0.799	0.000
100	301	0.802	0.803	-0.001
100	302	0.801	0.802	-0.001
100	303	0.802	0.804	-0.002
100	305	0.799	0.800	-0.001
100	307	0.800	0.801	-0.001
100	308	0.800	0.802	-0.002
100	309	0.803	0.803	0.000
100	310	0.801	0.802	-0.001
100	312	0.800	0.801	-0.001
100	313	0.800	0.801	-0.001
100	314	0.800	0.801	-0.001
100	316	0.802	0.804	-0.002
100	317	0.800	0.801	-0.001
100	318	0.799	0.800	-0.001
100	320	0.800	0.801	-0.001
100	321	0.799	0.800	-0.001
100	322	0.799	0.801	-0.002
	Max	0.803	0.804	0.000
	Average	0.800	0.801	-0.001
	Min	0.798	0.799	-0.002
	Std Dev	0.001	0.001	0.001

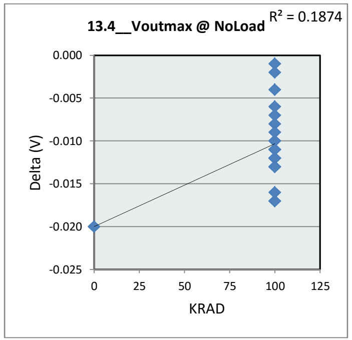


	13.2__Vout=0.8@Vin=1.5	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.816	V
Min Limit	0.784	V
KRAD	0	100
LL	0.784	0.784
Min	0.803	0.799
Average	0.803	0.801
Max	0.803	0.804
UL	0.816	0.816

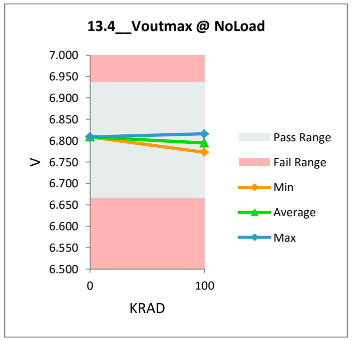


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.4__Voutmax @ NoLoad		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	6.936	6.936	
	Min Limit	6.666	6.666	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.789	6.809	-0.020
100	294	6.783	6.795	-0.012
100	296	6.780	6.793	-0.013
100	298	6.783	6.790	-0.007
100	299	6.767	6.784	-0.017
100	300	6.772	6.773	-0.001
100	301	6.802	6.808	-0.006
100	302	6.789	6.799	-0.010
100	303	6.803	6.814	-0.011
100	305	6.770	6.781	-0.011
100	307	6.782	6.794	-0.012
100	308	6.781	6.798	-0.017
100	309	6.805	6.807	-0.002
100	310	6.791	6.803	-0.012
100	312	6.786	6.794	-0.008
100	313	6.782	6.795	-0.013
100	314	6.783	6.793	-0.010
100	316	6.804	6.816	-0.012
100	317	6.785	6.789	-0.004
100	318	6.775	6.784	-0.009
100	320	6.784	6.795	-0.011
100	321	6.772	6.788	-0.016
100	322	6.778	6.791	-0.013
	Max	6.805	6.816	-0.001
	Average	6.785	6.795	-0.011
	Min	6.767	6.773	-0.020
	Std Dev	0.011	0.011	0.005

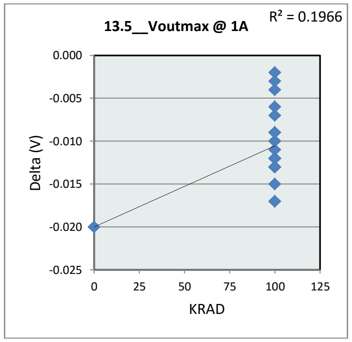


	13.4__Voutmax @ NoLoad	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	6.936	V
Min Limit	6.666	V
KRAD	0	100
LL	6.666	6.666
Min	6.809	6.773
Average	6.809	6.795
Max	6.809	6.816
UL	6.936	6.936

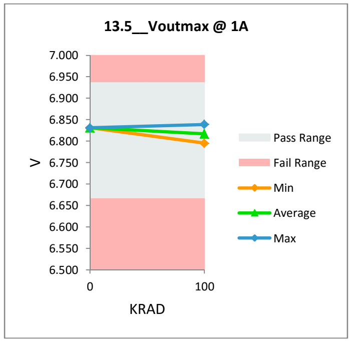


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.5__Voutmax @ 1A		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	6.936	6.936	
	Min Limit	6.666	6.666	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.811	6.831	-0.020
100	294	6.805	6.817	-0.012
100	296	6.802	6.815	-0.013
100	298	6.805	6.812	-0.007
100	299	6.789	6.806	-0.017
100	300	6.793	6.795	-0.002
100	301	6.824	6.830	-0.006
100	302	6.811	6.821	-0.010
100	303	6.825	6.837	-0.012
100	305	6.792	6.803	-0.011
100	307	6.804	6.816	-0.012
100	308	6.803	6.820	-0.017
100	309	6.827	6.830	-0.003
100	310	6.813	6.825	-0.012
100	312	6.808	6.817	-0.009
100	313	6.804	6.817	-0.013
100	314	6.805	6.815	-0.010
100	316	6.826	6.839	-0.013
100	317	6.807	6.811	-0.004
100	318	6.796	6.805	-0.009
100	320	6.806	6.818	-0.012
100	321	6.794	6.809	-0.015
100	322	6.800	6.813	-0.013
	Max	6.827	6.839	-0.002
	Average	6.807	6.817	-0.011
	Min	6.789	6.795	-0.020
	Std Dev	0.011	0.011	0.004



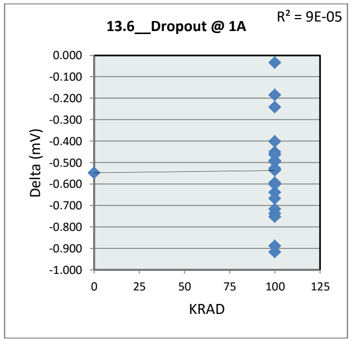
	13.5__Voutmax @ 1A	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	6.936	V
Min Limit	6.666	V
KRAD	0	100
LL	6.666	6.666
Min	6.831	6.795
Average	6.831	6.817
Max	6.831	6.839
UL	6.936	6.936



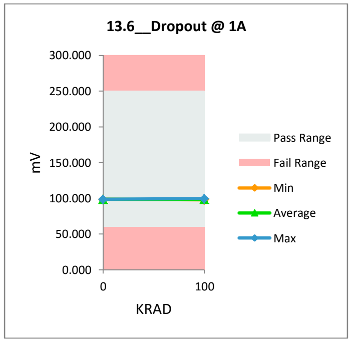
TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

	13.6__Dropout @ 1A	
Test Site	CLAB	CLAB
Tester	EAG03	EAG03
Test Number	EF506901	EF506901
Unit	mV	mV
Max Limit	250	250
Min Limit	60	60

KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	98.085	98.632	-0.547
100	294	97.976	98.693	-0.717
100	296	97.977	98.219	-0.242
100	298	97.718	98.212	-0.494
100	299	97.679	98.080	-0.401
100	300	97.748	98.199	-0.451
100	301	98.736	99.270	-0.534
100	302	97.926	98.462	-0.536
100	303	98.419	99.307	-0.888
100	305	97.334	97.928	-0.594
100	307	97.610	98.137	-0.527
100	308	97.650	98.289	-0.639
100	309	98.833	98.867	-0.034
100	310	98.110	98.847	-0.737
100	312	97.919	98.672	-0.753
100	313	97.857	98.524	-0.667
100	314	97.725	98.216	-0.491
100	316	98.586	99.503	-0.917
100	317	98.063	98.247	-0.184
100	318	97.764	98.226	-0.462
100	320	97.717	98.319	-0.602
100	321	97.568	98.031	-0.463
100	322	97.854	98.350	-0.496
	Max	98.833	99.503	-0.034
	Average	97.950	98.488	-0.538
	Min	97.334	97.928	-0.917
	Std Dev	0.378	0.427	0.205



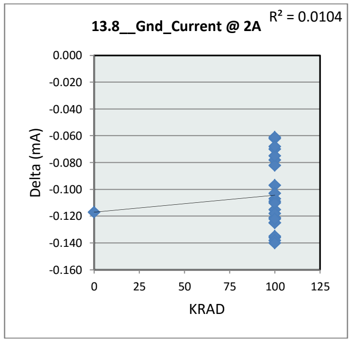
	13.6__Dropout @ 1A	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	250	mV
Min Limit	60	mV
KRAD	0	100
LL	60.000	60.000
Min	98.632	97.928
Average	98.632	98.482
Max	98.632	99.503
UL	250.000	250.000



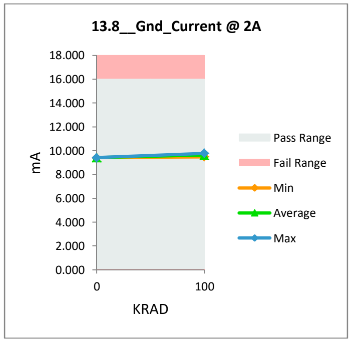
TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

	13.8__Gnd_Current @ 2A	
Test Site	CLAB	CLAB
Tester	EAG03	EAG03
Test Number	EF506901	EF506901
Unit	mA	mA
Max Limit	16	16
Min Limit	0.1	0.1

KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	9.303	9.420	-0.117
100	294	9.607	9.704	-0.097
100	296	9.562	9.687	-0.125
100	298	9.351	9.487	-0.136
100	299	9.534	9.669	-0.135
100	300	9.455	9.533	-0.078
100	301	9.603	9.665	-0.062
100	302	9.477	9.615	-0.138
100	303	9.499	9.560	-0.061
100	305	9.503	9.585	-0.082
100	307	9.515	9.655	-0.140
100	308	9.393	9.500	-0.107
100	309	9.418	9.539	-0.121
100	310	9.663	9.772	-0.109
100	312	9.451	9.566	-0.115
100	313	9.615	9.733	-0.118
100	314	9.537	9.647	-0.110
100	316	9.650	9.775	-0.125
100	317	9.635	9.705	-0.070
100	318	9.371	9.493	-0.122
100	320	9.532	9.635	-0.103
100	321	9.645	9.720	-0.075
100	322	9.581	9.649	-0.068
	Max	9.663	9.775	-0.061
	Average	9.517	9.622	-0.105
	Min	9.303	9.420	-0.140
	Std Dev	0.103	0.097	0.026

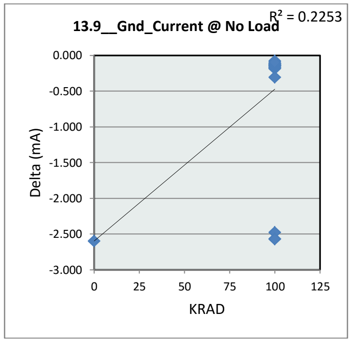


	13.8__Gnd_Current @ 2A	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	16	mA
Min Limit	0.1	mA
KRAD	0	100
LL	0.100	0.100
Min	9.420	9.487
Average	9.420	9.632
Max	9.420	9.775
UL	16.000	16.000

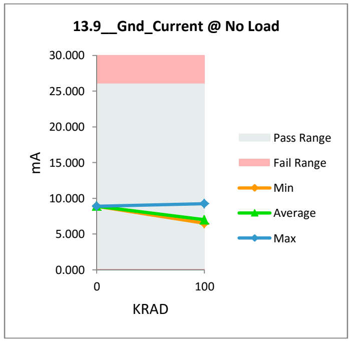


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.9__Gnd_Current @ No Load		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mA	mA	
	Max Limit	26	26	
	Min Limit	0.1	0.1	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.312	8.910	-2.598
100	294	6.549	6.668	-0.119
100	296	6.513	6.695	-0.182
100	298	6.340	6.497	-0.157
100	299	6.483	6.650	-0.167
100	300	6.417	6.549	-0.132
100	301	6.646	9.122	-2.476
100	302	6.437	6.625	-0.188
100	303	6.518	9.082	-2.564
100	305	6.467	6.586	-0.119
100	307	6.459	6.602	-0.143
100	308	6.437	6.576	-0.139
100	309	6.509	6.814	-0.305
100	310	6.637	6.779	-0.142
100	312	6.447	6.616	-0.169
100	313	6.561	6.697	-0.136
100	314	6.494	6.635	-0.141
100	316	6.679	9.251	-2.572
100	317	6.609	6.688	-0.079
100	318	6.360	6.507	-0.147
100	320	6.506	6.625	-0.119
100	321	6.606	6.722	-0.116
100	322	6.547	6.644	-0.097
	Max	6.679	9.251	-0.079
	Average	6.501	7.067	-0.566
	Min	6.312	6.497	-2.598
	Std Dev	0.097	0.954	0.933

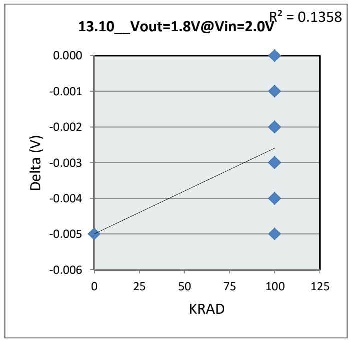


	13.9__Gnd_Current @ No Load	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	26	mA
Min Limit	0.1	mA
KRAD	0	100
LL	0.100	0.100
Min	8.910	6.497
Average	8.910	6.983
Max	8.910	9.251
UL	26.000	26.000

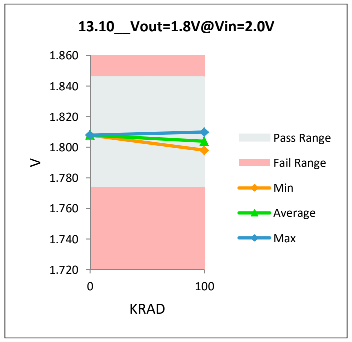


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.10__Vout=1.8V@Vin=2.0V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.846	1.846	
	Min Limit	1.774	1.774	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.803	1.808	-0.005
100	294	1.801	1.804	-0.003
100	296	1.800	1.804	-0.004
100	298	1.801	1.803	-0.002
100	299	1.797	1.801	-0.004
100	300	1.798	1.798	0.000
100	301	1.806	1.807	-0.001
100	302	1.802	1.805	-0.003
100	303	1.806	1.809	-0.003
100	305	1.798	1.800	-0.002
100	307	1.801	1.804	-0.003
100	308	1.800	1.805	-0.005
100	309	1.807	1.807	0.000
100	310	1.803	1.806	-0.003
100	312	1.802	1.804	-0.002
100	313	1.801	1.804	-0.003
100	314	1.801	1.803	-0.002
100	316	1.806	1.810	-0.004
100	317	1.801	1.802	-0.001
100	318	1.799	1.801	-0.002
100	320	1.801	1.804	-0.003
100	321	1.798	1.802	-0.004
100	322	1.800	1.803	-0.003
	Max	1.807	1.810	0.000
	Average	1.801	1.804	-0.003
	Min	1.797	1.798	-0.005
	Std Dev	0.003	0.003	0.001

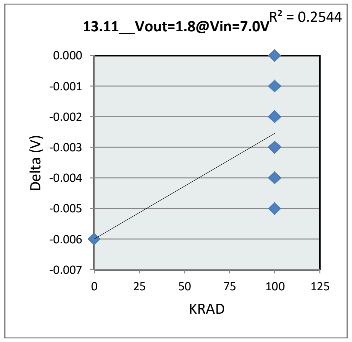


	13.10__Vout=1.8V@Vin=2.0V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.846	V
Min Limit	1.774	V
KRAD	0	100
LL	1.774	1.774
Min	1.808	1.798
Average	1.808	1.804
Max	1.808	1.810
UL	1.846	1.846

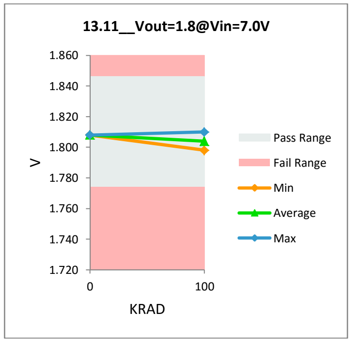


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.11__Vout=1.8@Vin=7.0V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.846	1.846	
	Min Limit	1.774	1.774	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.802	1.808	-0.006
100	294	1.801	1.804	-0.003
100	296	1.800	1.803	-0.003
100	298	1.801	1.803	-0.002
100	299	1.797	1.801	-0.004
100	300	1.798	1.798	0.000
100	301	1.806	1.807	-0.001
100	302	1.802	1.805	-0.003
100	303	1.806	1.809	-0.003
100	305	1.798	1.800	-0.002
100	307	1.801	1.804	-0.003
100	308	1.800	1.805	-0.005
100	309	1.807	1.807	0.000
100	310	1.803	1.806	-0.003
100	312	1.802	1.804	-0.002
100	313	1.801	1.804	-0.003
100	314	1.801	1.803	-0.002
100	316	1.806	1.810	-0.004
100	317	1.801	1.802	-0.001
100	318	1.799	1.801	-0.002
100	320	1.801	1.804	-0.003
100	321	1.798	1.802	-0.004
100	322	1.800	1.803	-0.003
	Max	1.807	1.810	0.000
	Average	1.801	1.804	-0.003
	Min	1.797	1.798	-0.006
	Std Dev	0.003	0.003	0.001

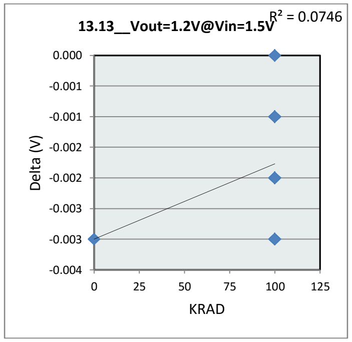


	13.11__Vout=1.8@Vin=7.0V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.846	V
Min Limit	1.774	V
KRAD	0	100
LL	1.774	1.774
Min	1.808	1.798
Average	1.808	1.804
Max	1.808	1.810
UL	1.846	1.846

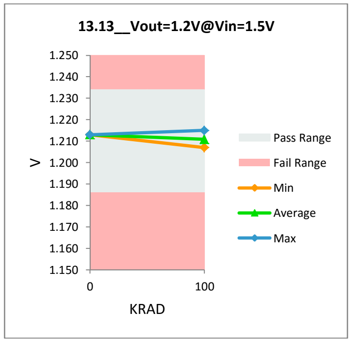


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.13__Vout=1.2V@Vin=1.5V		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		V	V	
Max Limit		1.234	1.234	
Min Limit		1.186	1.186	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.210	1.213	-0.003
100	294	1.209	1.211	-0.002
100	296	1.208	1.211	-0.003
100	298	1.209	1.210	-0.001
100	299	1.206	1.209	-0.003
100	300	1.207	1.207	0.000
100	301	1.212	1.213	-0.001
100	302	1.210	1.211	-0.001
100	303	1.212	1.214	-0.002
100	305	1.207	1.208	-0.001
100	307	1.209	1.211	-0.002
100	308	1.208	1.211	-0.003
100	309	1.213	1.213	0.000
100	310	1.210	1.212	-0.002
100	312	1.209	1.211	-0.002
100	313	1.209	1.211	-0.002
100	314	1.209	1.210	-0.001
100	316	1.212	1.215	-0.003
100	317	1.209	1.210	-0.001
100	318	1.207	1.209	-0.002
100	320	1.209	1.211	-0.002
100	321	1.207	1.210	-0.003
100	322	1.208	1.210	-0.002
	Max	1.213	1.215	0.000
	Average	1.209	1.211	-0.002
	Min	1.206	1.207	-0.003
	Std Dev	0.002	0.002	0.001

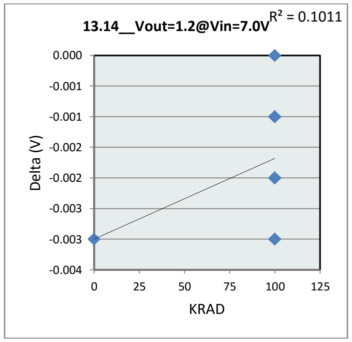


	13.13__Vout=1.2V@Vin=1.5V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.234	V
Min Limit	1.186	V
KRAD	0	100
LL	1.186	1.186
Min	1.213	1.207
Average	1.213	1.211
Max	1.213	1.215
UL	1.234	1.234

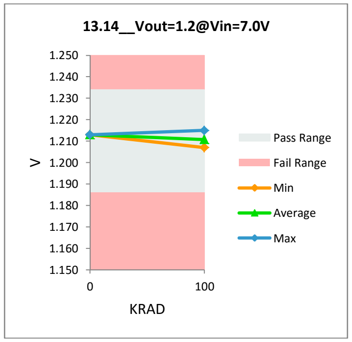


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.14__Vout=1.2@Vin=7.0V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.234	1.234	
	Min Limit	1.186	1.186	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.210	1.213	-0.003
100	294	1.209	1.211	-0.002
100	296	1.208	1.210	-0.002
100	298	1.209	1.210	-0.001
100	299	1.206	1.209	-0.003
100	300	1.207	1.207	0.000
100	301	1.212	1.213	-0.001
100	302	1.210	1.211	-0.001
100	303	1.212	1.214	-0.002
100	305	1.207	1.208	-0.001
100	307	1.209	1.211	-0.002
100	308	1.208	1.211	-0.003
100	309	1.213	1.213	0.000
100	310	1.210	1.212	-0.002
100	312	1.209	1.211	-0.002
100	313	1.209	1.211	-0.002
100	314	1.209	1.210	-0.001
100	316	1.212	1.215	-0.003
100	317	1.209	1.210	-0.001
100	318	1.207	1.209	-0.002
100	320	1.209	1.211	-0.002
100	321	1.207	1.209	-0.002
100	322	1.208	1.210	-0.002
	Max	1.213	1.215	0.000
	Average	1.209	1.211	-0.002
	Min	1.206	1.207	-0.003
	Std Dev	0.002	0.002	0.001

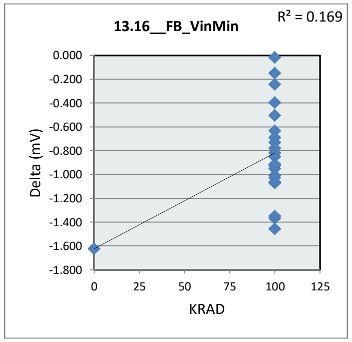


	13.14__Vout=1.2@Vin=7.0V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.234	V
Min Limit	1.186	V
KRAD	0	100
LL	1.186	1.186
Min	1.213	1.207
Average	1.213	1.211
Max	1.213	1.215
UL	1.234	1.234

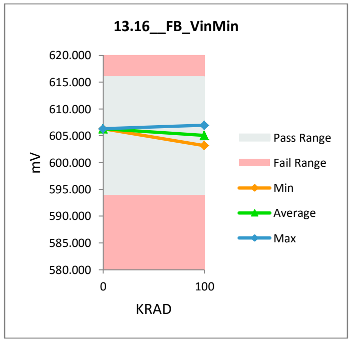


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.16__FB_VinMin		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.687	606.310	-1.623
100	294	604.216	605.224	-1.008
100	296	603.939	604.965	-1.026
100	298	604.170	604.675	-0.505
100	299	602.670	604.037	-1.367
100	300	603.154	603.172	-0.018
100	301	605.780	606.176	-0.396
100	302	604.542	605.361	-0.819
100	303	605.872	606.824	-0.952
100	305	602.987	603.765	-0.778
100	307	604.037	604.961	-0.924
100	308	603.911	605.366	-1.455
100	309	605.991	606.139	-0.148
100	310	604.858	605.709	-0.851
100	312	604.385	605.018	-0.633
100	313	604.020	605.091	-1.071
100	314	604.170	604.860	-0.690
100	316	605.908	606.971	-1.063
100	317	604.252	604.495	-0.243
100	318	603.430	604.161	-0.731
100	320	604.189	605.101	-0.912
100	321	603.152	604.500	-1.348
100	322	603.629	604.693	-1.064
	Max	605.991	606.971	-0.018
	Average	604.259	605.112	-0.853
	Min	602.670	603.172	-1.623
	Std Dev	0.937	0.939	0.408

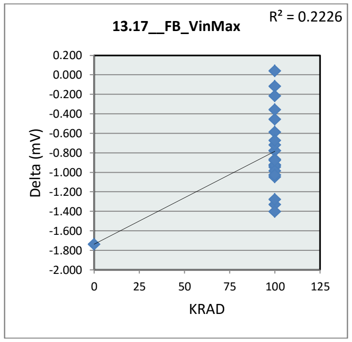


	13.16__FB_VinMin	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.310	603.172
Average	606.310	605.057
Max	606.310	606.971
UL	616.000	616.000

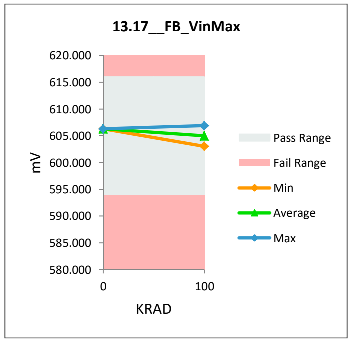


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		13.17__FB_VinMax		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.570	606.308	-1.738
100	294	604.081	605.003	-0.922
100	296	603.822	604.851	-1.029
100	298	604.070	604.527	-0.457
100	299	602.681	604.010	-1.329
100	300	603.081	603.040	0.041
100	301	605.759	606.115	-0.356
100	302	604.595	605.374	-0.779
100	303	605.812	606.756	-0.944
100	305	602.951	603.730	-0.779
100	307	603.997	604.927	-0.930
100	308	603.884	605.288	-1.404
100	309	605.990	606.107	-0.117
100	310	604.805	605.672	-0.867
100	312	604.371	604.958	-0.587
100	313	603.961	605.008	-1.047
100	314	604.100	604.818	-0.718
100	316	605.909	606.893	-0.984
100	317	604.240	604.456	-0.216
100	318	603.333	604.005	-0.672
100	320	604.177	605.053	-0.876
100	321	603.082	604.361	-1.279
100	322	603.657	604.686	-1.029
	Max	605.990	606.893	0.041
	Average	604.214	605.041	-0.827
	Min	602.681	603.040	-1.738
	Std Dev	0.945	0.953	0.421

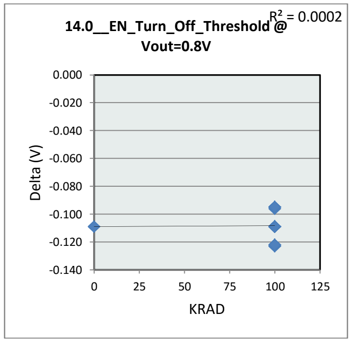


	13.17__FB_VinMax	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.308	603.040
Average	606.308	604.984
Max	606.308	606.893
UL	616.000	616.000

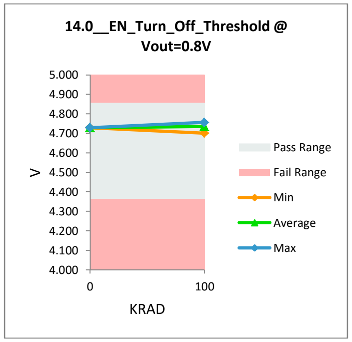


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		14.0__EN_Turn_Off_Threshold @		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	4.855	4.855	
	Min Limit	4.363	4.363	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	4.620	4.729	-0.109
100	294	4.661	4.756	-0.095
100	296	4.620	4.742	-0.122
100	298	4.620	4.742	-0.122
100	299	4.620	4.729	-0.109
100	300	4.633	4.742	-0.109
100	301	4.633	4.729	-0.096
100	302	4.620	4.729	-0.109
100	303	4.633	4.756	-0.123
100	305	4.620	4.715	-0.095
100	307	4.633	4.742	-0.109
100	308	4.620	4.715	-0.095
100	309	4.606	4.701	-0.095
100	310	4.620	4.729	-0.109
100	312	4.606	4.729	-0.123
100	313	4.647	4.756	-0.109
100	314	4.620	4.729	-0.109
100	316	4.620	4.742	-0.122
100	317	4.620	4.715	-0.095
100	318	4.633	4.742	-0.109
100	320	4.620	4.729	-0.109
100	321	4.647	4.756	-0.109
100	322	4.647	4.756	-0.109
	Max	4.661	4.756	-0.095
	Average	4.627	4.735	-0.108
	Min	4.606	4.701	-0.123
	Std Dev	0.013	0.015	0.010

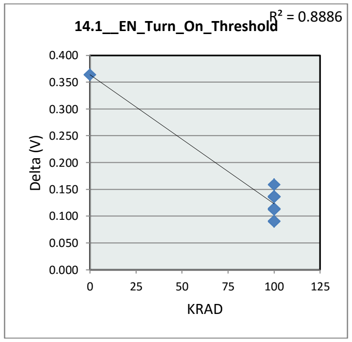


	14.0__EN_Turn_Off_Threshold	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	4.855	V
Min Limit	4.363	V
KRAD	0	100
LL	4.363	4.363
Min	4.729	4.701
Average	4.729	4.736
Max	4.729	4.756
UL	4.855	4.855

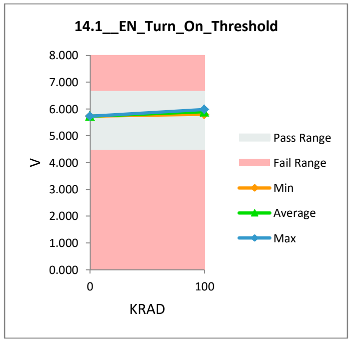


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		14.1__EN_Turn_On_Threshold		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	6.65	6.65	
	Min Limit	4.473	4.473	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.095	5.731	0.364
100	294	6.049	5.936	0.113
100	296	5.959	5.822	0.137
100	298	6.095	5.959	0.136
100	299	6.027	5.890	0.137
100	300	6.095	5.959	0.136
100	301	6.049	5.959	0.090
100	302	6.004	5.868	0.136
100	303	5.959	5.822	0.137
100	305	5.981	5.868	0.113
100	307	5.959	5.822	0.137
100	308	6.072	5.959	0.113
100	309	6.095	5.981	0.114
100	310	5.959	5.845	0.114
100	312	6.072	5.913	0.159
100	313	6.004	5.868	0.136
100	314	5.913	5.799	0.114
100	316	5.981	5.845	0.136
100	317	6.072	5.959	0.113
100	318	6.095	5.959	0.136
100	320	5.981	5.868	0.113
100	321	5.913	5.822	0.091
100	322	5.959	5.868	0.091
	Max	6.095	5.981	0.364
	Average	6.017	5.884	0.133
	Min	5.913	5.731	0.090
	Std Dev	0.062	0.066	0.053

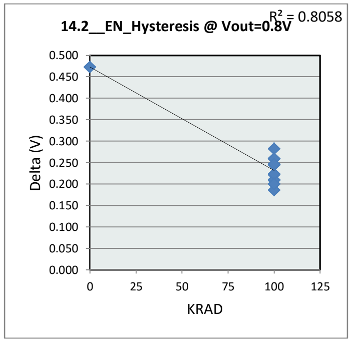


	14.1__EN_Turn_On_Threshold	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	6.65	V
Min Limit	4.473	V
KRAD	0	100
LL	4.473	4.473
Min	5.731	5.799
Average	5.731	5.891
Max	5.731	5.981
UL	6.650	6.650

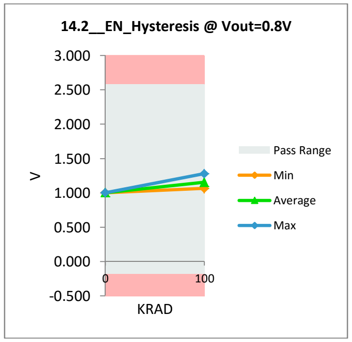


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		14.2__EN_Hysteresis @ Vout=0.		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	2.577	2.577	
	Min Limit	-0.179	-0.179	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.475	1.002	0.473
100	294	1.389	1.180	0.209
100	296	1.339	1.080	0.259
100	298	1.475	1.216	0.259
100	299	1.407	1.162	0.245
100	300	1.462	1.216	0.246
100	301	1.416	1.230	0.186
100	302	1.384	1.139	0.245
100	303	1.325	1.066	0.259
100	305	1.362	1.153	0.209
100	307	1.325	1.080	0.245
100	308	1.453	1.243	0.210
100	309	1.489	1.280	0.209
100	310	1.339	1.116	0.223
100	312	1.466	1.184	0.282
100	313	1.357	1.112	0.245
100	314	1.293	1.071	0.222
100	316	1.362	1.103	0.259
100	317	1.453	1.243	0.210
100	318	1.462	1.216	0.246
100	320	1.362	1.139	0.223
100	321	1.266	1.066	0.200
100	322	1.312	1.112	0.200
	Max	1.489	1.280	0.473
	Average	1.390	1.148	0.242
	Min	1.266	1.002	0.186
	Std Dev	0.067	0.072	0.056



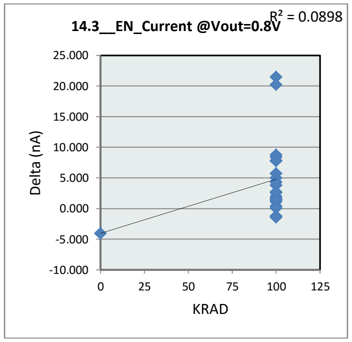
	14.2__EN_Hysteresis @ Vout=	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	2.577	V
Min Limit	-0.179	V
KRAD	0	100
LL	-0.179	-0.179
Min	1.002	1.066
Average	1.002	1.155
Max	1.002	1.280
UL	2.577	2.577



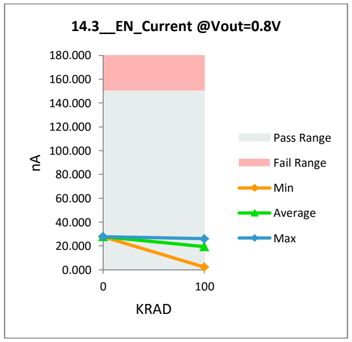
TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

	14.3__EN_Current @Vout=0.8V	
Test Site	CLAB	CLAB
Tester	EAG03	EAG03
Test Number	EF506901	EF506901
Unit	nA	nA
Max Limit	150	150
Min Limit	0.1	0.1

KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	23.860	27.904	-4.044
100	294	23.255	21.755	1.500
100	296	25.045	23.569	1.476
100	298	24.307	15.558	8.749
100	299	23.702	22.556	1.146
100	300	27.456	21.747	5.709
100	301	23.844	2.349	21.495
100	302	24.959	19.980	4.979
100	303	23.490	21.535	1.955
100	305	24.362	16.611	7.751
100	307	24.056	23.648	0.408
100	308	25.854	5.655	20.199
100	309	24.205	20.420	3.785
100	310	24.189	21.621	2.568
100	312	23.538	19.234	4.304
100	313	22.509	23.726	-1.217
100	314	23.318	21.967	1.351
100	316	24.598	16.202	8.396
100	317	24.566	26.027	-1.461
100	318	23.357	21.731	1.626
100	320	22.925	22.823	0.102
100	321	25.713	17.883	7.830
100	322	23.805	21.119	2.686
	Max	27.456	27.904	21.495
	Average	24.214	19.810	4.404
	Min	22.509	2.349	-4.044
	Std Dev	1.081	5.799	6.144

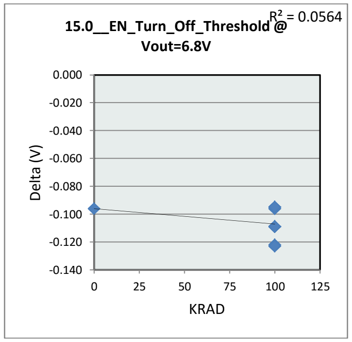


	14.3__EN_Current @Vout=0.8	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	150	nA
Min Limit	0.1	nA
KRAD	0	100
LL	0.100	0.100
Min	27.904	2.349
Average	27.904	19.442
Max	27.904	26.027
UL	150.000	150.000

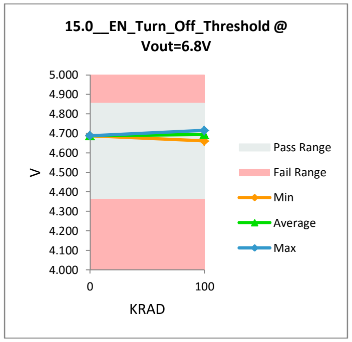


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		15.0__EN_Turn_Off_Threshold		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	4.855	4.855	
	Min Limit	4.363	4.363	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	4.592	4.688	-0.096
100	294	4.620	4.715	-0.095
100	296	4.579	4.701	-0.122
100	298	4.579	4.701	-0.122
100	299	4.579	4.688	-0.109
100	300	4.592	4.701	-0.109
100	301	4.592	4.688	-0.096
100	302	4.579	4.688	-0.109
100	303	4.592	4.715	-0.123
100	305	4.579	4.674	-0.095
100	307	4.592	4.701	-0.109
100	308	4.579	4.674	-0.095
100	309	4.565	4.661	-0.096
100	310	4.579	4.688	-0.109
100	312	4.565	4.688	-0.123
100	313	4.606	4.715	-0.109
100	314	4.579	4.688	-0.109
100	316	4.592	4.701	-0.109
100	317	4.579	4.674	-0.095
100	318	4.592	4.701	-0.109
100	320	4.579	4.688	-0.109
100	321	4.620	4.715	-0.095
100	322	4.606	4.715	-0.109
	Max	4.620	4.715	-0.095
	Average	4.588	4.694	-0.107
	Min	4.565	4.661	-0.123
	Std Dev	0.015	0.015	0.010

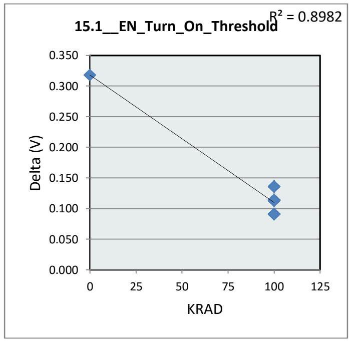


	15.0__EN_Turn_Off_Threshold	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	4.855	V
Min Limit	4.363	V
KRAD	0	100
LL	4.363	4.363
Min	4.688	4.661
Average	4.688	4.695
Max	4.688	4.715
UL	4.855	4.855

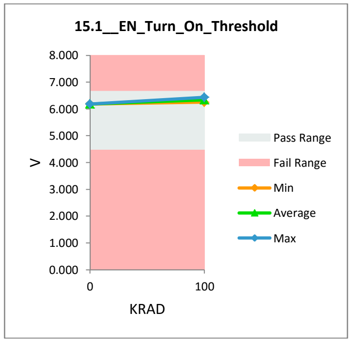


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		15.1__EN_Turn_On_Threshold		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		V	V	
Max Limit		6.65	6.65	
Min Limit		4.473	4.473	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.504	6.186	0.318
100	294	6.482	6.391	0.091
100	296	6.391	6.277	0.114
100	298	6.527	6.391	0.136
100	299	6.459	6.345	0.114
100	300	6.504	6.391	0.113
100	301	6.504	6.413	0.091
100	302	6.436	6.322	0.114
100	303	6.413	6.277	0.136
100	305	6.413	6.322	0.091
100	307	6.391	6.277	0.114
100	308	6.482	6.391	0.091
100	309	6.527	6.436	0.091
100	310	6.413	6.300	0.113
100	312	6.504	6.368	0.136
100	313	6.436	6.322	0.114
100	314	6.368	6.254	0.114
100	316	6.436	6.322	0.114
100	317	6.504	6.391	0.113
100	318	6.504	6.391	0.113
100	320	6.436	6.322	0.114
100	321	6.368	6.277	0.091
100	322	6.391	6.300	0.091
	Max	6.527	6.436	0.318
	Average	6.452	6.333	0.119
	Min	6.368	6.186	0.091
	Std Dev	0.052	0.061	0.046

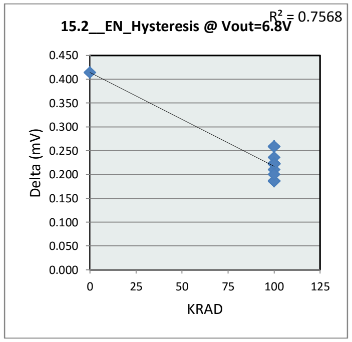


	15.1__EN_Turn_On_Threshold	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	6.65	V
Min Limit	4.473	V
KRAD	0	100
LL	4.473	4.473
Min	6.186	6.254
Average	6.186	6.340
Max	6.186	6.436
UL	6.650	6.650

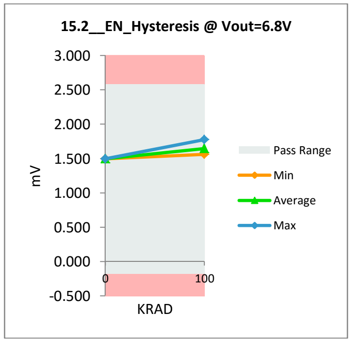


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		15.2__EN_Hysteresis @ Vout=6.		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	2.577	2.577	
	Min Limit	-0.179	-0.179	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.912	1.498	0.414
100	294	1.862	1.676	0.186
100	296	1.812	1.576	0.236
100	298	1.948	1.689	0.259
100	299	1.880	1.657	0.223
100	300	1.912	1.689	0.223
100	301	1.912	1.726	0.186
100	302	1.857	1.635	0.222
100	303	1.821	1.562	0.259
100	305	1.835	1.648	0.187
100	307	1.798	1.576	0.222
100	308	1.903	1.716	0.187
100	309	1.962	1.776	0.186
100	310	1.835	1.612	0.223
100	312	1.939	1.680	0.259
100	313	1.830	1.607	0.223
100	314	1.789	1.566	0.223
100	316	1.844	1.621	0.223
100	317	1.926	1.716	0.210
100	318	1.912	1.689	0.223
100	320	1.857	1.635	0.222
100	321	1.748	1.562	0.186
100	322	1.785	1.585	0.200
	Max	1.962	1.776	0.414
	Average	1.864	1.639	0.225
	Min	1.748	1.498	0.186
	Std Dev	0.058	0.067	0.047

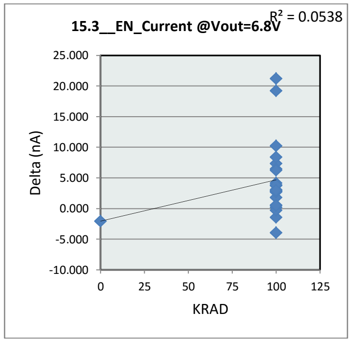


	15.2__EN_Hysteresis @ Vout=	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	2.577	mV
Min Limit	-0.179	mV
KRAD	0	100
LL	-0.179	-0.179
Min	1.498	1.562
Average	1.498	1.645
Max	1.498	1.776
UL	2.577	2.577

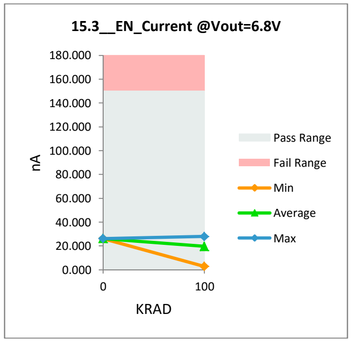


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		15.3__EN_Current @Vout=6.8V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	nA	nA	
	Max Limit	150	150	
	Min Limit	0.1	0.1	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	24.166	26.223	-2.057
100	294	23.946	20.200	3.746
100	296	23.624	25.061	-1.437
100	298	23.632	16.265	7.367
100	299	23.757	23.216	0.541
100	300	25.470	22.391	3.079
100	301	24.095	2.883	21.212
100	302	23.035	20.310	2.725
100	303	25.140	22.273	2.867
100	305	25.045	16.650	8.395
100	307	23.750	23.569	0.181
100	308	24.716	5.498	19.218
100	309	25.375	18.904	6.471
100	310	24.166	24.441	-0.275
100	312	23.577	19.414	4.163
100	313	24.291	22.501	1.790
100	314	25.446	21.582	3.864
100	316	25.045	14.828	10.217
100	317	24.009	27.936	-3.927
100	318	24.127	21.433	2.694
100	320	24.574	21.629	2.945
100	321	24.559	18.323	6.236
100	322	22.532	22.014	0.518
	Max	25.470	27.936	21.212
	Average	24.264	19.893	4.371
	Min	22.532	2.883	-3.927
	Std Dev	0.769	5.870	6.040

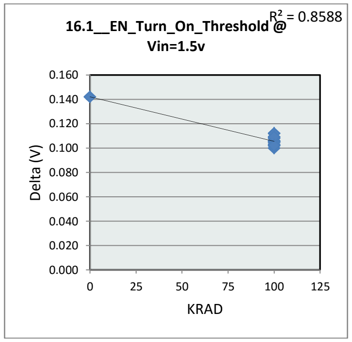


	15.3__EN_Current @Vout=6.8	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	150	nA
Min Limit	0.1	nA
KRAD	0	100
LL	0.100	0.100
Min	26.223	2.883
Average	26.223	19.606
Max	26.223	27.936
UL	150.000	150.000

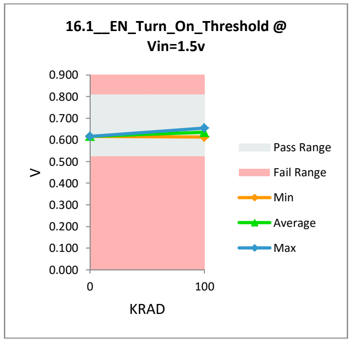


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		16.1__EN_Turn_On_Threshold @		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	0.807	0.807	
	Min Limit	0.524	0.524	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.758	0.616	0.142
100	294	0.748	0.643	0.105
100	296	0.730	0.622	0.108
100	298	0.761	0.649	0.112
100	299	0.742	0.637	0.105
100	300	0.755	0.649	0.106
100	301	0.752	0.652	0.100
100	302	0.733	0.628	0.105
100	303	0.730	0.625	0.105
100	305	0.730	0.628	0.102
100	307	0.727	0.622	0.105
100	308	0.752	0.643	0.109
100	309	0.761	0.655	0.106
100	310	0.730	0.625	0.105
100	312	0.752	0.640	0.112
100	313	0.736	0.631	0.105
100	314	0.721	0.613	0.108
100	316	0.727	0.622	0.105
100	317	0.752	0.649	0.103
100	318	0.758	0.649	0.109
100	320	0.736	0.634	0.102
100	321	0.721	0.619	0.102
100	322	0.730	0.628	0.102
	Max	0.761	0.655	0.142
	Average	0.741	0.634	0.107
	Min	0.721	0.613	0.100
	Std Dev	0.014	0.013	0.008

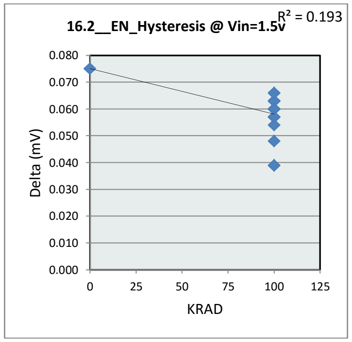


	16.1__EN_Turn_On_Threshold	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.807	V
Min Limit	0.524	V
KRAD	0	100
LL	0.524	0.524
Min	0.616	0.613
Average	0.616	0.635
Max	0.616	0.655
UL	0.807	0.807

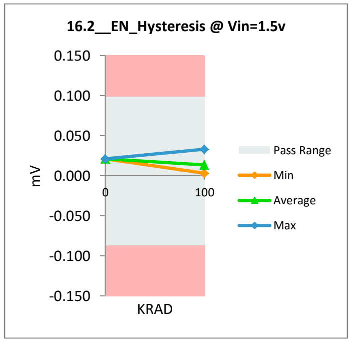


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		16.2__EN_Hysteresis @ Vin=1.5		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	0.098	0.098	
	Min Limit	-0.087	-0.087	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.096	0.021	0.075
100	294	0.078	0.018	0.060
100	296	0.063	0.000	0.063
100	298	0.093	0.027	0.066
100	299	0.072	0.009	0.063
100	300	0.087	0.027	0.060
100	301	0.081	0.027	0.054
100	302	0.066	0.006	0.060
100	303	0.060	0.000	0.060
100	305	0.060	0.000	0.060
100	307	0.060	0.003	0.057
100	308	0.084	0.021	0.063
100	309	0.096	0.033	0.063
100	310	0.060	0.003	0.057
100	312	0.090	0.027	0.063
100	313	0.066	0.003	0.063
100	314	0.051	0.012	0.039
100	316	0.054	0.006	0.048
100	317	0.081	0.021	0.060
100	318	0.093	0.027	0.066
100	320	0.069	0.012	0.057
100	321	0.048	0.009	0.039
100	322	0.060	0.003	0.057
	Max	0.096	0.033	0.075
	Average	0.073	0.014	0.059
	Min	0.048	0.000	0.039
	Std Dev	0.015	0.011	0.008

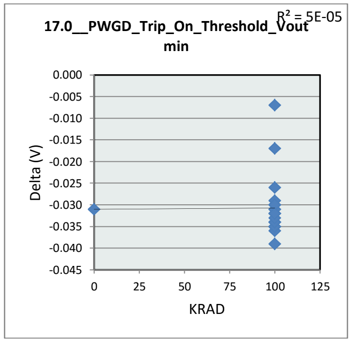


	16.2__EN_Hysteresis @ Vin=1	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.098	mV
Min Limit	-0.087	mV
KRAD	0	100
LL	-0.087	-0.087
Min	0.021	0.003
Average	0.021	0.013
Max	0.021	0.033
UL	0.098	0.098

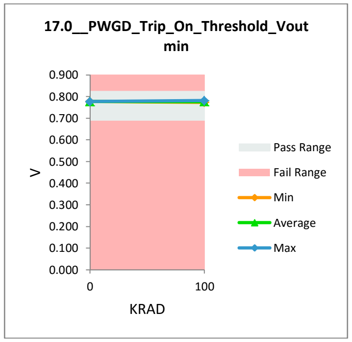


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		17.0__PWGD_Trip_On_Threshol		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	0.824	0.824	
	Min Limit	0.688	0.688	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.746	0.777	-0.031
100	294	0.746	0.776	-0.030
100	296	0.738	0.773	-0.035
100	298	0.750	0.776	-0.026
100	299	0.742	0.777	-0.035
100	300	0.758	0.775	-0.017
100	301	0.770	0.777	-0.007
100	302	0.742	0.776	-0.034
100	303	0.745	0.781	-0.036
100	305	0.739	0.774	-0.035
100	307	0.736	0.775	-0.039
100	308	0.742	0.777	-0.035
100	309	0.747	0.778	-0.031
100	310	0.745	0.777	-0.032
100	312	0.748	0.777	-0.029
100	313	0.742	0.776	-0.034
100	314	0.744	0.776	-0.032
100	316	0.746	0.776	-0.030
100	317	0.742	0.776	-0.034
100	318	0.745	0.776	-0.031
100	320	0.742	0.775	-0.033
100	321	0.744	0.774	-0.030
100	322	0.741	0.773	-0.032
	Max	0.770	0.781	-0.007
	Average	0.745	0.776	-0.031
	Min	0.736	0.773	-0.039
	Std Dev	0.007	0.002	0.007

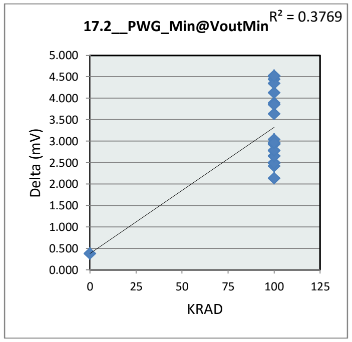


	17.0__PWGD_Trip_On_Thresh	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.824	V
Min Limit	0.688	V
KRAD	0	100
LL	0.688	0.688
Min	0.777	0.773
Average	0.777	0.776
Max	0.777	0.781
UL	0.824	0.824

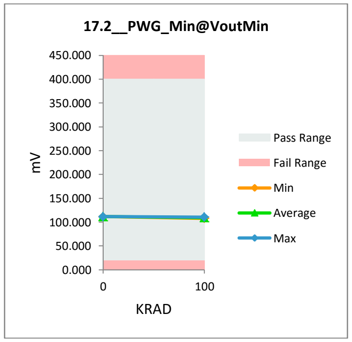


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		17.2__PWG_Min@VoutMin		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	20	20	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	112.014	111.634	0.380
100	294	113.217	108.707	4.510
100	296	112.523	110.107	2.416
100	298	112.273	109.774	2.499
100	299	112.841	110.182	2.659
100	300	112.143	108.510	3.633
100	301	112.682	108.159	4.523
100	302	112.740	109.797	2.943
100	303	112.660	110.525	2.135
100	305	112.573	108.680	3.893
100	307	112.045	109.561	2.484
100	308	113.015	108.569	4.446
100	309	112.832	108.700	4.132
100	310	112.802	109.761	3.041
100	312	112.977	110.199	2.778
100	313	112.831	110.178	2.653
100	314	112.877	109.922	2.955
100	316	112.934	110.008	2.926
100	317	113.224	109.367	3.857
100	318	112.767	109.980	2.787
100	320	113.256	110.293	2.963
100	321	112.767	108.419	4.348
100	322	112.292	107.770	4.522
	Max	113.256	111.634	4.523
	Average	112.708	109.513	3.195
	Min	112.014	107.770	0.380
	Std Dev	0.356	0.921	1.000

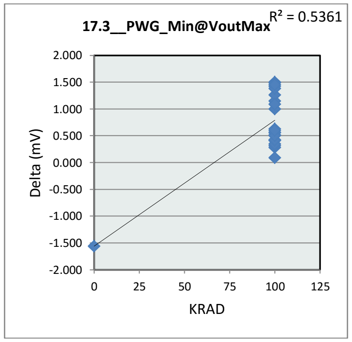


	17.2__PWG_Min@VoutMin	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	400	mV
Min Limit	20	mV
KRAD	0	100
LL	20.000	20.000
Min	111.634	107.770
Average	111.634	109.417
Max	111.634	110.525
UL	400.000	400.000

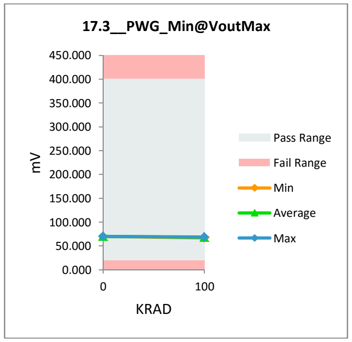


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		17.3__PWG_Min@VoutMax		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	20	20	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	68.689	70.251	-1.562
100	294	69.162	67.660	1.502
100	296	68.767	68.483	0.284
100	298	68.869	68.553	0.316
100	299	69.137	68.723	0.414
100	300	68.604	67.604	1.000
100	301	68.567	67.080	1.487
100	302	69.059	68.500	0.559
100	303	68.983	68.894	0.089
100	305	68.991	67.842	1.149
100	307	68.720	68.375	0.345
100	308	69.153	67.732	1.421
100	309	69.033	67.771	1.262
100	310	68.886	68.256	0.630
100	312	69.082	68.668	0.414
100	313	68.973	68.549	0.424
100	314	69.047	68.487	0.560
100	316	68.997	68.484	0.513
100	317	68.628	67.540	1.088
100	318	68.928	68.426	0.502
100	320	69.284	68.687	0.597
100	321	68.942	67.561	1.381
100	322	68.628	67.174	1.454
	Max	69.284	70.251	1.502
	Average	68.919	68.230	0.688
	Min	68.567	67.080	-1.562
	Std Dev	0.202	0.687	0.670

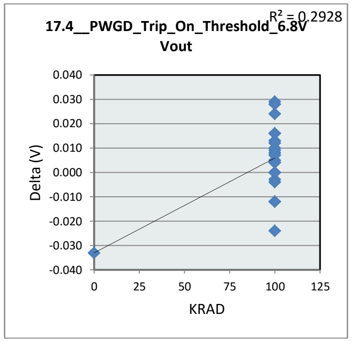


	17.3__PWG_Min@VoutMax	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	400	mV
Min Limit	20	mV
KRAD	0	100
LL	20.000	20.000
Min	70.251	67.080
Average	70.251	68.139
Max	70.251	68.894
UL	400.000	400.000

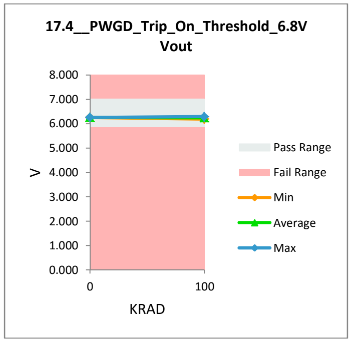


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		17.4__PWGD_Trip_On_Threshol		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	7.004	7.004	
	Min Limit	5.848	5.848	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.224	6.257	-0.033
100	294	6.238	6.225	0.013
100	296	6.246	6.217	0.029
100	298	6.230	6.233	-0.003
100	299	6.250	6.254	-0.004
100	300	6.282	6.273	0.009
100	301	6.254	6.246	0.008
100	302	6.261	6.261	0.000
100	303	6.278	6.290	-0.012
100	305	6.234	6.229	0.005
100	307	6.221	6.221	0.000
100	308	6.229	6.225	0.004
100	309	6.313	6.289	0.024
100	310	6.273	6.269	0.004
100	312	6.245	6.238	0.007
100	313	6.245	6.245	0.000
100	314	6.249	6.233	0.016
100	316	6.229	6.241	-0.012
100	317	6.251	6.241	0.010
100	318	6.253	6.277	-0.024
100	320	6.229	6.217	0.012
100	321	6.217	6.201	0.016
100	322	6.216	6.188	0.028
	Max	6.313	6.290	0.029
	Average	6.246	6.242	0.004
	Min	6.216	6.188	-0.033
	Std Dev	0.023	0.026	0.015



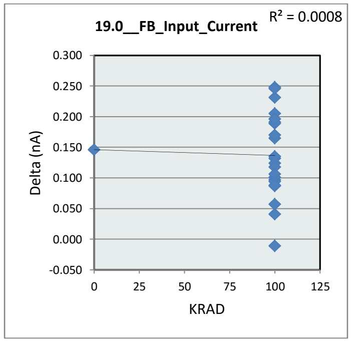
	17.4__PWGD_Trip_On_Thresh	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	7.004	V
Min Limit	5.848	V
KRAD	0	100
LL	5.848	5.848
Min	6.257	6.188
Average	6.257	6.242
Max	6.257	6.290
UL	7.004	7.004



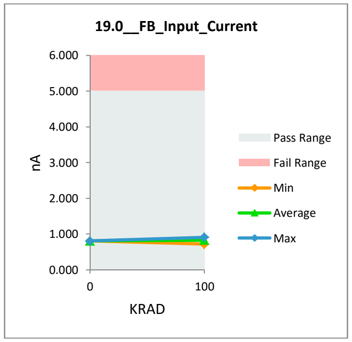
TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

	19.0__FB_Input_Current	
Test Site	CLAB	CLAB
Tester	EAG03	EAG03
Test Number	EF506901	EF506901
Unit	nA	nA
Max Limit	5	5
Min Limit	0.001	0.001

KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.953	0.807	0.146
100	294	0.875	0.751	0.124
100	296	1.006	0.909	0.097
100	298	0.905	0.716	0.189
100	299	1.040	0.849	0.191
100	300	0.950	0.832	0.118
100	301	1.008	0.876	0.132
100	302	0.921	0.786	0.135
100	303	0.896	0.907	-0.011
100	305	0.936	0.835	0.101
100	307	0.936	0.731	0.205
100	308	0.833	0.792	0.041
100	309	0.942	0.855	0.087
100	310	0.978	0.872	0.106
100	312	1.026	0.861	0.165
100	313	1.050	0.802	0.248
100	314	1.027	0.796	0.231
100	316	0.978	0.808	0.170
100	317	0.890	0.796	0.094
100	318	0.927	0.870	0.057
100	320	1.041	0.845	0.196
100	321	1.062	0.816	0.246
100	322	0.983	0.895	0.088
	Max	1.062	0.909	0.248
	Average	0.964	0.826	0.137
	Min	0.833	0.716	-0.011
	Std Dev	0.062	0.052	0.067

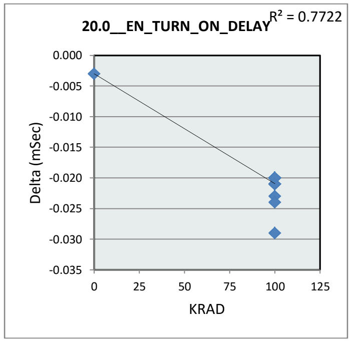


	19.0__FB_Input_Current	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	5	nA
Min Limit	0.001	nA
KRAD	0	100
LL	0.001	0.001
Min	0.807	0.716
Average	0.807	0.827
Max	0.807	0.909
UL	5.000	5.000

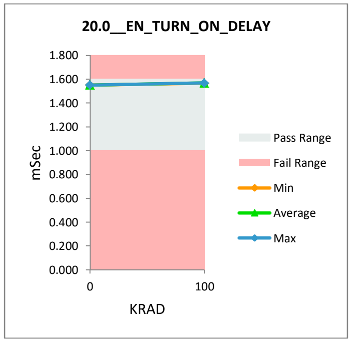


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		20.0__EN_TURN_ON_DELAY		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		mSec	mSec	
Max Limit		1.6	1.6	
Min Limit		1	1	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.548	1.551	-0.003
100	294	1.547	1.568	-0.021
100	296	1.547	1.568	-0.021
100	298	1.548	1.568	-0.020
100	299	1.547	1.568	-0.021
100	300	1.548	1.568	-0.020
100	301	1.545	1.568	-0.023
100	302	1.548	1.568	-0.020
100	303	1.548	1.568	-0.020
100	305	1.548	1.568	-0.020
100	307	1.548	1.568	-0.020
100	308	1.548	1.568	-0.020
100	309	1.548	1.568	-0.020
100	310	1.548	1.568	-0.020
100	312	1.548	1.568	-0.020
100	313	1.541	1.565	-0.024
100	314	1.548	1.568	-0.020
100	316	1.547	1.568	-0.021
100	317	1.548	1.568	-0.020
100	318	1.548	1.568	-0.020
100	320	1.548	1.568	-0.020
100	321	1.539	1.568	-0.029
100	322	1.547	1.568	-0.021
	Max	1.548	1.568	-0.003
	Average	1.547	1.567	-0.020
	Min	1.539	1.551	-0.029
	Std Dev	0.002	0.004	0.004

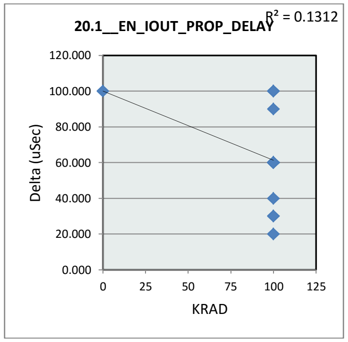


	20.0__EN_TURN_ON_DELAY	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.6	mSec
Min Limit	1	mSec
KRAD	0	100
LL	1.000	1.000
Min	1.551	1.565
Average	1.551	1.568
Max	1.551	1.568
UL	1.600	1.600

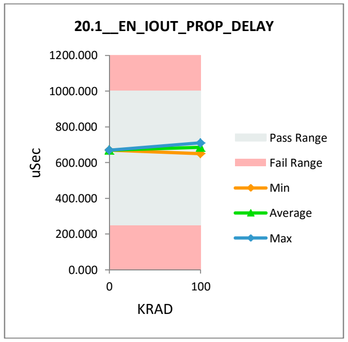


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		20.1__EN_IOUT_PROP_DELAY		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	uSec	uSec	
	Max Limit	1000	1000	
	Min Limit	250	250	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	770.000	670.000	100.000
100	294	760.000	700.000	60.000
100	296	740.000	680.000	60.000
100	298	770.000	710.000	60.000
100	299	710.000	690.000	20.000
100	300	770.000	710.000	60.000
100	301	760.000	660.000	100.000
100	302	750.000	690.000	60.000
100	303	740.000	680.000	60.000
100	305	730.000	690.000	40.000
100	307	740.000	680.000	60.000
100	308	760.000	660.000	100.000
100	309	770.000	710.000	60.000
100	310	740.000	680.000	60.000
100	312	760.000	700.000	60.000
100	313	750.000	690.000	60.000
100	314	700.000	670.000	30.000
100	316	740.000	680.000	60.000
100	317	740.000	710.000	30.000
100	318	770.000	710.000	60.000
100	320	750.000	650.000	100.000
100	321	740.000	680.000	60.000
100	322	740.000	650.000	90.000
	Max	770.000	710.000	100.000
	Average	747.826	684.783	63.043
	Min	700.000	650.000	20.000
	Std Dev	18.576	19.038	22.245

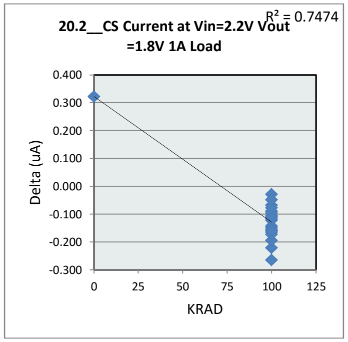


	20.1__EN_IOUT_PROP_DELAY	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1000	uSec
Min Limit	250	uSec
KRAD	0	100
LL	250.000	250.000
Min	670.000	650.000
Average	670.000	685.455
Max	670.000	710.000
UL	1000.000	1000.000

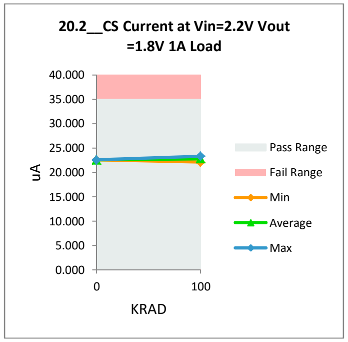


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		20.2__CS Current at Vin=2.2V V		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		uA	uA	
Max Limit		35	35	
Min Limit		0.05	0.05	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	22.887	22.565	0.322
100	294	22.160	22.266	-0.106
100	296	22.258	22.401	-0.143
100	298	22.960	23.107	-0.147
100	299	23.094	23.315	-0.221
100	300	22.585	22.653	-0.068
100	301	22.692	22.846	-0.154
100	302	22.665	22.694	-0.029
100	303	22.795	22.885	-0.090
100	305	22.581	22.698	-0.117
100	307	22.557	22.647	-0.090
100	308	22.809	23.003	-0.194
100	309	22.921	23.186	-0.265
100	310	22.943	23.051	-0.108
100	312	22.790	22.954	-0.164
100	313	22.338	22.511	-0.173
100	314	22.599	22.721	-0.122
100	316	22.831	22.927	-0.096
100	317	22.628	22.787	-0.159
100	318	22.666	22.780	-0.114
100	320	22.899	23.059	-0.160
100	321	22.424	22.501	-0.077
100	322	22.036	22.084	-0.048
	Max	23.094	23.315	0.322
	Average	22.657	22.767	-0.110
	Min	22.036	22.084	-0.265
	Std Dev	0.271	0.299	0.109

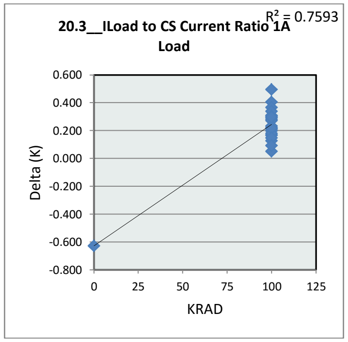


	20.2__CS Current at Vin=2.2V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	35	uA
Min Limit	0.05	uA
KRAD	0	100
LL	0.050	0.050
Min	22.565	22.084
Average	22.565	22.776
Max	22.565	23.315
UL	35.000	35.000

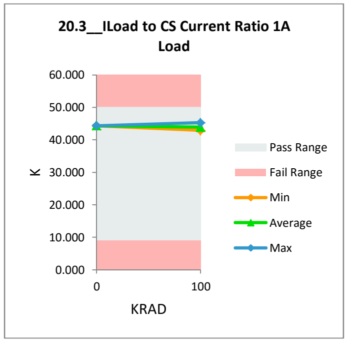


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		20.3__ILoad to CS Current Ratio		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		K	K	
Max Limit		50	50	
Min Limit		9	9	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	43.692	44.321	-0.629
100	294	45.126	44.915	0.211
100	296	44.927	44.646	0.281
100	298	43.553	43.281	0.272
100	299	43.300	42.895	0.405
100	300	44.276	44.148	0.128
100	301	44.067	43.775	0.292
100	302	44.119	44.068	0.051
100	303	43.868	43.701	0.167
100	305	44.283	44.061	0.222
100	307	44.330	44.161	0.169
100	308	43.842	43.476	0.366
100	309	43.628	43.133	0.495
100	310	43.585	43.387	0.198
100	312	43.877	43.569	0.308
100	313	44.767	44.427	0.340
100	314	44.248	44.016	0.232
100	316	43.799	43.620	0.179
100	317	44.192	43.888	0.304
100	318	44.118	43.902	0.216
100	320	43.669	43.371	0.298
100	321	44.594	44.446	0.148
100	322	45.378	45.285	0.093
	Max	45.378	45.285	0.495
	Average	44.141	43.934	0.206
	Min	43.300	42.895	-0.629
	Std Dev	0.531	0.579	0.209

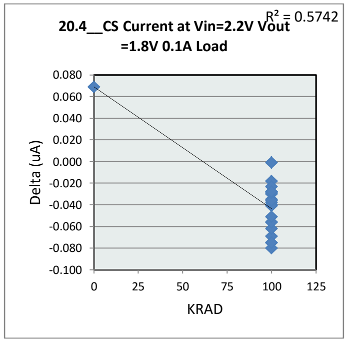


	20.3__ILoad to CS Current Rat	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	50	K
Min Limit	9	K
KRAD	0	100
LL	9.000	9.000
Min	44.321	42.895
Average	44.321	43.917
Max	44.321	45.285
UL	50.000	50.000

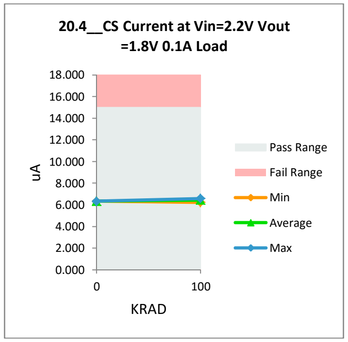


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		20.4__CS Current at Vin=2.2V V		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		uA	uA	
Max Limit		15	15	
Min Limit		0.05	0.05	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.398	6.329	0.069
100	294	6.336	6.374	-0.038
100	296	6.341	6.410	-0.069
100	298	6.433	6.489	-0.056
100	299	6.495	6.575	-0.080
100	300	6.352	6.380	-0.028
100	301	6.486	6.504	-0.018
100	302	6.417	6.447	-0.030
100	303	6.435	6.458	-0.023
100	305	6.333	6.395	-0.062
100	307	6.320	6.355	-0.035
100	308	6.416	6.472	-0.056
100	309	6.361	6.436	-0.075
100	310	6.550	6.590	-0.040
100	312	6.414	6.470	-0.056
100	313	6.405	6.480	-0.075
100	314	6.365	6.394	-0.029
100	316	6.414	6.455	-0.041
100	317	6.433	6.469	-0.036
100	318	6.347	6.376	-0.029
100	320	6.447	6.498	-0.051
100	321	6.339	6.367	-0.028
100	322	6.235	6.236	-0.001
	Max	6.550	6.590	0.069
	Average	6.394	6.433	-0.039
	Min	6.235	6.236	-0.080
	Std Dev	0.068	0.079	0.031

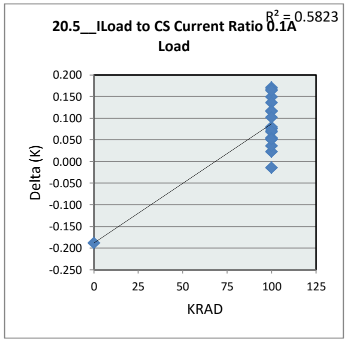


	20.4__CS Current at Vin=2.2V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	15	uA
Min Limit	0.05	uA
KRAD	0	100
LL	0.050	0.050
Min	6.329	6.236
Average	6.329	6.438
Max	6.329	6.590
UL	15.000	15.000

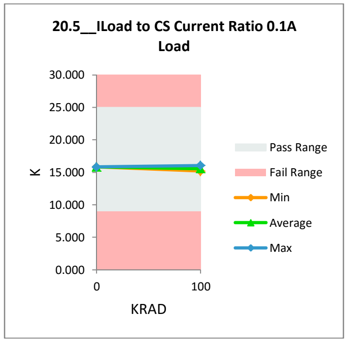


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		20.5__ILoad to CS Current Ratio		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	K	K	
	Max Limit	25	25	
	Min Limit	9	9	
KRAD	Serial #	PreRLAT_3-3-17.tx	101A-RLAT-POST_	Delta
0	C1	15.636	15.824	-0.188
100	294	15.789	15.713	0.076
100	296	15.775	15.626	0.149
100	298	15.551	15.434	0.117
100	299	15.402	15.231	0.171
100	300	15.748	15.697	0.051
100	301	15.423	15.400	0.023
100	302	15.588	15.533	0.055
100	303	15.545	15.509	0.036
100	305	15.796	15.660	0.136
100	307	15.828	15.759	0.069
100	308	15.592	15.475	0.117
100	309	15.728	15.561	0.167
100	310	15.273	15.197	0.076
100	312	15.595	15.479	0.116
100	313	15.620	15.456	0.164
100	314	15.717	15.663	0.054
100	316	15.597	15.517	0.080
100	317	15.551	15.481	0.070
100	318	15.760	15.706	0.054
100	320	15.516	15.414	0.102
100	321	15.782	15.730	0.052
100	322	16.045	16.059	-0.014
	Max	16.045	16.059	0.171
	Average	15.646	15.571	0.075
	Min	15.273	15.197	-0.188
	Std Dev	0.167	0.192	0.075

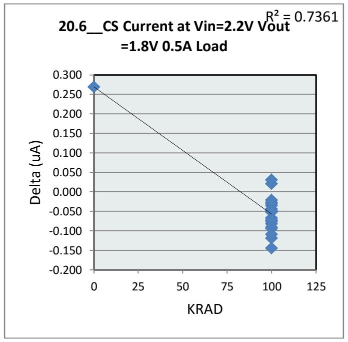


	20.5__ILoad to CS Current Rat	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	25	K
Min Limit	9	K
KRAD	0	100
LL	9.000	9.000
Min	15.824	15.197
Average	15.824	15.559
Max	15.824	16.059
UL	25.000	25.000

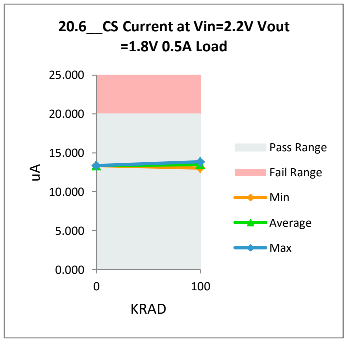


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		20.6__CS Current at Vin=2.2V V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	uA	uA	
	Max Limit	20	20	
	Min Limit	0.05	0.05	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	13.630	13.361	0.269
100	294	13.147	13.198	-0.051
100	296	13.219	13.295	-0.076
100	298	13.648	13.721	-0.073
100	299	13.739	13.858	-0.119
100	300	13.369	13.390	-0.021
100	301	13.499	13.566	-0.067
100	302	13.497	13.476	0.021
100	303	13.539	13.569	-0.030
100	305	13.399	13.443	-0.044
100	307	13.381	13.416	-0.035
100	308	13.541	13.632	-0.091
100	309	13.566	13.710	-0.144
100	310	13.680	13.728	-0.048
100	312	13.517	13.611	-0.094
100	313	13.273	13.382	-0.109
100	314	13.428	13.458	-0.030
100	316	13.549	13.600	-0.051
100	317	13.436	13.518	-0.082
100	318	13.428	13.479	-0.051
100	320	13.609	13.681	-0.072
100	321	13.295	13.322	-0.027
100	322	13.081	13.050	0.031
	Max	13.739	13.858	0.269
	Average	13.455	13.498	-0.043
	Min	13.081	13.050	-0.144
	Std Dev	0.170	0.188	0.079

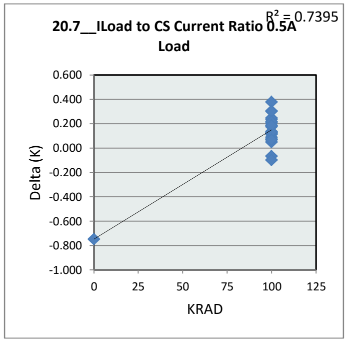


	20.6__CS Current at Vin=2.2V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	20	uA
Min Limit	0.05	uA
KRAD	0	100
LL	0.050	0.050
Min	13.361	13.050
Average	13.361	13.505
Max	13.361	13.858
UL	20.000	20.000

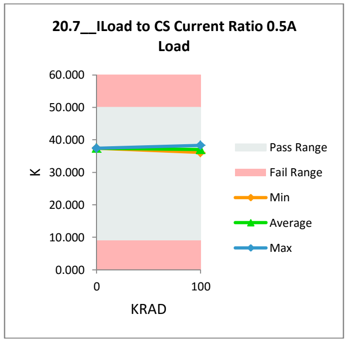


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		20.7__ILoad to CS Current Ratio		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		K	K	
Max Limit		50	50	
Min Limit		9	9	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	36.685	37.433	-0.748
100	294	38.032	37.895	0.137
100	296	37.826	37.619	0.207
100	298	36.636	36.450	0.186
100	299	36.394	36.090	0.304
100	300	37.400	37.351	0.049
100	301	37.042	36.867	0.175
100	302	37.047	37.113	-0.066
100	303	36.930	36.858	0.072
100	305	37.317	37.204	0.113
100	307	37.367	37.279	0.088
100	308	36.926	36.689	0.237
100	309	36.857	36.479	0.378
100	310	36.550	36.430	0.120
100	312	36.992	36.745	0.247
100	313	37.673	37.372	0.301
100	314	37.235	37.161	0.074
100	316	36.904	36.775	0.129
100	317	37.215	36.997	0.218
100	318	37.235	37.105	0.130
100	320	36.741	36.556	0.185
100	321	37.610	37.542	0.068
100	322	38.225	38.323	-0.098
	Max	38.225	38.323	0.378
	Average	37.167	37.058	0.109
	Min	36.394	36.090	-0.748
	Std Dev	0.472	0.520	0.217

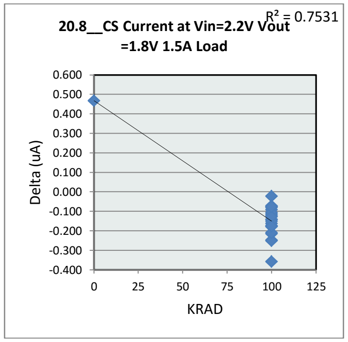


	20.7__ILoad to CS Current Rat	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	50	K
Min Limit	9	K
KRAD	0	100
LL	9.000	9.000
Min	37.433	36.090
Average	37.433	37.041
Max	37.433	38.323
UL	50.000	50.000

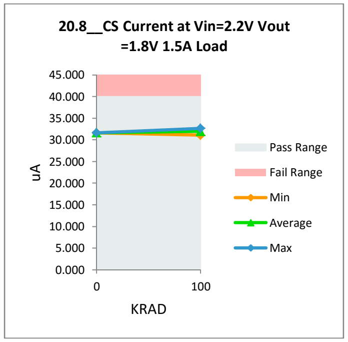


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		20.8__CS Current at Vin=2.2V V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	uA	uA	
	Max Limit	40	40	
	Min Limit	0.05	0.05	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	32.103	31.636	0.467
100	294	31.172	31.294	-0.122
100	296	31.280	31.423	-0.143
100	298	32.198	32.360	-0.162
100	299	32.414	32.662	-0.248
100	300	31.786	31.900	-0.114
100	301	31.812	32.027	-0.215
100	302	31.785	31.807	-0.022
100	303	31.960	32.052	-0.092
100	305	31.755	31.896	-0.141
100	307	31.692	31.772	-0.080
100	308	32.027	32.277	-0.250
100	309	32.167	32.525	-0.358
100	310	32.101	32.207	-0.106
100	312	32.012	32.191	-0.179
100	313	31.383	31.556	-0.173
100	314	31.741	31.892	-0.151
100	316	31.995	32.067	-0.072
100	317	31.780	31.990	-0.210
100	318	31.870	31.997	-0.127
100	320	32.118	32.294	-0.176
100	321	31.550	31.625	-0.075
100	322	30.999	31.076	-0.077
	Max	32.414	32.662	0.467
	Average	31.813	31.936	-0.123
	Min	30.999	31.076	-0.358
	Std Dev	0.349	0.386	0.148

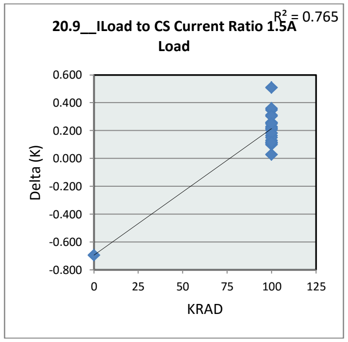


	20.8__CS Current at Vin=2.2V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	40	uA
Min Limit	0.05	uA
KRAD	0	100
LL	0.050	0.050
Min	31.636	31.076
Average	31.636	31.950
Max	31.636	32.662
UL	40.000	40.000

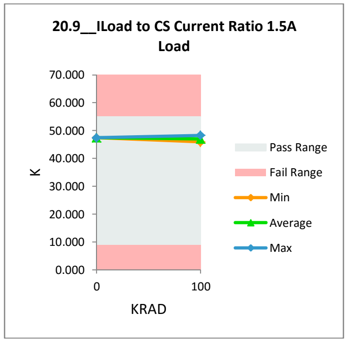


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		20.9__ILoad to CS Current Ratio		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	K	K	
	Max Limit	55	55	
	Min Limit	9	9	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	46.724	47.419	-0.695
100	294	48.120	47.937	0.183
100	296	47.954	47.740	0.214
100	298	46.586	46.358	0.228
100	299	46.277	45.929	0.348
100	300	47.190	47.027	0.163
100	301	47.152	46.840	0.312
100	302	47.192	47.164	0.028
100	303	46.934	46.804	0.130
100	305	47.237	47.032	0.205
100	307	47.331	47.215	0.116
100	308	46.836	46.477	0.359
100	309	46.632	46.122	0.510
100	310	46.728	46.578	0.150
100	312	46.858	46.601	0.257
100	313	47.797	47.538	0.259
100	314	47.257	47.038	0.219
100	316	46.882	46.782	0.100
100	317	47.199	46.894	0.305
100	318	47.066	46.884	0.182
100	320	46.702	46.453	0.249
100	321	47.544	47.435	0.109
100	322	48.388	48.273	0.115
	Max	48.388	48.273	0.510
	Average	47.156	46.980	0.176
	Min	46.277	45.929	-0.695
	Std Dev	0.521	0.570	0.217

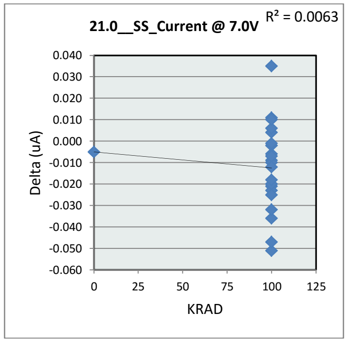


	20.9__ILoad to CS Current Rat	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	55	K
Min Limit	9	K
KRAD	0	100
LL	9.000	9.000
Min	47.419	45.929
Average	47.419	46.960
Max	47.419	48.273
UL	55.000	55.000

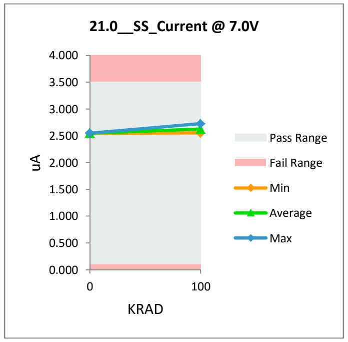


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		21.0__SS_Current @ 7.0V		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		uA	uA	
Max Limit		3.5	3.5	
Min Limit		0.1	0.1	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	2.543	2.548	-0.005
100	294	2.674	2.670	0.004
100	296	2.604	2.655	-0.051
100	298	2.533	2.569	-0.036
100	299	2.608	2.629	-0.021
100	300	2.590	2.622	-0.032
100	301	2.646	2.652	-0.006
100	302	2.644	2.609	0.035
100	303	2.603	2.612	-0.009
100	305	2.614	2.616	-0.002
100	307	2.608	2.631	-0.023
100	308	2.575	2.622	-0.047
100	309	2.569	2.589	-0.020
100	310	2.705	2.725	-0.020
100	312	2.626	2.651	-0.025
100	313	2.636	2.630	0.006
100	314	2.601	2.611	-0.010
100	316	2.592	2.599	-0.007
100	317	2.603	2.592	0.011
100	318	2.535	2.553	-0.018
100	320	2.627	2.639	-0.012
100	321	2.636	2.626	0.010
100	322	2.630	2.631	-0.001
	Max	2.705	2.725	0.035
	Average	2.609	2.621	-0.012
	Min	2.533	2.548	-0.051
	Std Dev	0.041	0.038	0.020

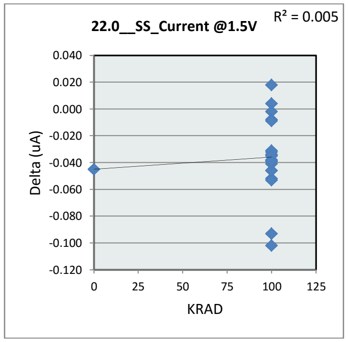


	21.0__SS_Current @ 7.0V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	3.5	uA
Min Limit	0.1	uA
KRAD	0	100
LL	0.100	0.100
Min	2.548	2.553
Average	2.548	2.624
Max	2.548	2.725
UL	3.500	3.500

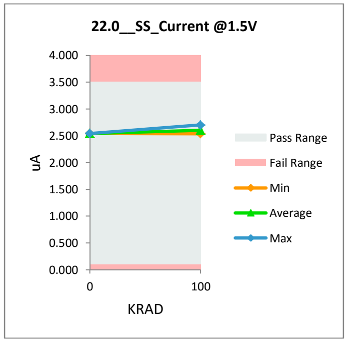


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		22.0__SS_Current @1.5V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	uA	uA	
	Max Limit	3.5	3.5	
	Min Limit	0.1	0.1	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	2.497	2.542	-0.045
100	294	2.656	2.652	0.004
100	296	2.580	2.619	-0.039
100	298	2.482	2.575	-0.093
100	299	2.564	2.603	-0.039
100	300	2.551	2.585	-0.034
100	301	2.596	2.631	-0.035
100	302	2.595	2.577	0.018
100	303	2.547	2.585	-0.038
100	305	2.564	2.610	-0.046
100	307	2.570	2.602	-0.032
100	308	2.511	2.613	-0.102
100	309	2.523	2.554	-0.031
100	310	2.650	2.702	-0.052
100	312	2.596	2.634	-0.038
100	313	2.590	2.592	-0.002
100	314	2.550	2.603	-0.053
100	316	2.539	2.585	-0.046
100	317	2.569	2.577	-0.008
100	318	2.496	2.537	-0.041
100	320	2.580	2.615	-0.035
100	321	2.578	2.587	-0.009
100	322	2.571	2.610	-0.039
	Max	2.656	2.702	0.018
	Average	2.563	2.600	-0.036
	Min	2.482	2.537	-0.102
	Std Dev	0.044	0.036	0.027



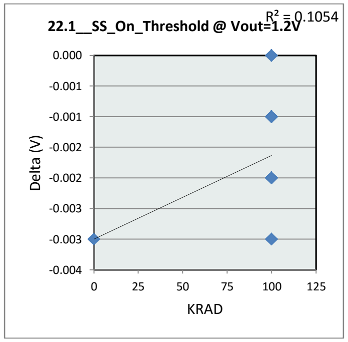
	22.0__SS_Current @1.5V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	3.5	uA
Min Limit	0.1	uA
KRAD	0	100
LL	0.100	0.100
Min	2.542	2.537
Average	2.542	2.602
Max	2.542	2.702
UL	3.500	3.500



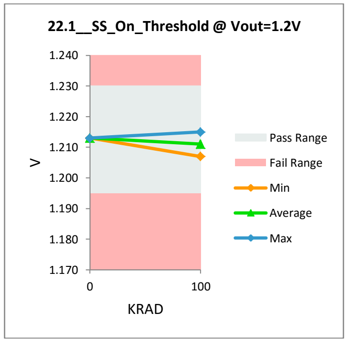
TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

	22.1__SS_On_Threshold @ Vout	
Test Site	CLAB	CLAB
Tester	EAG03	EAG03
Test Number	EF506901	EF506901
Unit	V	V
Max Limit	1.23	1.23
Min Limit	1.195	1.195

KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.210	1.213	-0.003
100	294	1.209	1.211	-0.002
100	296	1.209	1.211	-0.002
100	298	1.209	1.210	-0.001
100	299	1.206	1.209	-0.003
100	300	1.207	1.207	0.000
100	301	1.212	1.213	-0.001
100	302	1.210	1.212	-0.002
100	303	1.213	1.214	-0.001
100	305	1.207	1.209	-0.002
100	307	1.209	1.211	-0.002
100	308	1.209	1.212	-0.003
100	309	1.213	1.213	0.000
100	310	1.211	1.212	-0.001
100	312	1.210	1.211	-0.001
100	313	1.209	1.211	-0.002
100	314	1.209	1.211	-0.002
100	316	1.213	1.215	-0.002
100	317	1.209	1.210	-0.001
100	318	1.208	1.209	-0.001
100	320	1.209	1.211	-0.002
100	321	1.207	1.210	-0.003
100	322	1.208	1.210	-0.002
	Max	1.213	1.215	0.000
	Average	1.209	1.211	-0.002
	Min	1.206	1.207	-0.003
	Std Dev	0.002	0.002	0.001

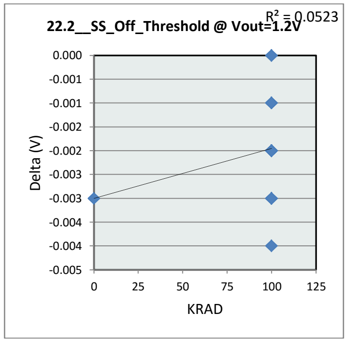


	22.1__SS_On_Threshold @ Vo	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.23	V
Min Limit	1.195	V
KRAD	0	100
LL	1.195	1.195
Min	1.213	1.207
Average	1.213	1.211
Max	1.213	1.215
UL	1.230	1.230

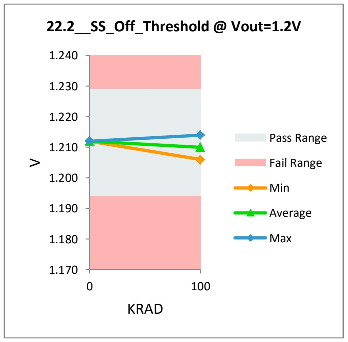


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		22.2__SS_Off_Threshold @ Vout		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.229	1.229	
	Min Limit	1.194	1.194	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.209	1.212	-0.003
100	294	1.208	1.210	-0.002
100	296	1.207	1.210	-0.003
100	298	1.208	1.209	-0.001
100	299	1.205	1.208	-0.003
100	300	1.206	1.206	0.000
100	301	1.211	1.212	-0.001
100	302	1.209	1.211	-0.002
100	303	1.211	1.213	-0.002
100	305	1.206	1.208	-0.002
100	307	1.208	1.210	-0.002
100	308	1.207	1.211	-0.004
100	309	1.212	1.212	0.000
100	310	1.209	1.211	-0.002
100	312	1.208	1.210	-0.002
100	313	1.208	1.210	-0.002
100	314	1.208	1.210	-0.002
100	316	1.211	1.214	-0.003
100	317	1.208	1.209	-0.001
100	318	1.206	1.208	-0.002
100	320	1.208	1.210	-0.002
100	321	1.206	1.209	-0.003
100	322	1.207	1.209	-0.002
	Max	1.212	1.214	0.000
	Average	1.208	1.210	-0.002
	Min	1.205	1.206	-0.004
	Std Dev	0.002	0.002	0.001

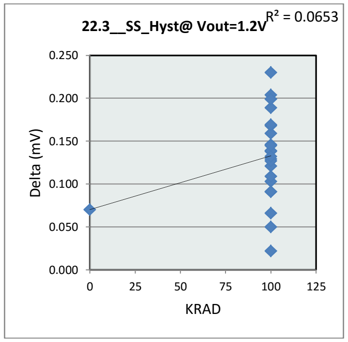


	22.2__SS_Off_Threshold @ Vo	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.229	V
Min Limit	1.194	V
KRAD	0	100
LL	1.194	1.194
Min	1.212	1.206
Average	1.212	1.210
Max	1.212	1.214
UL	1.229	1.229

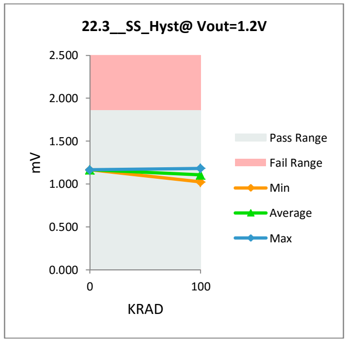


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		22.3__SS_Hyst@ Vout=1.2V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	1.857	1.857	
	Min Limit	0.002	0.002	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.235	1.165	0.070
100	294	1.261	1.072	0.189
100	296	1.246	1.143	0.103
100	298	1.194	1.073	0.121
100	299	1.233	1.183	0.050
100	300	1.149	1.058	0.091
100	301	1.292	1.088	0.204
100	302	1.265	1.156	0.109
100	303	1.342	1.143	0.199
100	305	1.195	1.057	0.138
100	307	1.206	1.067	0.139
100	308	1.208	1.079	0.129
100	309	1.256	1.110	0.146
100	310	1.285	1.117	0.168
100	312	1.227	1.136	0.091
100	313	1.240	1.174	0.066
100	314	1.230	1.103	0.127
100	316	1.304	1.172	0.132
100	317	1.266	1.036	0.230
100	318	1.150	1.128	0.022
100	320	1.247	1.102	0.145
100	321	1.269	1.110	0.159
100	322	1.192	1.023	0.169
	Max	1.342	1.183	0.230
	Average	1.239	1.108	0.130
	Min	1.149	1.023	0.022
	Std Dev	0.046	0.046	0.051



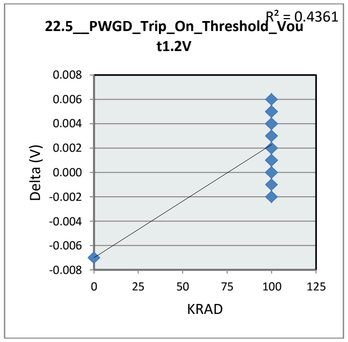
	22.3__SS_Hyst@ Vout=1.2V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.857	mV
Min Limit	0.002	mV
KRAD	0	100
LL	0.002	0.002
Min	1.165	1.023
Average	1.165	1.106
Max	1.165	1.183
UL	1.857	1.857



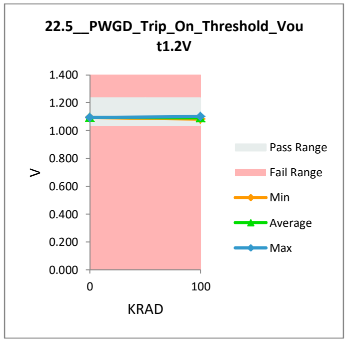
TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

	22.5__PWGD_Trip_On_Threshol	
Test Site	CLAB	CLAB
Tester	EAG03	EAG03
Test Number	EF506901	EF506901
Unit	V	V
Max Limit	1.236	1.236
Min Limit	1.032	1.032

KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.088	1.095	-0.007
100	294	1.092	1.088	0.004
100	296	1.094	1.089	0.005
100	298	1.090	1.091	-0.001
100	299	1.096	1.094	0.002
100	300	1.104	1.098	0.006
100	301	1.095	1.094	0.001
100	302	1.098	1.097	0.001
100	303	1.101	1.098	0.003
100	305	1.094	1.089	0.005
100	307	1.089	1.088	0.001
100	308	1.092	1.088	0.004
100	309	1.106	1.101	0.005
100	310	1.100	1.097	0.003
100	312	1.095	1.093	0.002
100	313	1.093	1.093	0.000
100	314	1.094	1.089	0.005
100	316	1.091	1.091	0.000
100	317	1.092	1.092	0.000
100	318	1.096	1.098	-0.002
100	320	1.089	1.088	0.001
100	321	1.087	1.086	0.001
100	322	1.087	1.083	0.004
	Max	1.106	1.101	0.006
	Average	1.094	1.092	0.002
	Min	1.087	1.083	-0.007
	Std Dev	0.005	0.005	0.003

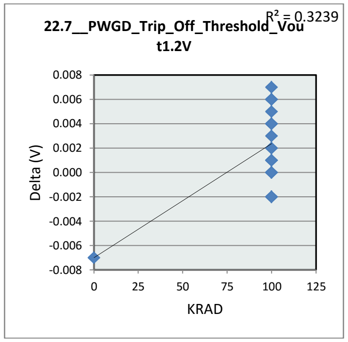


	22.5__PWGD_Trip_On_Thresh	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.236	V
Min Limit	1.032	V
KRAD	0	100
LL	1.032	1.032
Min	1.095	1.083
Average	1.095	1.092
Max	1.095	1.101
UL	1.236	1.236

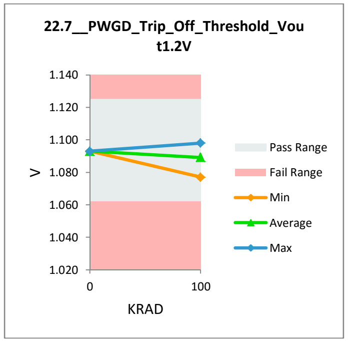


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		22.7__PWGD_Trip_Off_Threshol		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.125	1.125	
	Min Limit	1.062	1.062	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.086	1.093	-0.007
100	294	1.090	1.086	0.004
100	296	1.092	1.086	0.006
100	298	1.087	1.089	-0.002
100	299	1.094	1.094	0.000
100	300	1.101	1.095	0.006
100	301	1.093	1.088	0.005
100	302	1.092	1.094	-0.002
100	303	1.098	1.098	0.000
100	305	1.091	1.089	0.002
100	307	1.086	1.086	0.000
100	308	1.086	1.085	0.001
100	309	1.104	1.098	0.006
100	310	1.097	1.094	0.003
100	312	1.092	1.091	0.001
100	313	1.091	1.090	0.001
100	314	1.092	1.086	0.006
100	316	1.088	1.088	0.000
100	317	1.089	1.087	0.002
100	318	1.094	1.096	-0.002
100	320	1.089	1.085	0.004
100	321	1.084	1.080	0.004
100	322	1.084	1.077	0.007
	Max	1.104	1.098	0.007
	Average	1.091	1.089	0.002
	Min	1.084	1.077	-0.007
	Std Dev	0.005	0.005	0.003

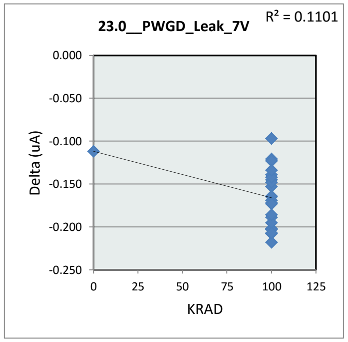


	22.7__PWGD_Trip_Off_Thresh	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.125	V
Min Limit	1.062	V
KRAD	0	100
LL	1.062	1.062
Min	1.093	1.077
Average	1.093	1.089
Max	1.093	1.098
UL	1.125	1.125

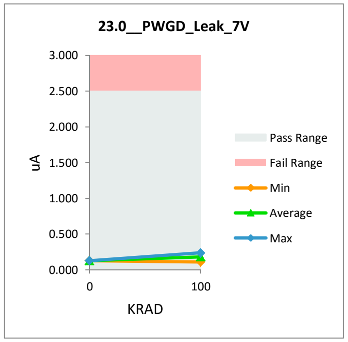


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		23.0__PWGD_Leak_7V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	uA	uA	
	Max Limit	2.5	2.5	
	Min Limit	0	0	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.015	0.127	-0.112
100	294	0.015	0.154	-0.139
100	296	0.019	0.227	-0.208
100	298	0.013	0.166	-0.153
100	299	0.016	0.181	-0.165
100	300	0.014	0.159	-0.145
100	301	0.013	0.134	-0.121
100	302	0.017	0.206	-0.189
100	303	0.018	0.220	-0.202
100	305	0.017	0.165	-0.148
100	307	0.018	0.221	-0.203
100	308	0.015	0.157	-0.142
100	309	0.013	0.136	-0.123
100	310	0.018	0.187	-0.169
100	312	0.016	0.180	-0.164
100	313	0.016	0.188	-0.172
100	314	0.020	0.238	-0.218
100	316	0.017	0.212	-0.195
100	317	0.012	0.109	-0.097
100	318	0.014	0.148	-0.134
100	320	0.017	0.190	-0.173
100	321	0.018	0.204	-0.186
100	322	0.021	0.228	-0.207
	Max	0.021	0.238	-0.097
	Average	0.016	0.180	-0.164
	Min	0.012	0.109	-0.218
	Std Dev	0.002	0.036	0.034



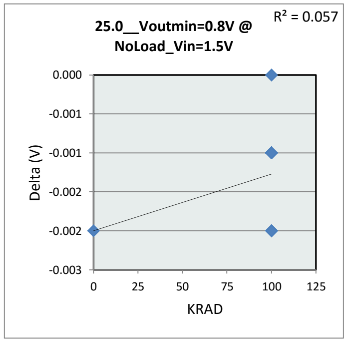
	23.0__PWGD_Leak_7V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	2.5	uA
Min Limit	0	uA
KRAD	0	100
LL	0.000	0.000
Min	0.127	0.109
Average	0.127	0.182
Max	0.127	0.238
UL	2.500	2.500



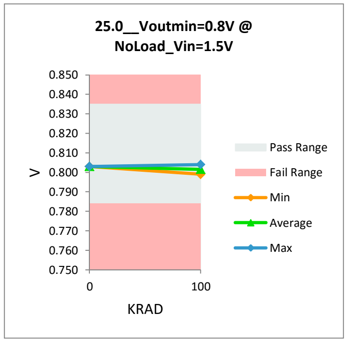
TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

	25.0__Voutmin=0.8V @ NoLoad_		
Test Site	CLAB	CLAB	
Tester	EAG03	EAG03	
Test Number	EF506901	EF506901	
Unit	V	V	
Max Limit	0.835	0.835	
Min Limit	0.784	0.784	

KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.801	0.803	-0.002
100	294	0.800	0.802	-0.002
100	296	0.800	0.801	-0.001
100	298	0.800	0.801	-0.001
100	299	0.798	0.800	-0.002
100	300	0.799	0.799	0.000
100	301	0.802	0.803	-0.001
100	302	0.801	0.802	-0.001
100	303	0.802	0.804	-0.002
100	305	0.799	0.800	-0.001
100	307	0.800	0.801	-0.001
100	308	0.800	0.802	-0.002
100	309	0.803	0.803	0.000
100	310	0.801	0.802	-0.001
100	312	0.801	0.802	-0.001
100	313	0.800	0.802	-0.002
100	314	0.800	0.801	-0.001
100	316	0.803	0.804	-0.001
100	317	0.800	0.801	-0.001
100	318	0.799	0.800	-0.001
100	320	0.800	0.802	-0.002
100	321	0.799	0.801	-0.002
100	322	0.799	0.801	-0.002
	Max	0.803	0.804	0.000
	Average	0.800	0.802	-0.001
	Min	0.798	0.799	-0.002
	Std Dev	0.001	0.001	0.001

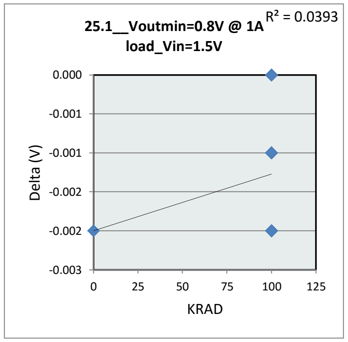


	25.0__Voutmin=0.8V @ NoLoa	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.835	V
Min Limit	0.784	V
KRAD	0	100
LL	0.784	0.784
Min	0.803	0.799
Average	0.803	0.802
Max	0.803	0.804
UL	0.835	0.835

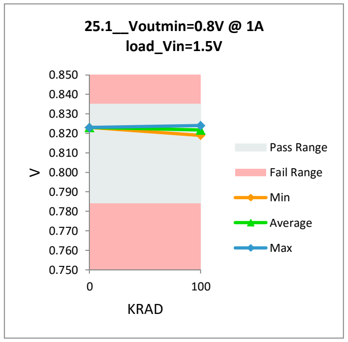


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.1__Voutmin=0.8V @ 1A load		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	0.835	0.835	
	Min Limit	0.784	0.784	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.821	0.823	-0.002
100	294	0.820	0.822	-0.002
100	296	0.820	0.822	-0.002
100	298	0.820	0.821	-0.001
100	299	0.818	0.820	-0.002
100	300	0.819	0.819	0.000
100	301	0.823	0.823	0.000
100	302	0.821	0.822	-0.001
100	303	0.823	0.824	-0.001
100	305	0.819	0.820	-0.001
100	307	0.820	0.822	-0.002
100	308	0.820	0.822	-0.002
100	309	0.823	0.823	0.000
100	310	0.821	0.823	-0.002
100	312	0.821	0.822	-0.001
100	313	0.820	0.822	-0.002
100	314	0.820	0.821	-0.001
100	316	0.823	0.824	-0.001
100	317	0.821	0.821	0.000
100	318	0.819	0.821	-0.002
100	320	0.820	0.822	-0.002
100	321	0.819	0.821	-0.002
100	322	0.820	0.821	-0.001
	Max	0.823	0.824	0.000
	Average	0.820	0.822	-0.001
	Min	0.818	0.819	-0.002
	Std Dev	0.001	0.001	0.001

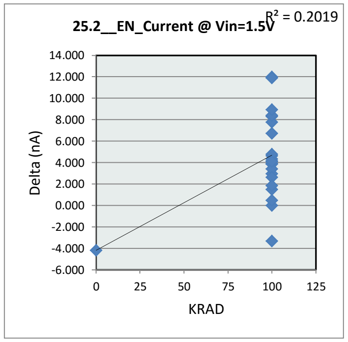


	25.1__Voutmin=0.8V @ 1A loa	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.835	V
Min Limit	0.784	V
KRAD	0	100
LL	0.784	0.784
Min	0.823	0.819
Average	0.823	0.822
Max	0.823	0.824
UL	0.835	0.835

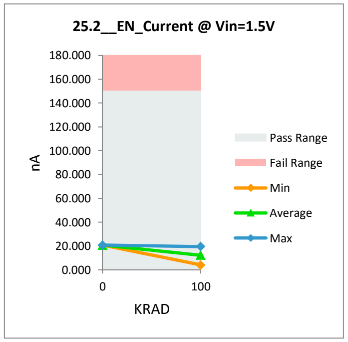


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.2__EN_Current @ Vin=1.5V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	nA	nA	
	Max Limit	150	150	
	Min Limit	0.1	0.1	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	16.493	20.663	-4.170
100	294	17.286	13.430	3.856
100	296	16.587	16.587	0.000
100	298	15.480	7.163	8.317
100	299	16.776	15.291	1.485
100	300	17.074	14.129	2.945
100	301	17.019	5.033	11.986
100	302	17.270	12.951	4.319
100	303	17.294	13.383	3.911
100	305	17.812	10.045	7.767
100	307	17.325	13.925	3.400
100	308	15.920	4.036	11.884
100	309	16.752	12.613	4.139
100	310	17.396	14.773	2.623
100	312	17.859	11.129	6.730
100	313	15.818	13.964	1.854
100	314	17.718	13.077	4.641
100	316	15.833	7.438	8.395
100	317	16.210	19.524	-3.314
100	318	15.590	15.126	0.464
100	320	17.286	12.503	4.783
100	321	19.265	10.320	8.945
100	322	17.875	13.776	4.099
	Max	19.265	20.663	11.986
	Average	16.954	12.647	4.307
	Min	15.480	4.036	-4.170
	Std Dev	0.898	4.027	4.112

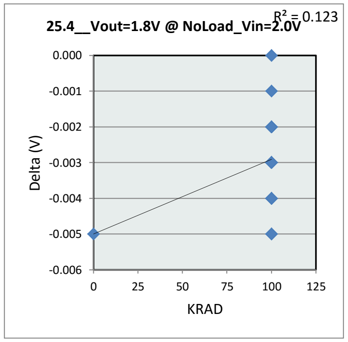


25.2__EN_Current @ Vin=1.5V		
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	150	nA
Min Limit	0.1	nA
KRAD	0	100
LL	0.100	0.100
Min	20.663	4.036
Average	20.663	12.283
Max	20.663	19.524
UL	150.000	150.000

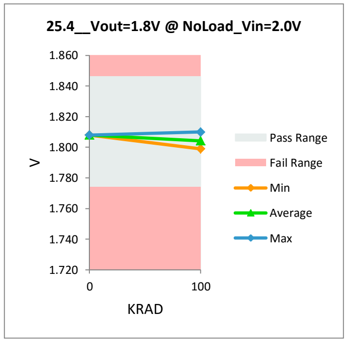


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.4__Vout=1.8V @ NoLoad_Vin		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.846	1.846	
	Min Limit	1.774	1.774	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.803	1.808	-0.005
100	294	1.801	1.805	-0.004
100	296	1.800	1.804	-0.004
100	298	1.801	1.803	-0.002
100	299	1.797	1.801	-0.004
100	300	1.798	1.799	-0.001
100	301	1.806	1.808	-0.002
100	302	1.802	1.805	-0.003
100	303	1.806	1.809	-0.003
100	305	1.798	1.801	-0.003
100	307	1.801	1.804	-0.003
100	308	1.800	1.805	-0.005
100	309	1.807	1.807	0.000
100	310	1.803	1.806	-0.003
100	312	1.802	1.804	-0.002
100	313	1.801	1.804	-0.003
100	314	1.801	1.804	-0.003
100	316	1.806	1.810	-0.004
100	317	1.801	1.803	-0.002
100	318	1.799	1.801	-0.002
100	320	1.801	1.804	-0.003
100	321	1.798	1.803	-0.005
100	322	1.800	1.803	-0.003
	Max	1.807	1.810	0.000
	Average	1.801	1.804	-0.003
	Min	1.797	1.799	-0.005
	Std Dev	0.003	0.003	0.001

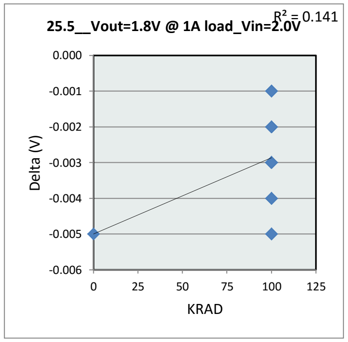


	25.4__Vout=1.8V @ NoLoad_V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.846	V
Min Limit	1.774	V
KRAD	0	100
LL	1.774	1.774
Min	1.808	1.799
Average	1.808	1.804
Max	1.808	1.810
UL	1.846	1.846

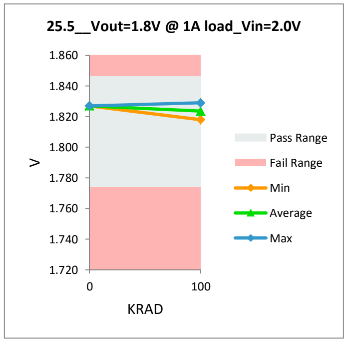


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.5__Vout=1.8V @ 1A load_Vin		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.846	1.846	
	Min Limit	1.774	1.774	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.822	1.827	-0.005
100	294	1.820	1.824	-0.004
100	296	1.820	1.823	-0.003
100	298	1.820	1.822	-0.002
100	299	1.816	1.821	-0.005
100	300	1.817	1.818	-0.001
100	301	1.825	1.827	-0.002
100	302	1.822	1.825	-0.003
100	303	1.826	1.829	-0.003
100	305	1.817	1.820	-0.003
100	307	1.820	1.823	-0.003
100	308	1.820	1.824	-0.004
100	309	1.826	1.827	-0.001
100	310	1.823	1.826	-0.003
100	312	1.821	1.823	-0.002
100	313	1.820	1.824	-0.004
100	314	1.821	1.823	-0.002
100	316	1.826	1.829	-0.003
100	317	1.821	1.822	-0.001
100	318	1.818	1.821	-0.003
100	320	1.821	1.824	-0.003
100	321	1.817	1.822	-0.005
100	322	1.819	1.822	-0.003
	Max	1.826	1.829	-0.001
	Average	1.821	1.824	-0.003
	Min	1.816	1.818	-0.005
	Std Dev	0.003	0.003	0.001

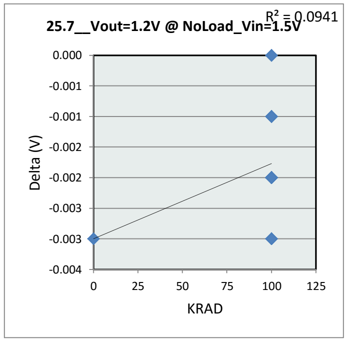


	25.5__Vout=1.8V @ 1A load_V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.846	V
Min Limit	1.774	V
KRAD	0	100
LL	1.774	1.774
Min	1.827	1.818
Average	1.827	1.824
Max	1.827	1.829
UL	1.846	1.846

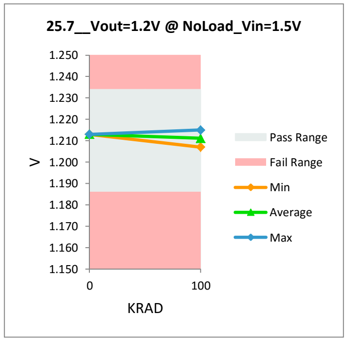


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.7__Vout=1.2V @ NoLoad_Vin		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.234	1.234	
	Min Limit	1.186	1.186	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.210	1.213	-0.003
100	294	1.209	1.211	-0.002
100	296	1.209	1.211	-0.002
100	298	1.209	1.210	-0.001
100	299	1.206	1.209	-0.003
100	300	1.207	1.207	0.000
100	301	1.212	1.214	-0.002
100	302	1.210	1.212	-0.002
100	303	1.213	1.215	-0.002
100	305	1.207	1.209	-0.002
100	307	1.209	1.211	-0.002
100	308	1.209	1.212	-0.003
100	309	1.213	1.213	0.000
100	310	1.211	1.213	-0.002
100	312	1.210	1.211	-0.001
100	313	1.209	1.211	-0.002
100	314	1.209	1.211	-0.002
100	316	1.213	1.215	-0.002
100	317	1.209	1.210	-0.001
100	318	1.208	1.209	-0.001
100	320	1.209	1.211	-0.002
100	321	1.207	1.210	-0.003
100	322	1.208	1.210	-0.002
	Max	1.213	1.215	0.000
	Average	1.209	1.211	-0.002
	Min	1.206	1.207	-0.003
	Std Dev	0.002	0.002	0.001

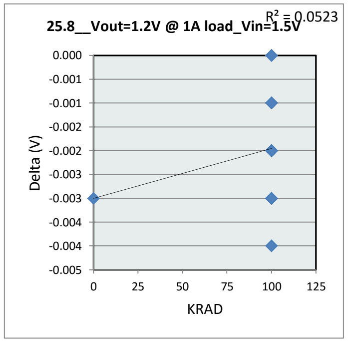


	25.7__Vout=1.2V @ NoLoad_V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.234	V
Min Limit	1.186	V
KRAD	0	100
LL	1.186	1.186
Min	1.213	1.207
Average	1.213	1.211
Max	1.213	1.215
UL	1.234	1.234

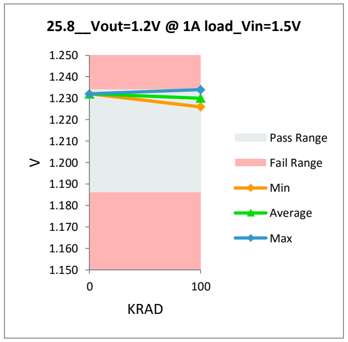


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.8__Vout=1.2V @ 1A load_Vin		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.234	1.234	
	Min Limit	1.186	1.186	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.229	1.232	-0.003
100	294	1.228	1.230	-0.002
100	296	1.227	1.230	-0.003
100	298	1.228	1.229	-0.001
100	299	1.225	1.228	-0.003
100	300	1.226	1.226	0.000
100	301	1.231	1.232	-0.001
100	302	1.229	1.231	-0.002
100	303	1.231	1.233	-0.002
100	305	1.226	1.228	-0.002
100	307	1.228	1.230	-0.002
100	308	1.227	1.231	-0.004
100	309	1.232	1.232	0.000
100	310	1.229	1.231	-0.002
100	312	1.228	1.230	-0.002
100	313	1.228	1.230	-0.002
100	314	1.228	1.230	-0.002
100	316	1.231	1.234	-0.003
100	317	1.228	1.229	-0.001
100	318	1.226	1.228	-0.002
100	320	1.228	1.230	-0.002
100	321	1.226	1.229	-0.003
100	322	1.227	1.229	-0.002
	Max	1.232	1.234	0.000
	Average	1.228	1.230	-0.002
	Min	1.225	1.226	-0.004
	Std Dev	0.002	0.002	0.001

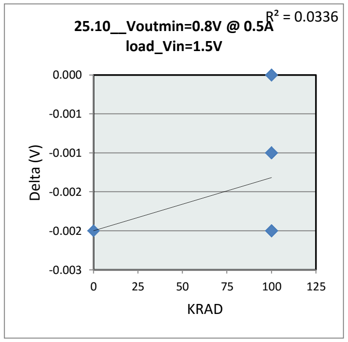


	25.8__Vout=1.2V @ 1A load_V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.234	V
Min Limit	1.186	V
KRAD	0	100
LL	1.186	1.186
Min	1.232	1.226
Average	1.232	1.230
Max	1.232	1.234
UL	1.234	1.234

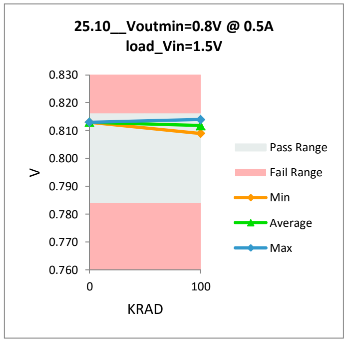


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.10__Voutmin=0.8V @ 0.5A lo		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.811	0.813	-0.002
100	294	0.810	0.812	-0.002
100	296	0.810	0.812	-0.002
100	298	0.810	0.811	-0.001
100	299	0.808	0.810	-0.002
100	300	0.809	0.809	0.000
100	301	0.813	0.813	0.000
100	302	0.811	0.812	-0.001
100	303	0.813	0.814	-0.001
100	305	0.809	0.810	-0.001
100	307	0.810	0.812	-0.002
100	308	0.810	0.812	-0.002
100	309	0.813	0.813	0.000
100	310	0.811	0.813	-0.002
100	312	0.811	0.812	-0.001
100	313	0.810	0.812	-0.002
100	314	0.810	0.812	-0.002
100	316	0.813	0.814	-0.001
100	317	0.811	0.811	0.000
100	318	0.809	0.811	-0.002
100	320	0.810	0.812	-0.002
100	321	0.809	0.811	-0.002
100	322	0.810	0.811	-0.001
	Max	0.813	0.814	0.000
	Average	0.810	0.812	-0.001
	Min	0.808	0.809	-0.002
	Std Dev	0.001	0.001	0.001

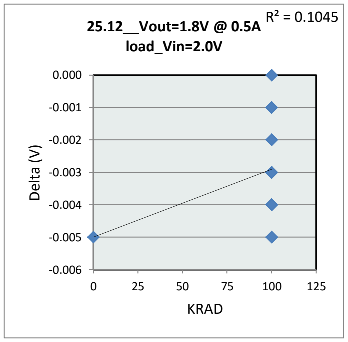


	25.10__Voutmin=0.8V @ 0.5A	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.816	V
Min Limit	0.784	V
KRAD	0	100
LL	0.784	0.784
Min	0.813	0.809
Average	0.813	0.812
Max	0.813	0.814
UL	0.816	0.816

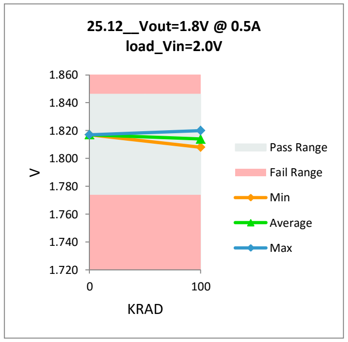


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.12__Vout=1.8V @ 0.5A load_		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.846	1.846	
	Min Limit	1.774	1.774	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.812	1.817	-0.005
100	294	1.811	1.814	-0.003
100	296	1.810	1.813	-0.003
100	298	1.811	1.813	-0.002
100	299	1.806	1.811	-0.005
100	300	1.808	1.808	0.000
100	301	1.816	1.817	-0.001
100	302	1.812	1.815	-0.003
100	303	1.816	1.819	-0.003
100	305	1.807	1.810	-0.003
100	307	1.810	1.814	-0.004
100	308	1.810	1.815	-0.005
100	309	1.816	1.817	-0.001
100	310	1.813	1.816	-0.003
100	312	1.811	1.814	-0.003
100	313	1.810	1.814	-0.004
100	314	1.811	1.813	-0.002
100	316	1.816	1.820	-0.004
100	317	1.811	1.812	-0.001
100	318	1.808	1.811	-0.003
100	320	1.811	1.814	-0.003
100	321	1.808	1.812	-0.004
100	322	1.809	1.813	-0.004
	Max	1.816	1.820	0.000
	Average	1.811	1.814	-0.003
	Min	1.806	1.808	-0.005
	Std Dev	0.003	0.003	0.001

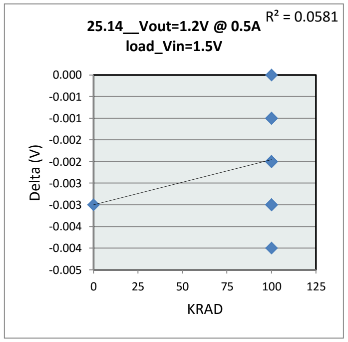


	25.12__Vout=1.8V @ 0.5A loa	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.846	V
Min Limit	1.774	V
KRAD	0	100
LL	1.774	1.774
Min	1.817	1.808
Average	1.817	1.814
Max	1.817	1.820
UL	1.846	1.846

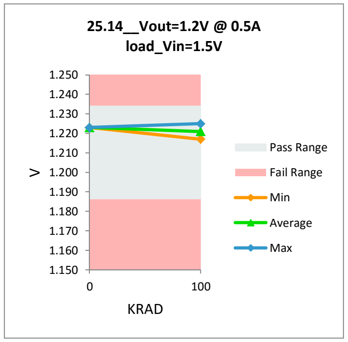


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.14__Vout=1.2V @ 0.5A load_		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.234	1.234	
	Min Limit	1.186	1.186	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.220	1.223	-0.003
100	294	1.219	1.221	-0.002
100	296	1.218	1.221	-0.003
100	298	1.219	1.220	-0.001
100	299	1.216	1.219	-0.003
100	300	1.217	1.217	0.000
100	301	1.222	1.223	-0.001
100	302	1.220	1.222	-0.002
100	303	1.222	1.224	-0.002
100	305	1.216	1.218	-0.002
100	307	1.219	1.221	-0.002
100	308	1.218	1.222	-0.004
100	309	1.222	1.223	-0.001
100	310	1.220	1.222	-0.002
100	312	1.219	1.221	-0.002
100	313	1.219	1.221	-0.002
100	314	1.219	1.220	-0.001
100	316	1.222	1.225	-0.003
100	317	1.219	1.220	-0.001
100	318	1.217	1.219	-0.002
100	320	1.219	1.221	-0.002
100	321	1.217	1.220	-0.003
100	322	1.218	1.220	-0.002
	Max	1.222	1.225	0.000
	Average	1.219	1.221	-0.002
	Min	1.216	1.217	-0.004
	Std Dev	0.002	0.002	0.001

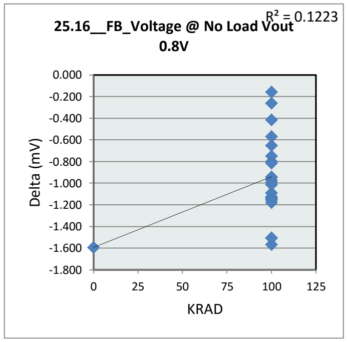


	25.14__Vout=1.2V @ 0.5A load	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.234	V
Min Limit	1.186	V
KRAD	0	100
LL	1.186	1.186
Min	1.223	1.217
Average	1.223	1.221
Max	1.223	1.225
UL	1.234	1.234

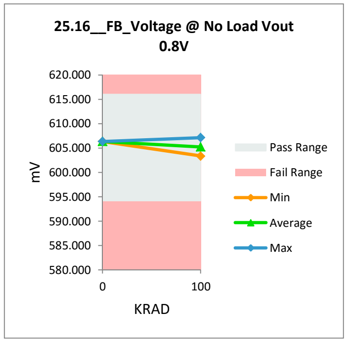


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.16__FB_Voltage @ No Load V		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		mV	mV	
Max Limit		616	616	
Min Limit		594	594	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.762	606.355	-1.593
100	294	604.246	605.371	-1.125
100	296	603.988	605.120	-1.132
100	298	604.204	604.856	-0.652
100	299	602.738	604.246	-1.508
100	300	603.189	603.347	-0.158
100	301	605.827	606.398	-0.571
100	302	604.597	605.539	-0.942
100	303	605.924	606.897	-0.973
100	305	603.030	603.976	-0.946
100	307	604.085	605.174	-1.089
100	308	603.965	605.532	-1.567
100	309	606.054	606.316	-0.262
100	310	604.908	605.901	-0.993
100	312	604.437	605.188	-0.751
100	313	604.073	605.218	-1.145
100	314	604.226	605.027	-0.801
100	316	605.967	607.123	-1.156
100	317	604.286	604.703	-0.417
100	318	603.455	604.271	-0.816
100	320	604.244	605.257	-1.013
100	321	603.188	604.692	-1.504
100	322	603.674	604.854	-1.180
	Max	606.054	607.123	-0.158
	Average	604.307	605.277	-0.969
	Min	602.738	603.347	-1.593
	Std Dev	0.941	0.922	0.389

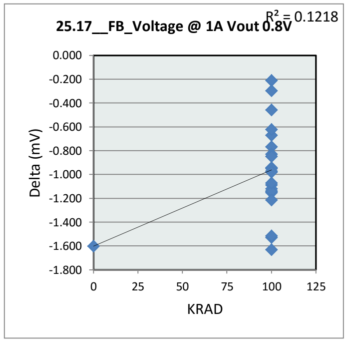


	25.16__FB_Voltage @ No Load	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.355	603.347
Average	606.355	605.228
Max	606.355	607.123
UL	616.000	616.000

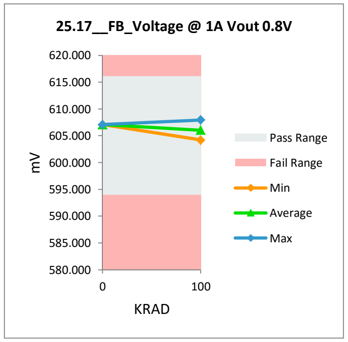


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.17__FB_Voltage @ 1A Vout 0		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		mV	mV	
Max Limit		616	616	
Min Limit		594	594	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	605.469	607.070	-1.601
100	294	605.049	606.187	-1.138
100	296	604.815	605.934	-1.119
100	298	604.948	605.618	-0.670
100	299	603.510	605.038	-1.528
100	300	603.987	604.197	-0.210
100	301	606.630	607.252	-0.622
100	302	605.359	606.302	-0.943
100	303	606.721	607.671	-0.950
100	305	603.777	604.748	-0.971
100	307	604.861	605.950	-1.089
100	308	604.707	606.338	-1.631
100	309	606.817	607.113	-0.296
100	310	605.732	606.711	-0.979
100	312	605.255	606.022	-0.767
100	313	604.937	606.090	-1.153
100	314	604.973	605.804	-0.831
100	316	606.817	607.958	-1.141
100	317	605.108	605.567	-0.459
100	318	604.188	605.037	-0.849
100	320	605.011	606.084	-1.073
100	321	604.007	605.523	-1.516
100	322	604.400	605.613	-1.213
	Max	606.817	607.958	-0.210
	Average	605.090	606.079	-0.989
	Min	603.510	604.197	-1.631
	Std Dev	0.951	0.920	0.382

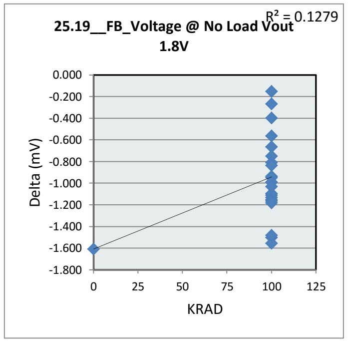


	25.17__FB_Voltage @ 1A Vout	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	607.070	604.197
Average	607.070	606.034
Max	607.070	607.958
UL	616.000	616.000

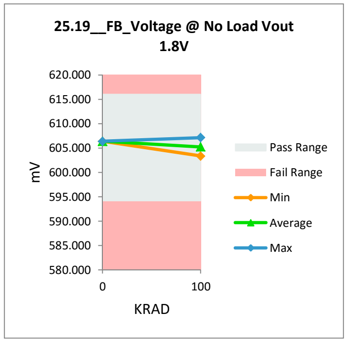


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.19__FB_Voltage @ No Load V		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		mV	mV	
Max Limit		616	616	
Min Limit		594	594	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.752	606.360	-1.608
100	294	604.235	605.345	-1.110
100	296	603.978	605.110	-1.132
100	298	604.187	604.852	-0.665
100	299	602.748	604.250	-1.502
100	300	603.180	603.332	-0.152
100	301	605.832	606.396	-0.564
100	302	604.612	605.548	-0.936
100	303	605.923	606.917	-0.994
100	305	603.036	603.984	-0.948
100	307	604.081	605.176	-1.095
100	308	603.962	605.518	-1.556
100	309	606.058	606.325	-0.267
100	310	604.919	605.908	-0.989
100	312	604.448	605.198	-0.750
100	313	604.084	605.238	-1.154
100	314	604.224	605.033	-0.809
100	316	605.974	607.139	-1.165
100	317	604.304	604.703	-0.399
100	318	603.447	604.282	-0.835
100	320	604.252	605.284	-1.032
100	321	603.188	604.669	-1.481
100	322	603.686	604.869	-1.183
	Max	606.058	607.139	-0.152
	Average	604.309	605.280	-0.971
	Min	602.748	603.332	-1.608
	Std Dev	0.942	0.926	0.388

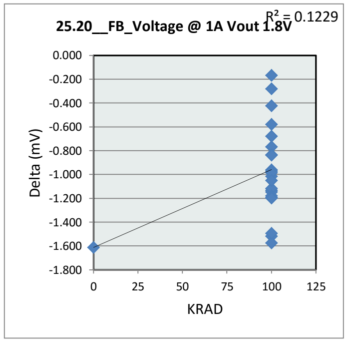


25.19__FB_Voltage @ No Load		
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.360	603.332
Average	606.360	605.231
Max	606.360	607.139
UL	616.000	616.000

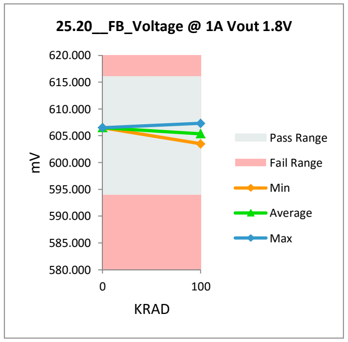


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.20__FB_Voltage @ 1A Vout 1		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.895	606.507	-1.612
100	294	604.368	605.502	-1.134
100	296	604.113	605.260	-1.147
100	298	604.335	605.014	-0.679
100	299	602.886	604.404	-1.518
100	300	603.315	603.483	-0.168
100	301	605.971	606.550	-0.579
100	302	604.750	605.712	-0.962
100	303	606.064	607.078	-1.014
100	305	603.172	604.143	-0.971
100	307	604.228	605.345	-1.117
100	308	604.105	605.679	-1.574
100	309	606.203	606.483	-0.280
100	310	605.058	606.044	-0.986
100	312	604.589	605.358	-0.769
100	313	604.216	605.396	-1.180
100	314	604.369	605.205	-0.836
100	316	606.113	607.307	-1.194
100	317	604.432	604.856	-0.424
100	318	603.587	604.424	-0.837
100	320	604.389	605.440	-1.051
100	321	603.329	604.824	-1.495
100	322	603.818	605.015	-1.197
	Max	606.203	607.307	-0.168
	Average	604.448	605.436	-0.988
	Min	602.886	603.483	-1.612
	Std Dev	0.943	0.928	0.388

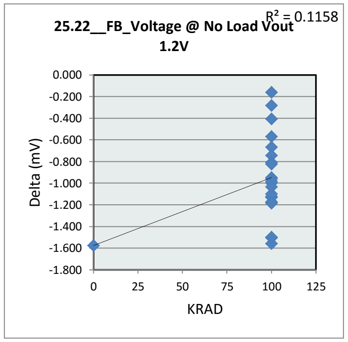


	25.20__FB_Voltage @ 1A Vout	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.507	603.483
Average	606.507	605.387
Max	606.507	607.307
UL	616.000	616.000

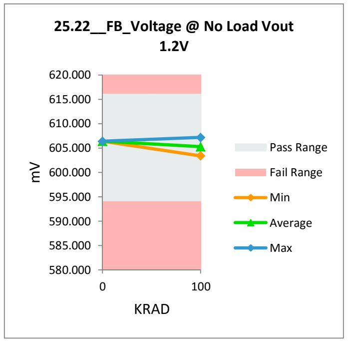


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.22__FB_Voltage @ No Load V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.789	606.366	-1.577
100	294	604.266	605.397	-1.131
100	296	604.018	605.141	-1.123
100	298	604.230	604.898	-0.668
100	299	602.756	604.262	-1.506
100	300	603.214	603.374	-0.160
100	301	605.857	606.428	-0.571
100	302	604.625	605.584	-0.959
100	303	605.949	606.948	-0.999
100	305	603.053	604.001	-0.948
100	307	604.105	605.203	-1.098
100	308	603.991	605.550	-1.559
100	309	606.066	606.348	-0.282
100	310	604.942	605.927	-0.985
100	312	604.463	605.208	-0.745
100	313	604.102	605.275	-1.173
100	314	604.256	605.065	-0.809
100	316	605.991	607.167	-1.176
100	317	604.316	604.723	-0.407
100	318	603.487	604.312	-0.825
100	320	604.271	605.305	-1.034
100	321	603.215	604.713	-1.498
100	322	603.686	604.870	-1.184
	Max	606.066	607.167	-0.160
	Average	604.333	605.307	-0.975
	Min	602.756	603.374	-1.577
	Std Dev	0.941	0.925	0.386

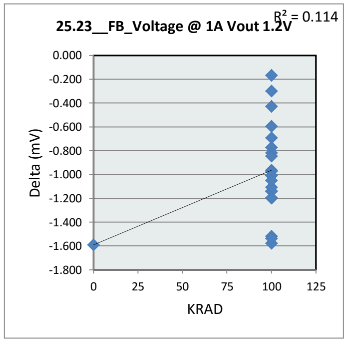


	25.22__FB_Voltage @ No Load	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.366	603.374
Average	606.366	605.259
Max	606.366	607.167
UL	616.000	616.000

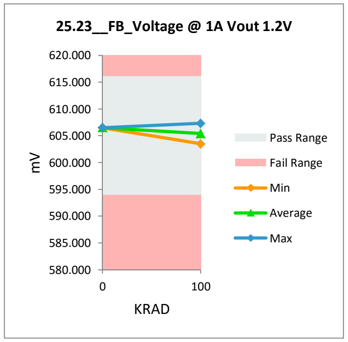


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		25.23__FB_Voltage @ 1A Vout 1		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.909	606.500	-1.591
100	294	604.389	605.532	-1.143
100	296	604.134	605.272	-1.138
100	298	604.352	605.045	-0.693
100	299	602.879	604.398	-1.519
100	300	603.329	603.498	-0.169
100	301	605.974	606.569	-0.595
100	302	604.747	605.712	-0.965
100	303	606.075	607.085	-1.010
100	305	603.175	604.146	-0.971
100	307	604.236	605.344	-1.108
100	308	604.111	605.688	-1.577
100	309	606.191	606.490	-0.299
100	310	605.064	606.071	-1.007
100	312	604.577	605.349	-0.772
100	313	604.219	605.417	-1.198
100	314	604.384	605.202	-0.818
100	316	606.115	607.313	-1.198
100	317	604.434	604.864	-0.430
100	318	603.606	604.452	-0.846
100	320	604.392	605.442	-1.050
100	321	603.340	604.876	-1.536
100	322	603.804	604.999	-1.195
	Max	606.191	607.313	-0.169
	Average	604.454	605.446	-0.993
	Min	602.879	603.498	-1.591
	Std Dev	0.942	0.926	0.386

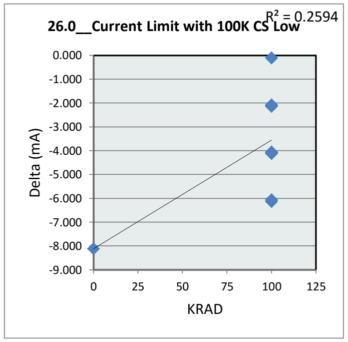


	25.23__FB_Voltage @ 1A Vout	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.500	603.498
Average	606.500	605.398
Max	606.500	607.313
UL	616.000	616.000

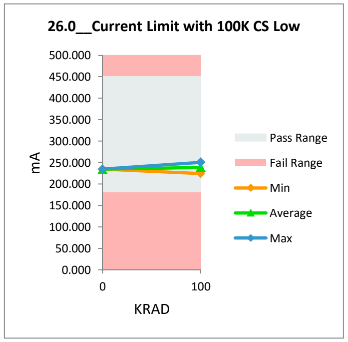


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		26.0__Current Limit with 100K C		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mA	mA	
	Max Limit	450	450	
	Min Limit	180	180	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	226.608	234.730	-8.122
100	294	246.687	250.767	-4.080
100	296	242.686	246.789	-4.103
100	298	228.584	230.729	-2.145
100	299	228.632	230.735	-2.103
100	300	244.687	248.808	-4.121
100	301	234.629	238.744	-4.115
100	302	234.623	240.757	-6.134
100	303	234.665	238.750	-4.085
100	305	236.683	242.746	-6.063
100	307	238.666	242.751	-4.085
100	308	220.629	224.678	-4.049
100	309	228.614	230.705	-2.091
100	310	234.647	238.756	-4.109
100	312	224.649	228.740	-4.091
100	313	246.681	246.795	-0.114
100	314	236.659	242.740	-6.081
100	316	230.621	230.717	-0.096
100	317	236.659	238.732	-2.073
100	318	234.659	238.738	-4.079
100	320	226.649	230.717	-4.068
100	321	236.648	240.751	-4.103
100	322	244.657	246.777	-2.120
	Max	246.687	250.767	-0.096
	Average	234.736	238.485	-3.749
	Min	220.629	224.678	-8.122
	Std Dev	7.193	7.168	1.872

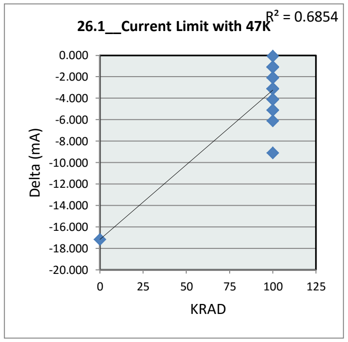


	26.0__Current Limit with 100K	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	450	mA
Min Limit	180	mA
KRAD	0	100
LL	180.000	180.000
Min	234.730	224.678
Average	234.730	238.656
Max	234.730	250.767
UL	450.000	450.000

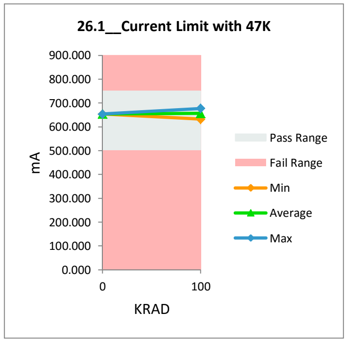


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		26.1__Current Limit with 47K		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mA	mA	
	Max Limit	750	750	
	Min Limit	500	500	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	636.185	653.350	-17.165
100	294	673.353	677.468	-4.115
100	296	669.351	673.454	-4.103
100	298	638.222	640.288	-2.066
100	299	640.187	641.304	-1.117
100	300	667.332	670.450	-3.118
100	301	654.270	656.373	-2.103
100	302	652.275	661.378	-9.103
100	303	651.236	654.360	-3.124
100	305	655.280	660.392	-5.112
100	307	658.272	661.396	-3.124
100	308	630.165	632.243	-2.078
100	309	640.211	641.304	-1.093
100	310	651.266	657.382	-6.116
100	312	637.195	641.298	-4.103
100	313	671.358	672.445	-1.087
100	314	658.290	663.390	-5.100
100	316	644.236	645.311	-1.075
100	317	658.302	658.385	-0.083
100	318	651.260	655.369	-4.109
100	320	638.174	641.304	-3.130
100	321	657.310	660.392	-3.082
100	322	669.339	672.433	-3.094
	Max	673.353	677.468	-0.083
	Average	652.307	656.151	-3.843
	Min	630.165	632.243	-17.165
	Std Dev	12.605	12.564	3.508

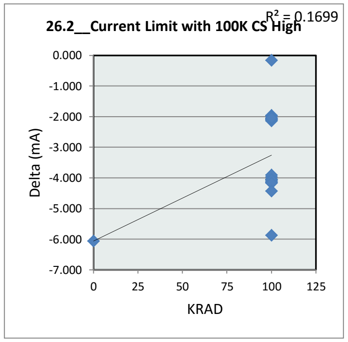


	26.1__Current Limit with 47K	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	750	mA
Min Limit	500	mA
KRAD	0	100
LL	500.000	500.000
Min	653.350	632.243
Average	653.350	656.278
Max	653.350	677.468
UL	750.000	750.000

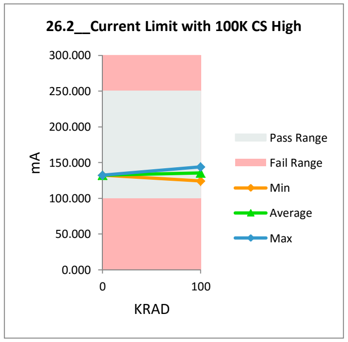


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		26.2__Current Limit with 100K C		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mA	mA	
	Max Limit	250	250	
	Min Limit	100	100	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	126.148	132.205	-6.057
100	294	140.208	142.173	-1.965
100	296	138.165	140.142	-1.977
100	298	126.053	130.210	-4.157
100	299	128.084	130.138	-2.054
100	300	140.023	143.995	-3.972
100	301	131.906	136.027	-4.121
100	302	132.091	137.962	-5.871
100	303	132.127	136.033	-3.906
100	305	133.979	138.028	-4.049
100	307	136.087	140.160	-4.073
100	308	122.027	124.100	-2.073
100	309	126.035	130.162	-4.127
100	310	132.133	136.176	-4.043
100	312	124.118	128.191	-4.073
100	313	139.814	141.916	-2.102
100	314	133.943	138.004	-4.061
100	316	130.061	130.222	-0.161
100	317	131.966	134.104	-2.138
100	318	132.061	136.230	-4.169
100	320	126.035	128.143	-2.108
100	321	134.062	136.111	-2.049
100	322	137.885	142.310	-4.425
	Max	140.208	143.995	-0.161
	Average	131.957	135.337	-3.380
	Min	122.027	124.100	-6.057
	Std Dev	5.290	5.355	1.416

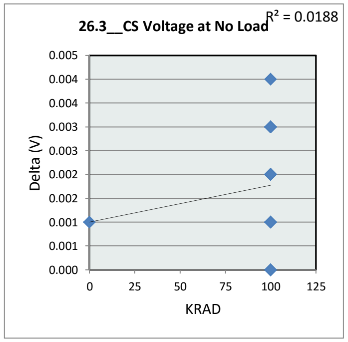


	26.2__Current Limit with 100K	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	250	mA
Min Limit	100	mA
KRAD	0	100
LL	100.000	100.000
Min	132.205	124.100
Average	132.205	135.479
Max	132.205	143.995
UL	250.000	250.000

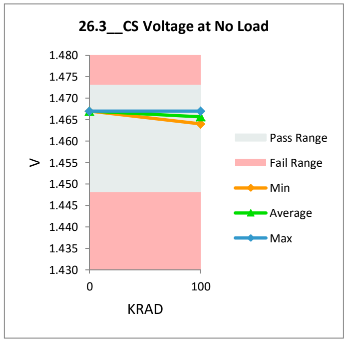


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		26.3__CS Voltage at No Load		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.473	1.473	
	Min Limit	1.448	1.448	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.468	1.467	0.001
100	294	1.467	1.466	0.001
100	296	1.468	1.465	0.003
100	298	1.466	1.466	0.000
100	299	1.468	1.466	0.002
100	300	1.468	1.466	0.002
100	301	1.467	1.465	0.002
100	302	1.466	1.466	0.000
100	303	1.468	1.466	0.002
100	305	1.467	1.466	0.001
100	307	1.468	1.465	0.003
100	308	1.466	1.466	0.000
100	309	1.468	1.467	0.001
100	310	1.466	1.466	0.000
100	312	1.468	1.464	0.004
100	313	1.467	1.464	0.003
100	314	1.468	1.466	0.002
100	316	1.468	1.465	0.003
100	317	1.467	1.466	0.001
100	318	1.468	1.465	0.003
100	320	1.468	1.466	0.002
100	321	1.467	1.466	0.001
100	322	1.470	1.467	0.003
	Max	1.470	1.467	0.004
	Average	1.467	1.466	0.002
	Min	1.466	1.464	0.000
	Std Dev	0.001	0.001	0.001

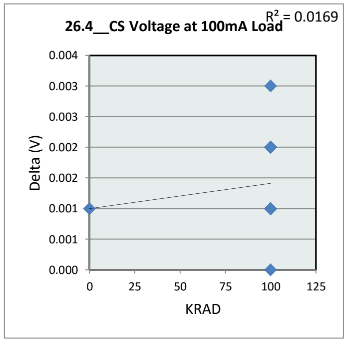


	26.3__CS Voltage at No Load	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.473	V
Min Limit	1.448	V
KRAD	0	100
LL	1.448	1.448
Min	1.467	1.464
Average	1.467	1.466
Max	1.467	1.467
UL	1.473	1.473

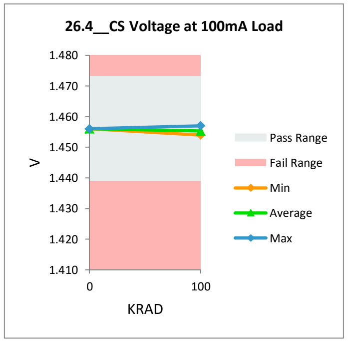


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		26.4__CS Voltage at 100mA Loa		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.473	1.473	
	Min Limit	1.439	1.439	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.457	1.456	0.001
100	294	1.456	1.455	0.001
100	296	1.457	1.455	0.002
100	298	1.456	1.455	0.001
100	299	1.457	1.455	0.002
100	300	1.457	1.456	0.001
100	301	1.456	1.455	0.001
100	302	1.456	1.455	0.001
100	303	1.457	1.456	0.001
100	305	1.457	1.455	0.002
100	307	1.457	1.455	0.002
100	308	1.456	1.455	0.001
100	309	1.457	1.455	0.002
100	310	1.455	1.454	0.001
100	312	1.456	1.455	0.001
100	313	1.457	1.455	0.002
100	314	1.457	1.456	0.001
100	316	1.457	1.455	0.002
100	317	1.457	1.456	0.001
100	318	1.457	1.456	0.001
100	320	1.457	1.454	0.003
100	321	1.458	1.456	0.002
100	322	1.457	1.457	0.000
	Max	1.458	1.457	0.003
	Average	1.457	1.455	0.001
	Min	1.455	1.454	0.000
	Std Dev	0.001	0.001	0.001

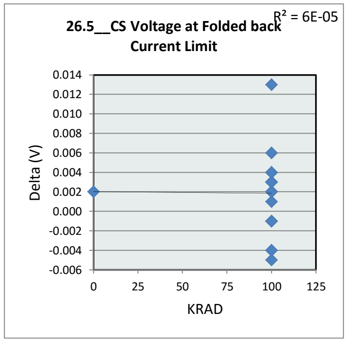


	26.4__CS Voltage at 100mA Lo	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.473	V
Min Limit	1.439	V
KRAD	0	100
LL	1.439	1.439
Min	1.456	1.454
Average	1.456	1.455
Max	1.456	1.457
UL	1.473	1.473

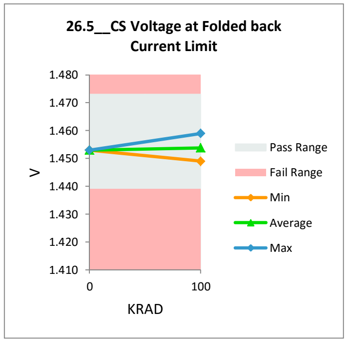


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		26.5__CS Voltage at Folded back		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.473	1.473	
	Min Limit	1.439	1.439	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.455	1.453	0.002
100	294	1.452	1.449	0.003
100	296	1.453	1.450	0.003
100	298	1.456	1.453	0.003
100	299	1.453	1.454	-0.001
100	300	1.454	1.459	-0.005
100	301	1.457	1.455	0.002
100	302	1.454	1.458	-0.004
100	303	1.454	1.458	-0.004
100	305	1.459	1.455	0.004
100	307	1.453	1.452	0.001
100	308	1.455	1.456	-0.001
100	309	1.456	1.452	0.004
100	310	1.452	1.453	-0.001
100	312	1.455	1.453	0.002
100	313	1.462	1.459	0.003
100	314	1.459	1.456	0.003
100	316	1.454	1.452	0.002
100	317	1.456	1.452	0.004
100	318	1.455	1.453	0.002
100	320	1.455	1.453	0.002
100	321	1.458	1.452	0.006
100	322	1.463	1.450	0.013
	Max	1.463	1.459	0.013
	Average	1.456	1.454	0.002
	Min	1.452	1.449	-0.005
	Std Dev	0.003	0.003	0.004

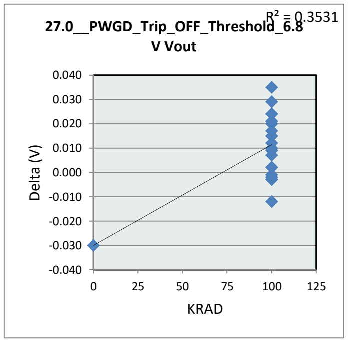


	26.5__CS Voltage at Folded ba	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.473	V
Min Limit	1.439	V
KRAD	0	100
LL	1.439	1.439
Min	1.453	1.449
Average	1.453	1.454
Max	1.453	1.459
UL	1.473	1.473

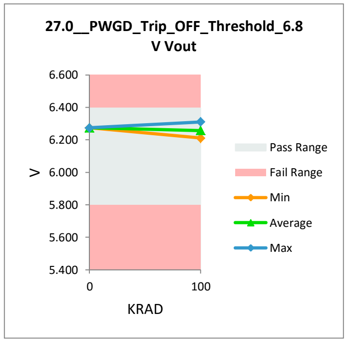


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		27.0__PWGD_Trip_OFF_Thresho		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	6.396	6.396	
	Min Limit	5.8	5.8	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	6.244	6.274	-0.030
100	294	6.257	6.237	0.020
100	296	6.272	6.237	0.035
100	298	6.247	6.250	-0.003
100	299	6.268	6.271	-0.003
100	300	6.302	6.278	0.024
100	301	6.271	6.261	0.010
100	302	6.278	6.280	-0.002
100	303	6.307	6.298	0.009
100	305	6.269	6.248	0.021
100	307	6.245	6.238	0.007
100	308	6.250	6.248	0.002
100	309	6.326	6.311	0.015
100	310	6.291	6.276	0.015
100	312	6.275	6.258	0.017
100	313	6.262	6.263	-0.001
100	314	6.270	6.241	0.029
100	316	6.256	6.254	0.002
100	317	6.261	6.252	0.009
100	318	6.279	6.291	-0.012
100	320	6.251	6.239	0.012
100	321	6.242	6.221	0.021
100	322	6.235	6.211	0.024
	Max	6.326	6.311	0.035
	Average	6.268	6.258	0.010
	Min	6.235	6.211	-0.030
	Std Dev	0.023	0.024	0.015

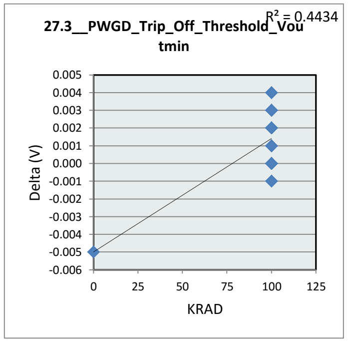


	27.0__PWGD_Trip_OFF_Thres	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	6.396	V
Min Limit	5.8	V
KRAD	0	100
LL	5.800	5.800
Min	6.274	6.211
Average	6.274	6.257
Max	6.274	6.311
UL	6.396	6.396

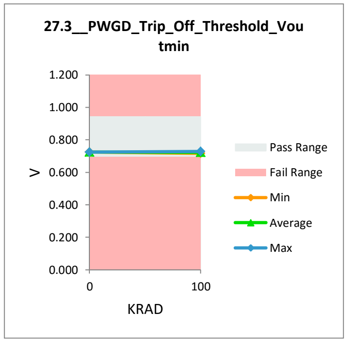


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		27.3__PWGD_Trip_Off_Threshol		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		V	V	
Max Limit		0.942	0.942	
Min Limit		0.695	0.695	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.720	0.725	-0.005
100	294	0.723	0.720	0.003
100	296	0.724	0.720	0.004
100	298	0.721	0.722	-0.001
100	299	0.726	0.724	0.002
100	300	0.729	0.727	0.002
100	301	0.725	0.722	0.003
100	302	0.726	0.726	0.000
100	303	0.729	0.729	0.000
100	305	0.724	0.721	0.003
100	307	0.721	0.720	0.001
100	308	0.722	0.720	0.002
100	309	0.732	0.728	0.004
100	310	0.728	0.726	0.002
100	312	0.724	0.724	0.000
100	313	0.724	0.723	0.001
100	314	0.724	0.721	0.003
100	316	0.722	0.722	0.000
100	317	0.723	0.723	0.000
100	318	0.726	0.727	-0.001
100	320	0.721	0.720	0.001
100	321	0.719	0.719	0.000
100	322	0.719	0.717	0.002
	Max	0.732	0.729	0.004
	Average	0.724	0.723	0.001
	Min	0.719	0.717	-0.005
	Std Dev	0.003	0.003	0.002

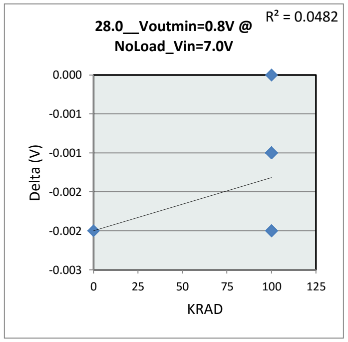


	27.3__PWGD_Trip_Off_Thresh	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.942	V
Min Limit	0.695	V
KRAD	0	100
LL	0.695	0.695
Min	0.725	0.717
Average	0.725	0.723
Max	0.725	0.729
UL	0.942	0.942

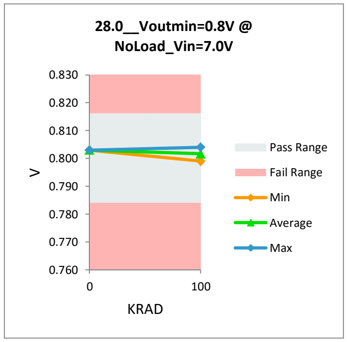


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.0__Voutmin=0.8V @ NoLoad		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.801	0.803	-0.002
100	294	0.800	0.802	-0.002
100	296	0.800	0.801	-0.001
100	298	0.800	0.801	-0.001
100	299	0.798	0.800	-0.002
100	300	0.799	0.799	0.000
100	301	0.802	0.803	-0.001
100	302	0.801	0.802	-0.001
100	303	0.802	0.804	-0.002
100	305	0.799	0.800	-0.001
100	307	0.800	0.802	-0.002
100	308	0.800	0.802	-0.002
100	309	0.803	0.803	0.000
100	310	0.801	0.803	-0.002
100	312	0.801	0.802	-0.001
100	313	0.800	0.802	-0.002
100	314	0.800	0.801	-0.001
100	316	0.803	0.804	-0.001
100	317	0.800	0.801	-0.001
100	318	0.799	0.800	-0.001
100	320	0.800	0.802	-0.002
100	321	0.799	0.801	-0.002
100	322	0.800	0.801	-0.001
	Max	0.803	0.804	0.000
	Average	0.800	0.802	-0.001
	Min	0.798	0.799	-0.002
	Std Dev	0.001	0.001	0.001

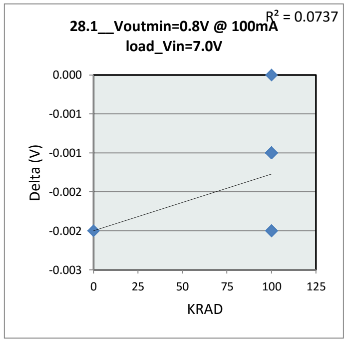


	28.0__Voutmin=0.8V @ NoLoa	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.816	V
Min Limit	0.784	V
KRAD	0	100
LL	0.784	0.784
Min	0.803	0.799
Average	0.803	0.802
Max	0.803	0.804
UL	0.816	0.816

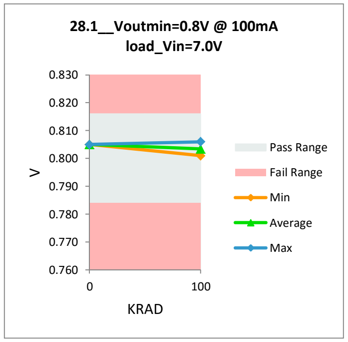


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.1__Voutmin=0.8V @ 100mA		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.803	0.805	-0.002
100	294	0.802	0.803	-0.001
100	296	0.802	0.803	-0.001
100	298	0.802	0.803	-0.001
100	299	0.800	0.802	-0.002
100	300	0.801	0.801	0.000
100	301	0.804	0.805	-0.001
100	302	0.803	0.804	-0.001
100	303	0.804	0.806	-0.002
100	305	0.800	0.802	-0.002
100	307	0.802	0.803	-0.001
100	308	0.802	0.804	-0.002
100	309	0.804	0.805	-0.001
100	310	0.803	0.804	-0.001
100	312	0.802	0.803	-0.001
100	313	0.802	0.803	-0.001
100	314	0.802	0.803	-0.001
100	316	0.804	0.806	-0.002
100	317	0.802	0.803	-0.001
100	318	0.801	0.802	-0.001
100	320	0.802	0.803	-0.001
100	321	0.801	0.803	-0.002
100	322	0.801	0.803	-0.002
	Max	0.804	0.806	0.000
	Average	0.802	0.803	-0.001
	Min	0.800	0.801	-0.002
	Std Dev	0.001	0.001	0.001



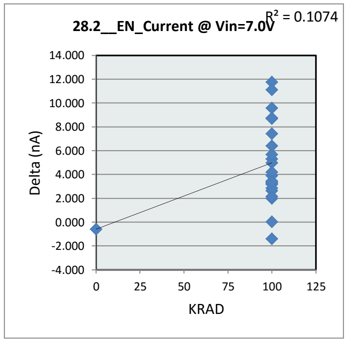
	28.1__Voutmin=0.8V @ 100m	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.816	V
Min Limit	0.784	V
KRAD	0	100
LL	0.784	0.784
Min	0.805	0.801
Average	0.805	0.803
Max	0.805	0.806
UL	0.816	0.816



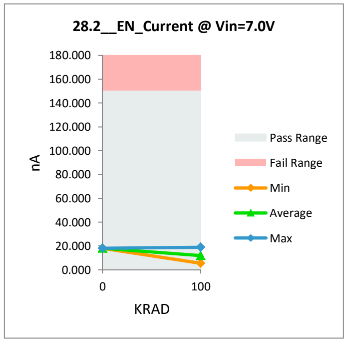
TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

	28.2__EN_Current @ Vin=7.0V	
Test Site	CLAB	CLAB
Tester	EAG03	EAG03
Test Number	EF506901	EF506901
Unit	nA	nA
Max Limit	150	150
Min Limit	0.1	0.1

KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	17.616	18.213	-0.597
100	294	16.705	14.058	2.647
100	296	16.414	16.383	0.031
100	298	16.532	7.783	8.749
100	299	16.705	14.726	1.979
100	300	16.517	14.373	2.144
100	301	15.566	8.153	7.413
100	302	16.116	12.943	3.173
100	303	17.726	13.815	3.911
100	305	16.689	7.988	8.701
100	307	16.202	12.959	3.243
100	308	17.263	5.505	11.758
100	309	17.161	11.852	5.309
100	310	18.833	13.854	4.979
100	312	17.239	11.553	5.686
100	313	18.252	14.043	4.209
100	314	17.333	13.878	3.455
100	316	17.373	6.276	11.097
100	317	17.530	18.920	-1.390
100	318	16.352	13.501	2.851
100	320	17.121	10.729	6.392
100	321	16.163	6.598	9.565
100	322	16.579	13.226	3.353
	Max	18.833	18.920	11.758
	Average	16.956	12.232	4.724
	Min	15.566	5.505	-1.390
	Std Dev	0.749	3.671	3.540

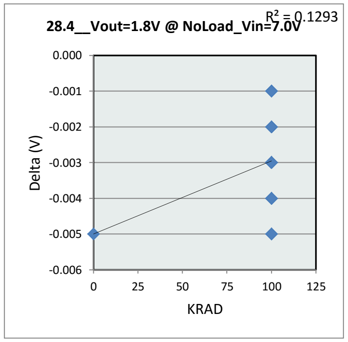


	28.2__EN_Current @ Vin=7.0V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	150	nA
Min Limit	0.1	nA
KRAD	0	100
LL	0.100	0.100
Min	18.213	5.505
Average	18.213	11.960
Max	18.213	18.920
UL	150.000	150.000

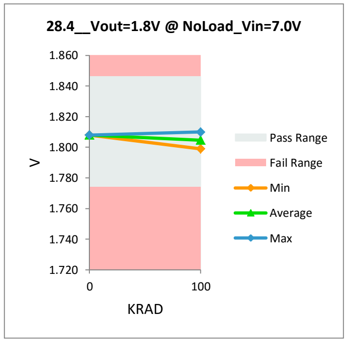


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.4__Vout=1.8V @ NoLoad_Vin		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.846	1.846	
	Min Limit	1.774	1.774	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.803	1.808	-0.005
100	294	1.801	1.805	-0.004
100	296	1.801	1.804	-0.003
100	298	1.801	1.803	-0.002
100	299	1.797	1.802	-0.005
100	300	1.798	1.799	-0.001
100	301	1.806	1.808	-0.002
100	302	1.803	1.806	-0.003
100	303	1.806	1.809	-0.003
100	305	1.798	1.801	-0.003
100	307	1.801	1.804	-0.003
100	308	1.801	1.805	-0.004
100	309	1.807	1.808	-0.001
100	310	1.804	1.807	-0.003
100	312	1.802	1.805	-0.003
100	313	1.801	1.805	-0.004
100	314	1.801	1.804	-0.003
100	316	1.807	1.810	-0.003
100	317	1.802	1.803	-0.001
100	318	1.799	1.801	-0.002
100	320	1.802	1.805	-0.003
100	321	1.798	1.803	-0.005
100	322	1.800	1.804	-0.004
	Max	1.807	1.810	-0.001
	Average	1.802	1.805	-0.003
	Min	1.797	1.799	-0.005
	Std Dev	0.003	0.003	0.001

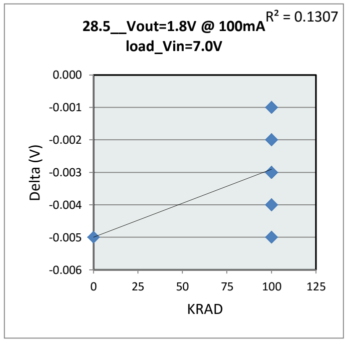


	28.4__Vout=1.8V @ NoLoad_V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.846	V
Min Limit	1.774	V
KRAD	0	100
LL	1.774	1.774
Min	1.808	1.799
Average	1.808	1.805
Max	1.808	1.810
UL	1.846	1.846

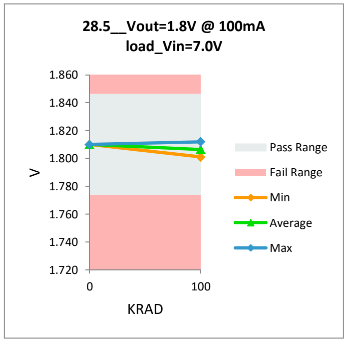


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.5__Vout=1.8V @ 100mA load		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		V	V	
Max Limit		1.846	1.846	
Min Limit		1.774	1.774	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.805	1.810	-0.005
100	294	1.803	1.806	-0.003
100	296	1.802	1.806	-0.004
100	298	1.803	1.805	-0.002
100	299	1.799	1.804	-0.005
100	300	1.800	1.801	-0.001
100	301	1.808	1.810	-0.002
100	302	1.805	1.808	-0.003
100	303	1.808	1.811	-0.003
100	305	1.800	1.803	-0.003
100	307	1.803	1.806	-0.003
100	308	1.803	1.807	-0.004
100	309	1.809	1.810	-0.001
100	310	1.805	1.809	-0.004
100	312	1.804	1.806	-0.002
100	313	1.803	1.806	-0.003
100	314	1.803	1.806	-0.003
100	316	1.809	1.812	-0.003
100	317	1.804	1.805	-0.001
100	318	1.801	1.803	-0.002
100	320	1.803	1.807	-0.004
100	321	1.800	1.805	-0.005
100	322	1.802	1.805	-0.003
	Max	1.809	1.812	-0.001
	Average	1.804	1.807	-0.003
	Min	1.799	1.801	-0.005
	Std Dev	0.003	0.003	0.001

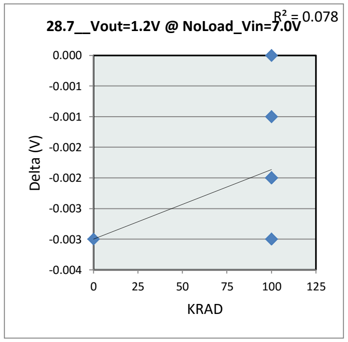


	28.5__Vout=1.8V @ 100mA loa	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.846	V
Min Limit	1.774	V
KRAD	0	100
LL	1.774	1.774
Min	1.810	1.801
Average	1.810	1.806
Max	1.810	1.812
UL	1.846	1.846

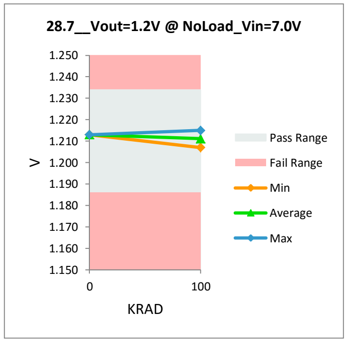


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.7__Vout=1.2V @ NoLoad_Vin		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.234	1.234	
	Min Limit	1.186	1.186	
KRAD	Serial #	'reRLAT_3-3-17.tx	l01A-RLAT-POST_	Delta
0	C1	1.210	1.213	-0.003
100	294	1.209	1.211	-0.002
100	296	1.209	1.211	-0.002
100	298	1.209	1.210	-0.001
100	299	1.206	1.209	-0.003
100	300	1.207	1.207	0.000
100	301	1.212	1.214	-0.002
100	302	1.210	1.212	-0.002
100	303	1.212	1.214	-0.002
100	305	1.207	1.209	-0.002
100	307	1.209	1.211	-0.002
100	308	1.209	1.212	-0.003
100	309	1.213	1.213	0.000
100	310	1.211	1.213	-0.002
100	312	1.210	1.211	-0.001
100	313	1.209	1.211	-0.002
100	314	1.209	1.211	-0.002
100	316	1.213	1.215	-0.002
100	317	1.209	1.210	-0.001
100	318	1.207	1.209	-0.002
100	320	1.209	1.211	-0.002
100	321	1.207	1.210	-0.003
100	322	1.208	1.211	-0.003
	Max	1.213	1.215	0.000
	Average	1.209	1.211	-0.002
	Min	1.206	1.207	-0.003
	Std Dev	0.002	0.002	0.001

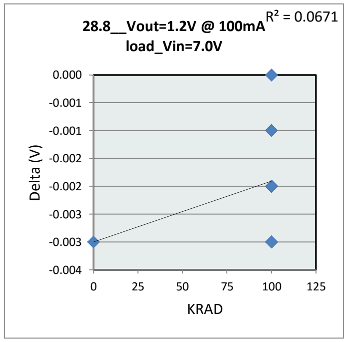


	28.7__Vout=1.2V @ NoLoad_V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.234	V
Min Limit	1.186	V
KRAD	0	100
LL	1.186	1.186
Min	1.213	1.207
Average	1.213	1.211
Max	1.213	1.215
UL	1.234	1.234

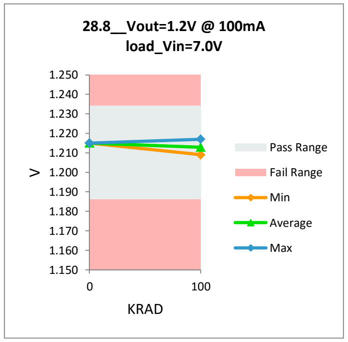


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.8__Vout=1.2V @ 100mA load		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.234	1.234	
	Min Limit	1.186	1.186	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.212	1.215	-0.003
100	294	1.211	1.213	-0.002
100	296	1.210	1.213	-0.003
100	298	1.211	1.212	-0.001
100	299	1.208	1.211	-0.003
100	300	1.209	1.209	0.000
100	301	1.214	1.215	-0.001
100	302	1.212	1.214	-0.002
100	303	1.214	1.216	-0.002
100	305	1.208	1.210	-0.002
100	307	1.211	1.213	-0.002
100	308	1.210	1.213	-0.003
100	309	1.215	1.215	0.000
100	310	1.212	1.214	-0.002
100	312	1.211	1.213	-0.002
100	313	1.211	1.213	-0.002
100	314	1.211	1.213	-0.002
100	316	1.214	1.217	-0.003
100	317	1.211	1.212	-0.001
100	318	1.209	1.211	-0.002
100	320	1.211	1.213	-0.002
100	321	1.209	1.212	-0.003
100	322	1.210	1.212	-0.002
	Max	1.215	1.217	0.000
	Average	1.211	1.213	-0.002
	Min	1.208	1.209	-0.003
	Std Dev	0.002	0.002	0.001

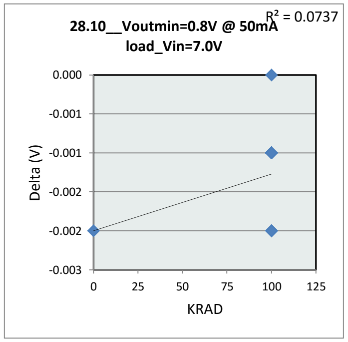


	28.8__Vout=1.2V @ 100mA loa	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.234	V
Min Limit	1.186	V
KRAD	0	100
LL	1.186	1.186
Min	1.215	1.209
Average	1.215	1.213
Max	1.215	1.217
UL	1.234	1.234

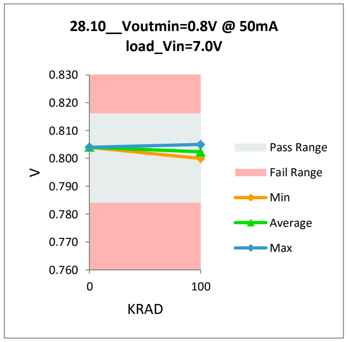


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.10__Voutmin=0.8V @ 50mA I		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.802	0.804	-0.002
100	294	0.801	0.802	-0.001
100	296	0.801	0.802	-0.001
100	298	0.801	0.802	-0.001
100	299	0.799	0.801	-0.002
100	300	0.800	0.800	0.000
100	301	0.803	0.804	-0.001
100	302	0.802	0.803	-0.001
100	303	0.803	0.805	-0.002
100	305	0.799	0.801	-0.002
100	307	0.801	0.802	-0.001
100	308	0.801	0.803	-0.002
100	309	0.803	0.804	-0.001
100	310	0.802	0.803	-0.001
100	312	0.801	0.802	-0.001
100	313	0.801	0.802	-0.001
100	314	0.801	0.802	-0.001
100	316	0.803	0.805	-0.002
100	317	0.801	0.802	-0.001
100	318	0.800	0.801	-0.001
100	320	0.801	0.802	-0.001
100	321	0.800	0.802	-0.002
100	322	0.800	0.802	-0.002
	Max	0.803	0.805	0.000
	Average	0.801	0.802	-0.001
	Min	0.799	0.800	-0.002
	Std Dev	0.001	0.001	0.001

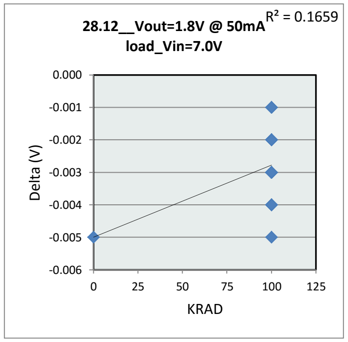


	28.10__Voutmin=0.8V @ 50mA	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	0.816	V
Min Limit	0.784	V
KRAD	0	100
LL	0.784	0.784
Min	0.804	0.800
Average	0.804	0.802
Max	0.804	0.805
UL	0.816	0.816

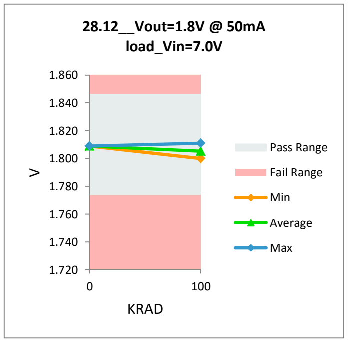


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.12__Vout=1.8V @ 50mA load		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.846	1.846	
	Min Limit	1.774	1.774	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	1.804	1.809	-0.005
100	294	1.802	1.805	-0.003
100	296	1.801	1.805	-0.004
100	298	1.802	1.804	-0.002
100	299	1.798	1.803	-0.005
100	300	1.799	1.800	-0.001
100	301	1.807	1.809	-0.002
100	302	1.804	1.806	-0.002
100	303	1.807	1.810	-0.003
100	305	1.799	1.802	-0.003
100	307	1.802	1.805	-0.003
100	308	1.802	1.806	-0.004
100	309	1.808	1.809	-0.001
100	310	1.804	1.807	-0.003
100	312	1.803	1.805	-0.002
100	313	1.802	1.805	-0.003
100	314	1.802	1.805	-0.003
100	316	1.808	1.811	-0.003
100	317	1.803	1.804	-0.001
100	318	1.800	1.802	-0.002
100	320	1.802	1.806	-0.004
100	321	1.799	1.803	-0.004
100	322	1.801	1.804	-0.003
	Max	1.808	1.811	-0.001
	Average	1.803	1.805	-0.003
	Min	1.798	1.800	-0.005
	Std Dev	0.003	0.003	0.001

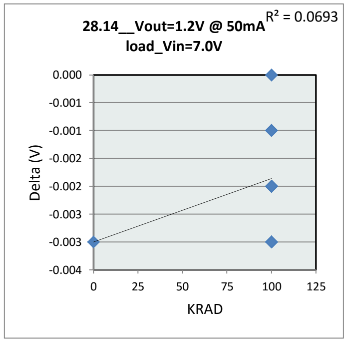


	28.12__Vout=1.8V @ 50mA loa	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.846	V
Min Limit	1.774	V
KRAD	0	100
LL	1.774	1.774
Min	1.809	1.800
Average	1.809	1.805
Max	1.809	1.811
UL	1.846	1.846

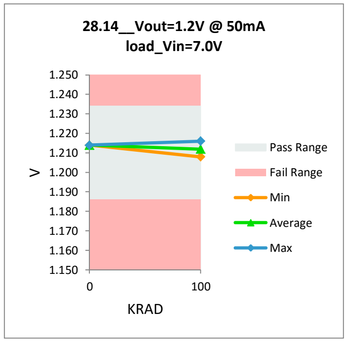


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.14__Vout=1.2V @ 50mA load		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	1.234	1.234	
	Min Limit	1.186	1.186	
KRAD	Serial #	PreRLAT_3-3-17.tx	101A-RLAT-POST_	Delta
0	C1	1.211	1.214	-0.003
100	294	1.210	1.212	-0.002
100	296	1.209	1.212	-0.003
100	298	1.210	1.211	-0.001
100	299	1.207	1.210	-0.003
100	300	1.208	1.208	0.000
100	301	1.213	1.214	-0.001
100	302	1.211	1.213	-0.002
100	303	1.213	1.215	-0.002
100	305	1.208	1.209	-0.001
100	307	1.210	1.212	-0.002
100	308	1.209	1.212	-0.003
100	309	1.214	1.214	0.000
100	310	1.211	1.213	-0.002
100	312	1.210	1.212	-0.002
100	313	1.210	1.212	-0.002
100	314	1.210	1.212	-0.002
100	316	1.213	1.216	-0.003
100	317	1.210	1.211	-0.001
100	318	1.208	1.210	-0.002
100	320	1.210	1.212	-0.002
100	321	1.208	1.211	-0.003
100	322	1.209	1.211	-0.002
	Max	1.214	1.216	0.000
	Average	1.210	1.212	-0.002
	Min	1.207	1.208	-0.003
	Std Dev	0.002	0.002	0.001

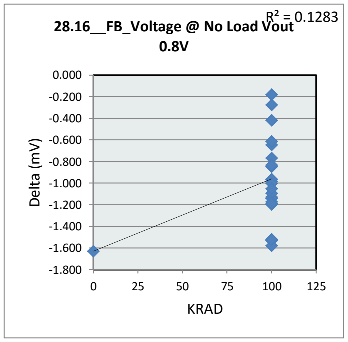


	28.14__Vout=1.2V @ 50mA loa	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	1.234	V
Min Limit	1.186	V
KRAD	0	100
LL	1.186	1.186
Min	1.214	1.208
Average	1.214	1.212
Max	1.214	1.216
UL	1.234	1.234

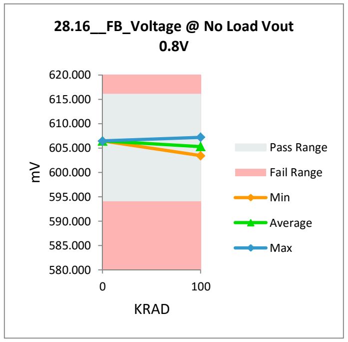


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.16__FB_Voltage @ No Load V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.802	606.431	-1.629
100	294	604.291	605.432	-1.141
100	296	604.038	605.168	-1.130
100	298	604.249	604.895	-0.646
100	299	602.800	604.330	-1.530
100	300	603.240	603.422	-0.182
100	301	605.878	606.492	-0.614
100	302	604.659	605.623	-0.964
100	303	605.982	606.966	-0.984
100	305	603.087	604.054	-0.967
100	307	604.137	605.231	-1.094
100	308	604.024	605.603	-1.579
100	309	606.106	606.383	-0.277
100	310	604.977	605.978	-1.001
100	312	604.498	605.265	-0.767
100	313	604.132	605.329	-1.197
100	314	604.292	605.141	-0.849
100	316	606.019	607.191	-1.172
100	317	604.357	604.776	-0.419
100	318	603.516	604.348	-0.832
100	320	604.298	605.350	-1.052
100	321	603.245	604.764	-1.519
100	322	603.730	604.921	-1.191
	Max	606.106	607.191	-0.182
	Average	604.363	605.352	-0.989
	Min	602.800	603.422	-1.629
	Std Dev	0.940	0.922	0.390

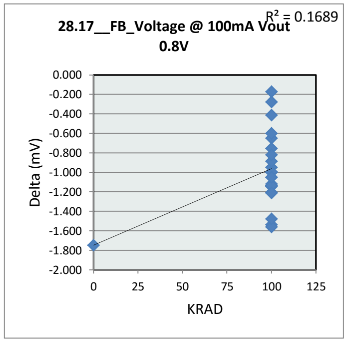


	28.16__FB_Voltage @ No Load	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.431	603.422
Average	606.431	605.303
Max	606.431	607.191
UL	616.000	616.000

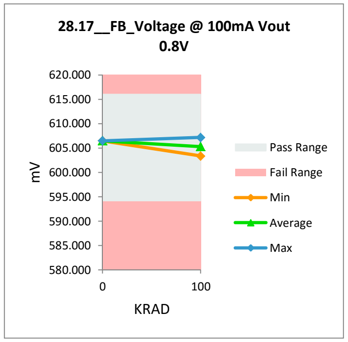


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.17__FB_Voltage @ 100mA Vo		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.715	606.462	-1.747
100	294	604.185	605.305	-1.120
100	296	603.949	605.096	-1.147
100	298	604.179	604.829	-0.650
100	299	602.826	604.362	-1.536
100	300	603.189	603.360	-0.171
100	301	605.871	606.470	-0.599
100	302	604.731	605.681	-0.950
100	303	605.939	606.939	-1.000
100	305	603.064	604.058	-0.994
100	307	604.117	605.254	-1.137
100	308	604.022	605.582	-1.560
100	309	606.128	606.406	-0.278
100	310	604.949	605.999	-1.050
100	312	604.506	605.260	-0.754
100	313	604.099	605.305	-1.206
100	314	604.243	605.128	-0.885
100	316	606.036	607.173	-1.137
100	317	604.363	604.777	-0.414
100	318	603.449	604.268	-0.819
100	320	604.306	605.358	-1.052
100	321	603.198	604.675	-1.477
100	322	603.765	604.976	-1.211
	Max	606.128	607.173	-0.171
	Average	604.340	605.336	-0.995
	Min	602.826	603.360	-1.747
	Std Dev	0.948	0.933	0.399

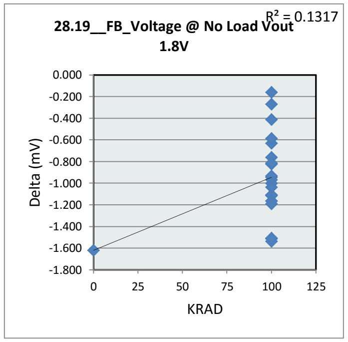


	28.17__FB_Voltage @ 100mA V	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.462	603.360
Average	606.462	605.285
Max	606.462	607.173
UL	616.000	616.000

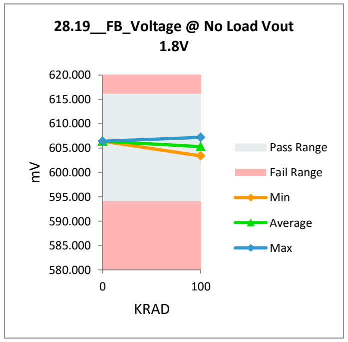


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.19__FB_Voltage @ No Load V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.788	606.409	-1.621
100	294	604.274	605.389	-1.115
100	296	604.019	605.134	-1.115
100	298	604.228	604.860	-0.632
100	299	602.798	604.313	-1.515
100	300	603.228	603.389	-0.161
100	301	605.872	606.458	-0.586
100	302	604.666	605.610	-0.944
100	303	605.966	606.936	-0.970
100	305	603.078	604.013	-0.935
100	307	604.123	605.231	-1.108
100	308	604.019	605.556	-1.537
100	309	606.102	606.373	-0.271
100	310	604.976	605.977	-1.001
100	312	604.503	605.264	-0.761
100	313	604.132	605.296	-1.164
100	314	604.281	605.105	-0.824
100	316	606.024	607.189	-1.165
100	317	604.357	604.771	-0.414
100	318	603.498	604.314	-0.816
100	320	604.295	605.333	-1.038
100	321	603.239	604.746	-1.507
100	322	603.731	604.923	-1.192
	Max	606.102	607.189	-0.161
	Average	604.356	605.330	-0.974
	Min	602.798	603.389	-1.621
	Std Dev	0.941	0.925	0.389

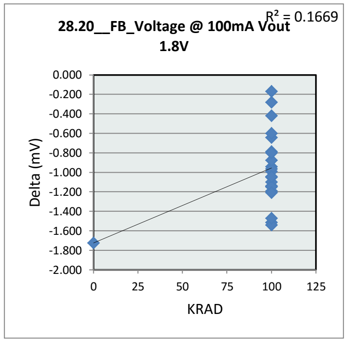


	28.19__FB_Voltage @ No Load	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.409	603.389
Average	606.409	605.281
Max	606.409	607.189
UL	616.000	616.000

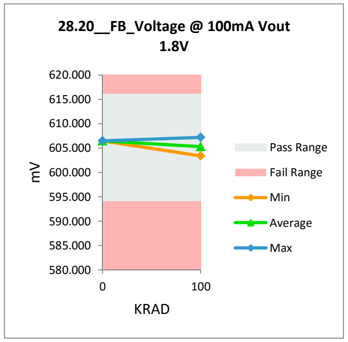


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.20__FB_Voltage @ 100mA Vo		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		mV	mV	
Max Limit		616	616	
Min Limit		594	594	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.741	606.466	-1.725
100	294	604.209	605.309	-1.100
100	296	603.975	605.124	-1.149
100	298	604.199	604.841	-0.642
100	299	602.852	604.365	-1.513
100	300	603.210	603.379	-0.169
100	301	605.890	606.491	-0.601
100	302	604.755	605.698	-0.943
100	303	605.963	606.955	-0.992
100	305	603.091	604.056	-0.965
100	307	604.142	605.282	-1.140
100	308	604.043	605.582	-1.539
100	309	606.149	606.431	-0.282
100	310	604.978	606.027	-1.049
100	312	604.533	605.322	-0.789
100	313	604.121	605.313	-1.192
100	314	604.271	605.146	-0.875
100	316	606.057	607.202	-1.145
100	317	604.384	604.803	-0.419
100	318	603.474	604.274	-0.800
100	320	604.337	605.382	-1.045
100	321	603.224	604.694	-1.470
100	322	603.793	605.001	-1.208
	Max	606.149	607.202	-0.169
	Average	604.365	605.354	-0.989
	Min	602.852	603.379	-1.725
	Std Dev	0.947	0.936	0.393

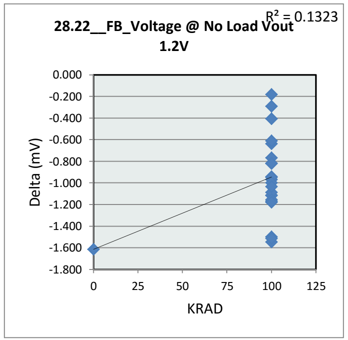


	28.20__FB_Voltage @ 100mA	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.466	603.379
Average	606.466	605.304
Max	606.466	607.202
UL	616.000	616.000

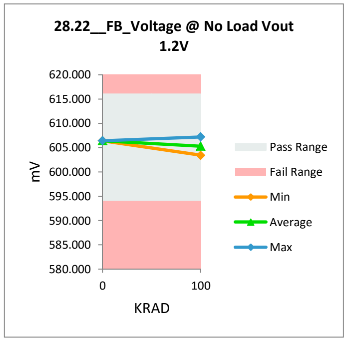


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.22__FB_Voltage @ No Load V		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.793	606.407	-1.614
100	294	604.281	605.395	-1.114
100	296	604.029	605.146	-1.117
100	298	604.232	604.870	-0.638
100	299	602.808	604.308	-1.500
100	300	603.230	603.413	-0.183
100	301	605.873	606.485	-0.612
100	302	604.673	605.614	-0.941
100	303	605.969	606.939	-0.970
100	305	603.084	604.033	-0.949
100	307	604.130	605.217	-1.087
100	308	604.019	605.566	-1.547
100	309	606.104	606.396	-0.292
100	310	604.983	605.982	-0.999
100	312	604.512	605.280	-0.768
100	313	604.136	605.307	-1.171
100	314	604.287	605.106	-0.819
100	316	606.029	607.185	-1.156
100	317	604.355	604.762	-0.407
100	318	603.502	604.323	-0.821
100	320	604.299	605.333	-1.034
100	321	603.244	604.757	-1.513
100	322	603.742	604.922	-1.180
	Max	606.104	607.185	-0.183
	Average	604.361	605.337	-0.975
	Min	602.808	603.413	-1.614
	Std Dev	0.940	0.924	0.383

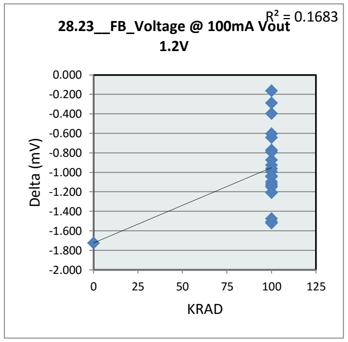


	28.22__FB_Voltage @ No Load	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.407	603.413
Average	606.407	605.288
Max	606.407	607.185
UL	616.000	616.000

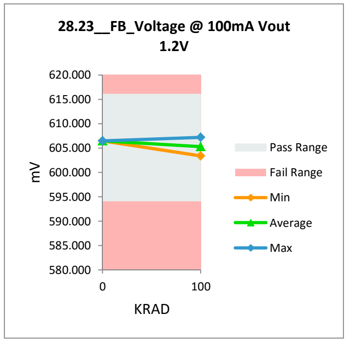


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		28.23__FB_Voltage @ 100mA Vo		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	604.741	606.466	-1.725
100	294	604.213	605.310	-1.097
100	296	603.976	605.125	-1.149
100	298	604.208	604.851	-0.643
100	299	602.851	604.360	-1.509
100	300	603.213	603.375	-0.162
100	301	605.894	606.498	-0.604
100	302	604.761	605.688	-0.927
100	303	605.957	606.948	-0.991
100	305	603.092	604.054	-0.962
100	307	604.143	605.262	-1.119
100	308	604.047	605.568	-1.521
100	309	606.147	606.434	-0.287
100	310	604.981	606.019	-1.038
100	312	604.542	605.312	-0.770
100	313	604.123	605.329	-1.206
100	314	604.274	605.146	-0.872
100	316	606.064	607.202	-1.138
100	317	604.388	604.783	-0.395
100	318	603.473	604.264	-0.791
100	320	604.330	605.374	-1.044
100	321	603.227	604.702	-1.475
100	322	603.796	605.003	-1.207
	Max	606.147	607.202	-0.162
	Average	604.367	605.351	-0.984
	Min	602.851	603.375	-1.725
	Std Dev	0.947	0.936	0.394

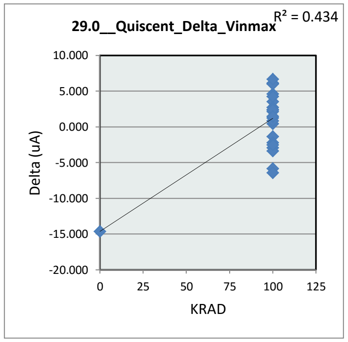


	28.23__FB_Voltage @ 100mA	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	616	mV
Min Limit	594	mV
KRAD	0	100
LL	594.000	594.000
Min	606.466	603.375
Average	606.466	605.300
Max	606.466	607.202
UL	616.000	616.000

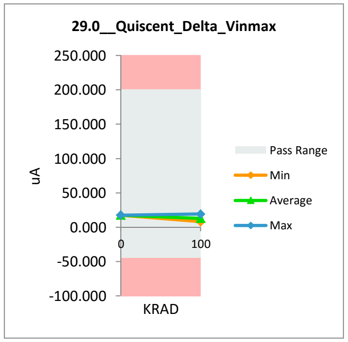


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		29.0__Quiscent_Delta_Vinmax		
Test Site		CLAB	CLAB	
Tester		EAG03	EAG03	
Test Number		EF506901	EF506901	
Unit		uA	uA	
Max Limit		200	200	
Min Limit		-43.816	-43.816	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	3.063	17.692	-14.629
100	294	18.661	12.610	6.051
100	296	13.467	19.328	-5.861
100	298	15.292	14.867	0.425
100	299	15.296	14.076	1.220
100	300	15.310	10.694	4.616
100	301	14.829	16.182	-1.353
100	302	12.659	15.608	-2.949
100	303	12.549	18.987	-6.438
100	305	13.032	9.510	3.522
100	307	12.390	14.585	-2.195
100	308	12.444	10.331	2.113
100	309	14.962	8.835	6.127
100	310	13.400	11.038	2.362
100	312	13.436	16.832	-3.396
100	313	13.587	16.111	-2.524
100	314	14.386	11.676	2.710
100	316	13.712	12.892	0.820
100	317	15.692	13.282	2.410
100	318	14.181	8.208	5.973
100	320	14.319	12.851	1.468
100	321	14.666	8.004	6.662
100	322	12.977	8.743	4.234
	Max	18.661	19.328	6.662
	Average	13.666	13.171	0.494
	Min	3.063	8.004	-14.629
	Std Dev	2.707	3.435	5.004

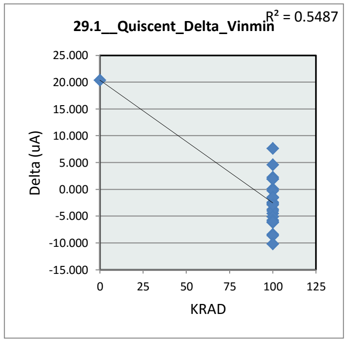


	29.0__Quiscent_Delta_Vinmax	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	200	uA
Min Limit	-43.816	uA
KRAD	0	100
LL	-43.816	-43.816
Min	17.692	8.004
Average	17.692	12.966
Max	17.692	19.328
UL	200.000	200.000

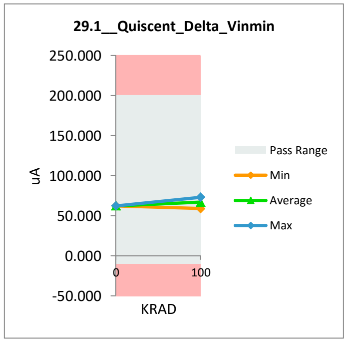


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		29.1__Quiscent_Delta_Vinmin		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	uA	uA	
	Max Limit	200	200	
	Min Limit	-10.059	-10.059	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	82.774	62.431	20.343
100	294	59.125	67.513	-8.388
100	296	65.009	60.434	4.575
100	298	63.970	66.599	-2.629
100	299	64.336	66.721	-2.385
100	300	64.090	67.803	-3.713
100	301	63.379	63.242	0.137
100	302	66.255	64.373	1.882
100	303	66.724	59.103	7.621
100	305	65.950	70.473	-4.523
100	307	66.993	64.737	2.256
100	308	65.916	69.943	-4.027
100	309	63.821	72.450	-8.629
100	310	65.167	70.268	-5.101
100	312	65.338	63.381	1.957
100	313	64.967	65.209	-0.242
100	314	65.613	67.194	-1.581
100	316	64.992	66.420	-1.428
100	317	62.057	67.808	-5.751
100	318	63.048	73.247	-10.199
100	320	64.346	67.231	-2.885
100	321	64.865	71.004	-6.139
100	322	65.130	71.181	-6.051
	Max	82.774	73.247	20.343
	Average	65.385	66.903	-1.517
	Min	59.125	59.103	-10.199
	Std Dev	4.140	3.720	6.434

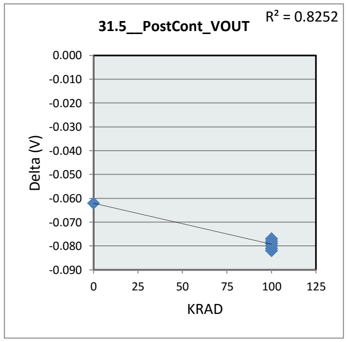


	29.1__Quiscent_Delta_Vinmin	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	200	uA
Min Limit	-10.059	uA
KRAD	0	100
LL	-10.059	-10.059
Min	62.431	59.103
Average	62.431	67.106
Max	62.431	73.247
UL	200.000	200.000

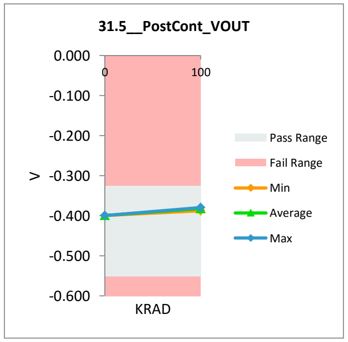


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		31.5__PostCont_VOUT		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	V	V	
	Max Limit	-0.325	-0.325	
	Min Limit	-0.55	-0.55	
KRAD	Serial #	PreRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	-0.461	-0.399	-0.062
100	294	-0.463	-0.384	-0.079
100	296	-0.461	-0.381	-0.080
100	298	-0.463	-0.381	-0.082
100	299	-0.462	-0.383	-0.079
100	300	-0.464	-0.383	-0.081
100	301	-0.461	-0.384	-0.077
100	302	-0.461	-0.380	-0.081
100	303	-0.462	-0.380	-0.082
100	305	-0.462	-0.385	-0.077
100	307	-0.460	-0.382	-0.078
100	308	-0.463	-0.383	-0.080
100	309	-0.464	-0.385	-0.079
100	310	-0.460	-0.382	-0.078
100	312	-0.462	-0.380	-0.082
100	313	-0.462	-0.381	-0.081
100	314	-0.459	-0.379	-0.080
100	316	-0.460	-0.380	-0.080
100	317	-0.465	-0.387	-0.078
100	318	-0.461	-0.384	-0.077
100	320	-0.459	-0.382	-0.077
100	321	-0.459	-0.381	-0.078
100	322	-0.459	-0.380	-0.079
	Max	-0.459	-0.379	-0.062
	Average	-0.461	-0.383	-0.079
	Min	-0.465	-0.399	-0.082
	Std Dev	0.002	0.004	0.004

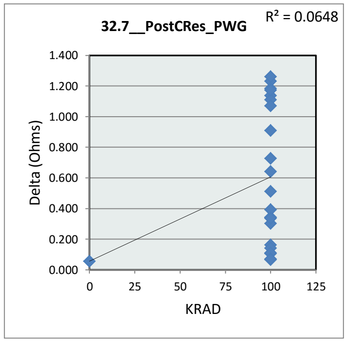


	31.5__PostCont_VOUT	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	-0.325	V
Min Limit	-0.55	V
KRAD	0	100
LL	-0.550	-0.550
Min	-0.399	-0.387
Average	-0.399	-0.382
Max	-0.399	-0.379
UL	-0.325	-0.325

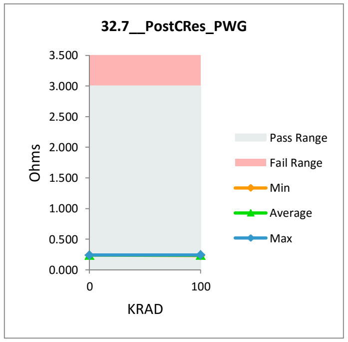


TID Report
TPS7H1101A_B1-SILICON_RLAT_100KRAD

		32.7__PostCRes_PWG		
	Test Site	CLAB	CLAB	
	Tester	EAG03	EAG03	
	Test Number	EF506901	EF506901	
	Unit	Ohms	Ohms	
	Max Limit	3	3	
	Min Limit	0	0	
KRAD	Serial #	reRLAT_3-3-17.tx	01A-RLAT-POST_	Delta
0	C1	0.297	0.241	0.056
100	294	0.399	0.236	0.163
100	296	1.471	0.240	1.231
100	298	0.379	0.238	0.141
100	299	1.424	0.240	1.184
100	300	0.308	0.241	0.067
100	301	0.343	0.237	0.106
100	302	1.377	0.240	1.137
100	303	0.581	0.239	0.342
100	305	0.879	0.237	0.642
100	307	1.349	0.239	1.110
100	308	1.308	0.238	1.070
100	309	0.580	0.238	0.342
100	310	0.633	0.240	0.393
100	312	0.966	0.239	0.727
100	313	0.543	0.240	0.303
100	314	1.502	0.242	1.260
100	316	0.750	0.239	0.511
100	317	0.351	0.240	0.111
100	318	0.310	0.239	0.071
100	320	1.414	0.240	1.174
100	321	0.573	0.237	0.336
100	322	1.143	0.233	0.910
	Max	1.502	0.242	1.260
	Average	0.821	0.239	0.582
	Min	0.297	0.233	0.056
	Std Dev	0.451	0.002	0.451



	32.7__PostCRes_PWG	
Test Site	CLAB	
Tester	EAG03	
Test Number	EF506901	
Max Limit	3	Ohms
Min Limit	0	Ohms
KRAD	0	100
LL	0.000	0.000
Min	0.241	0.233
Average	0.241	0.239
Max	0.241	0.242
UL	3.000	3.000



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